

Power Management in the New Millennium

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University of Wales Swansea

Talk Overview

- Introduction
- Silicon Power Devices
- Packaging
- Application Areas
- New Materials – SiC & Diamond
- Conclusion

Electronics

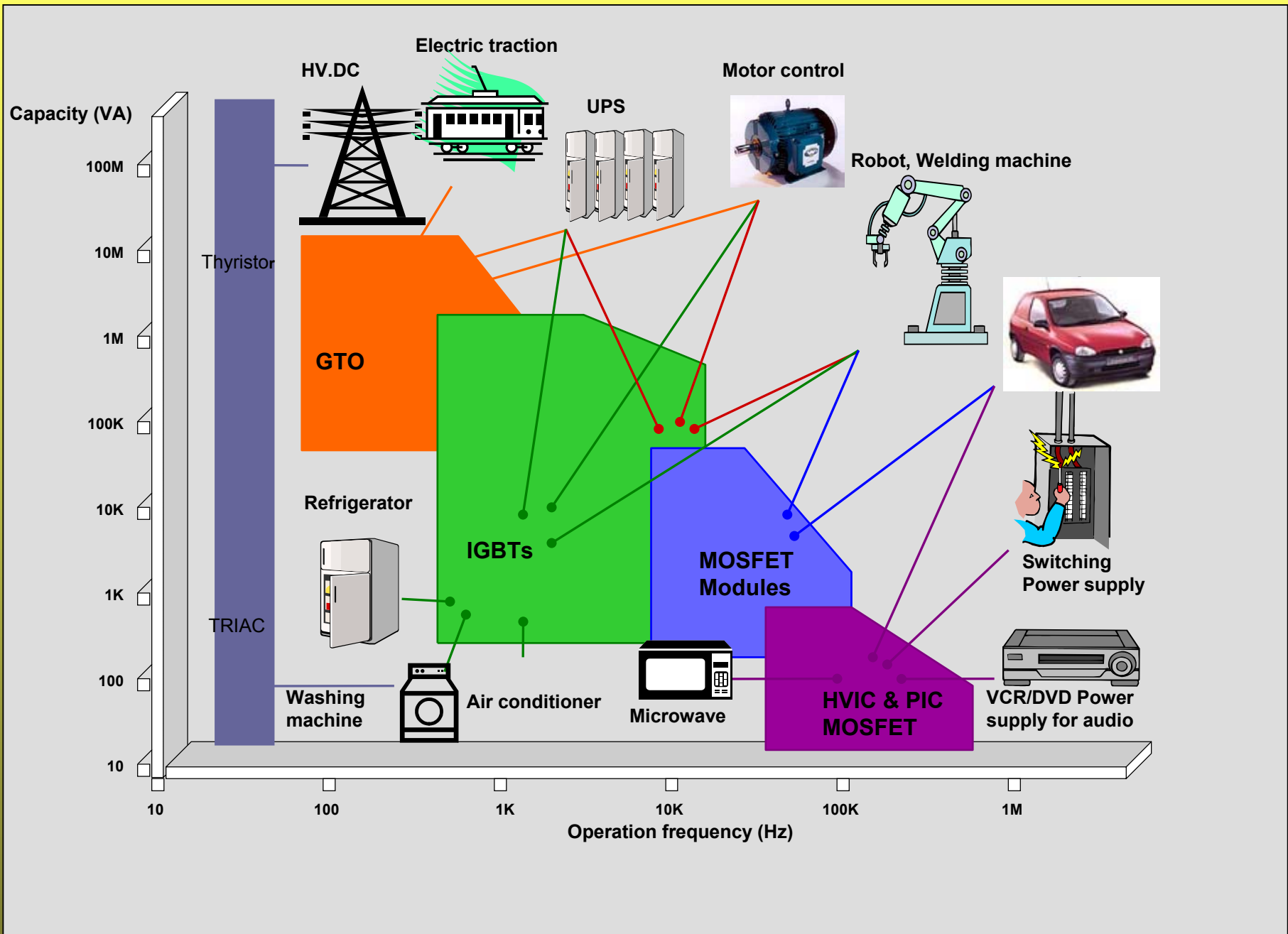
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graph TD; Electronics[Electronics] --- Diamond{ }; Diamond --- Energy[Energy Processing]; Diamond --- Information[Information Processing];
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**Energy
Processing**

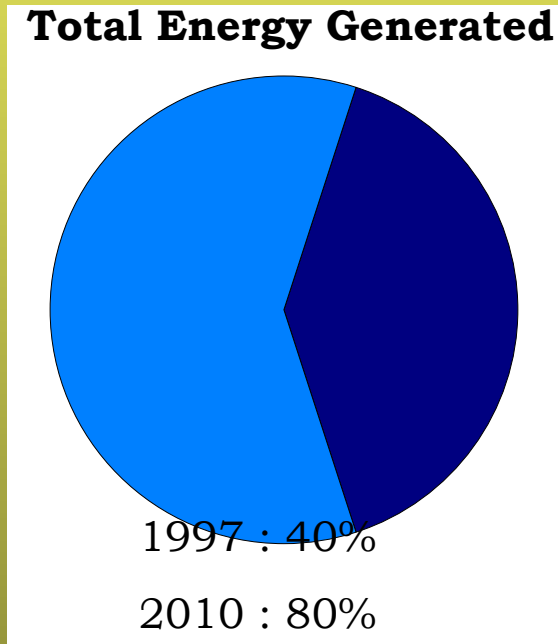
**Information
Processing**

Power Electronics is

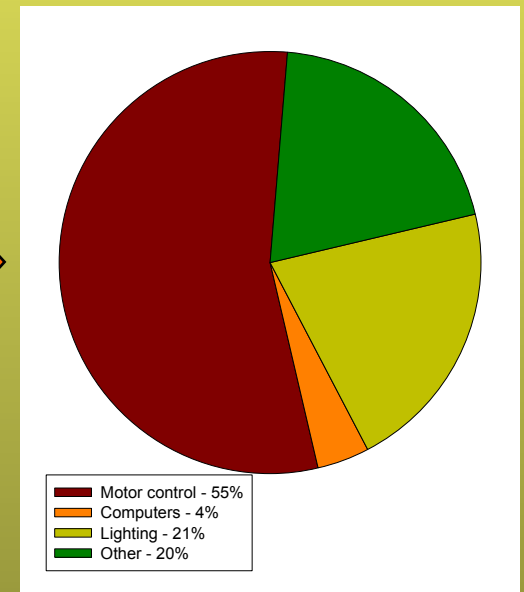
“Efficient processing of electrical energy through means of electronic switching devices”



Increasing Importance of Power Electronics in Energy Management



**Power
Electronic
Converter**

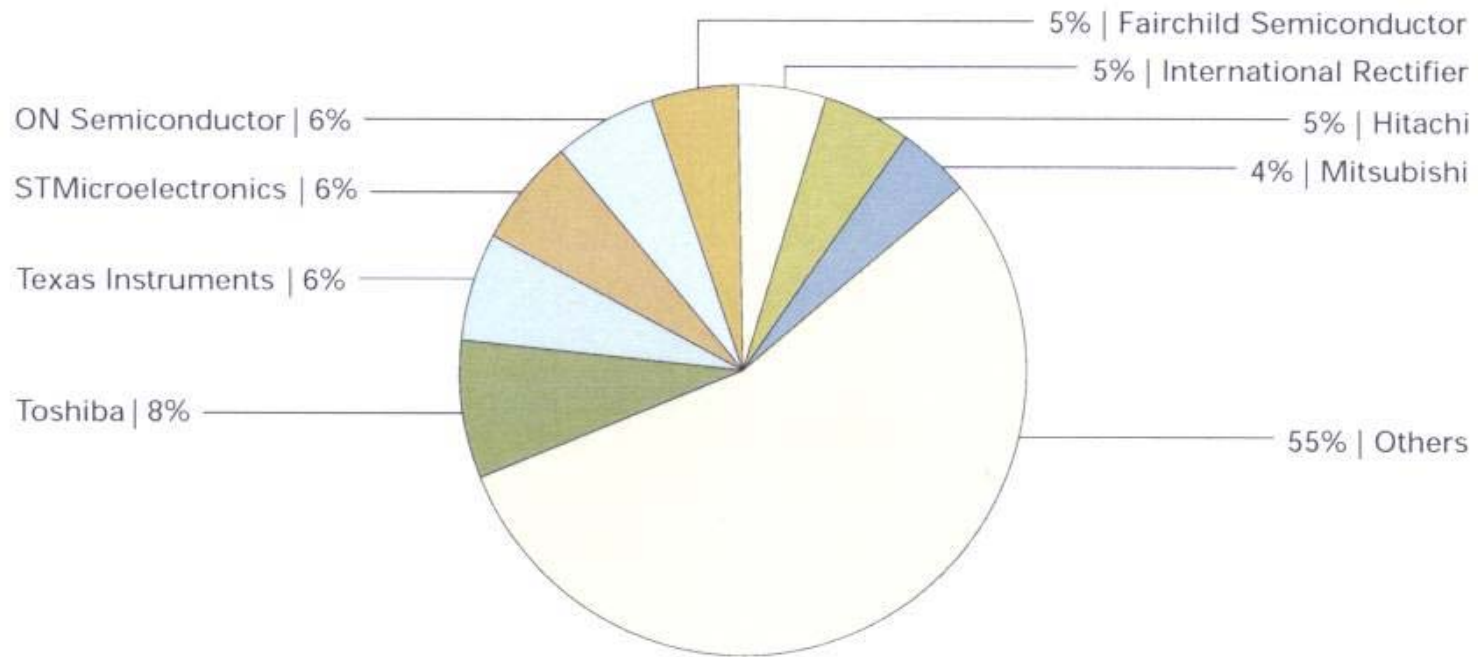


**Converter Technology is Driven by
Devices**

Power Management Market

- Total semiconductor market in 2000 - \$204b
 - 5% Power discretes - \$10b; CAGR 28%
 - Thyristors – 8%; \$0.8b
 - Diodes – 23%; \$2.3b
 - Power Transistors – 69%; \$6.9b
 - 3% Power Management ICs - \$6b; CAGR 61%;
20% of total analogue IC market

Market Share



Source: iSuppli Corp. | June, 2001

Application areas

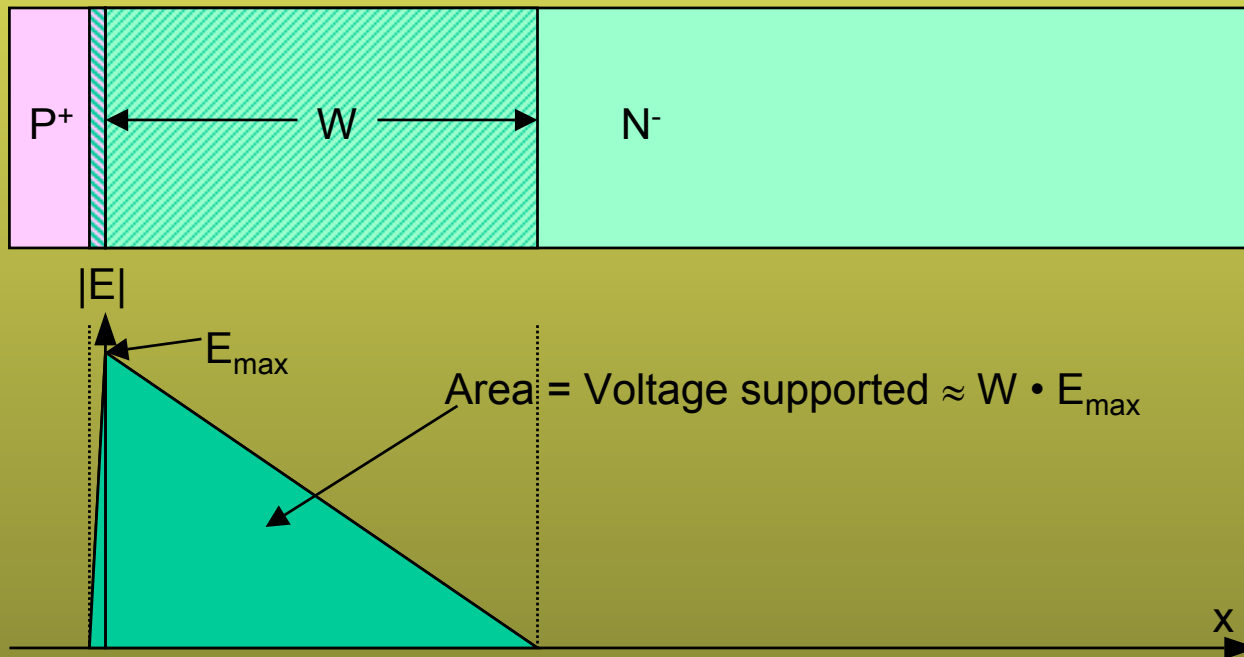
- Two Main Areas of Growth
 - IT, communications, computers – DC/DC
 - Motion control - DC/AC
- Both are driven by improvements in devices and device technology

2. Basics of Power Devices

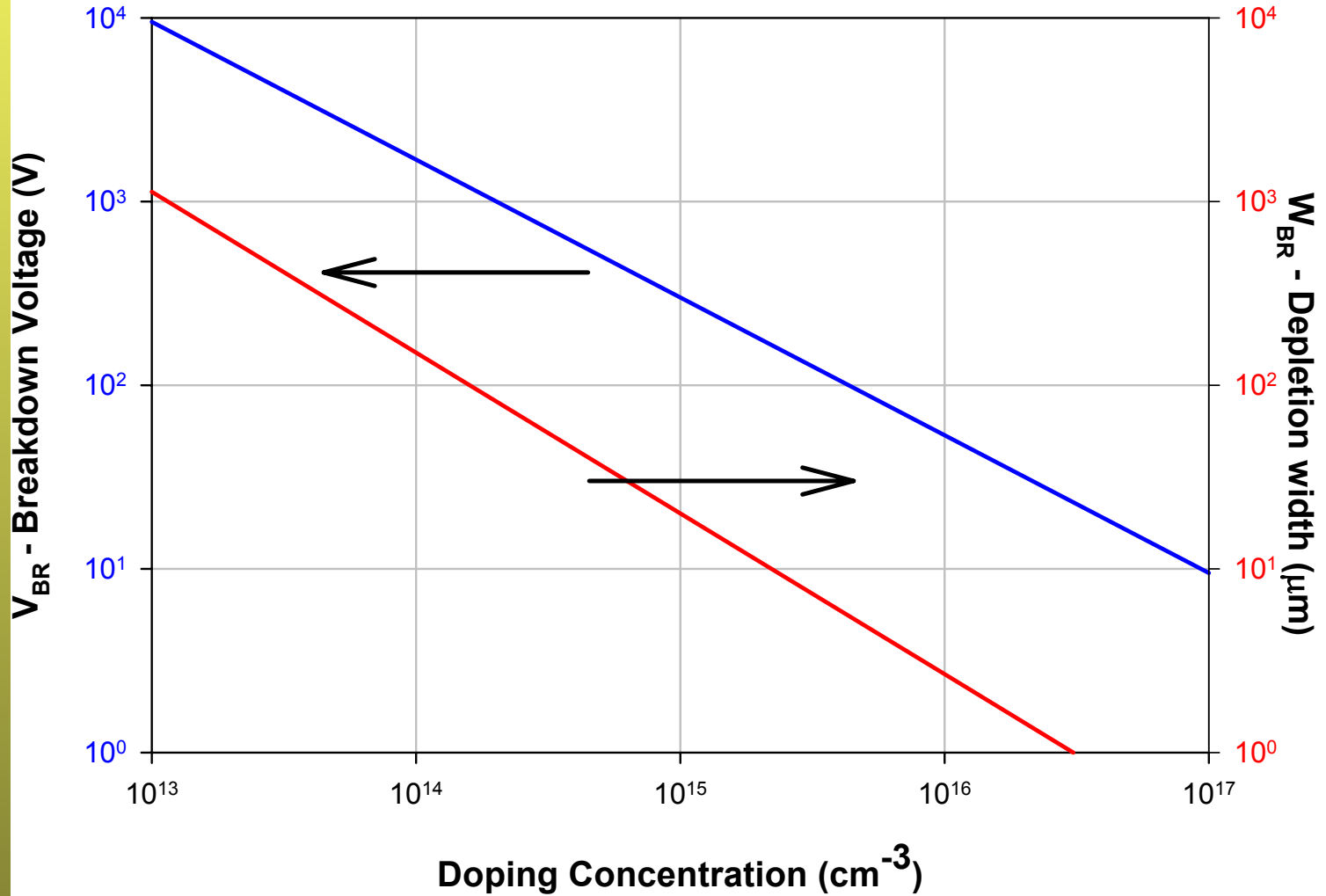
The ideal power device:

1. When on – zero resistance
2. When off – support infinite voltage
3. Switch between on and off (and *vice-versa*) in zero time
4. Zero Power dissipation
5. Small, light and cheap!

Blocking capability



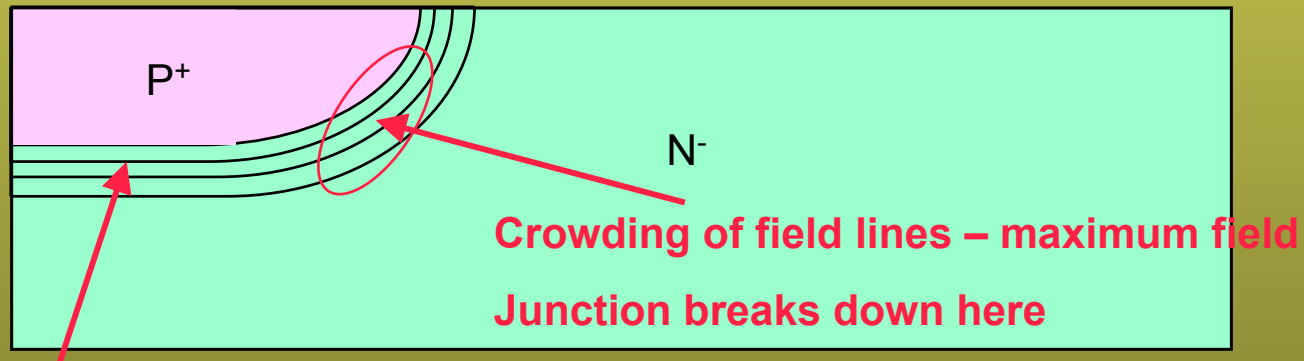
Avalanche Breakdown Voltage and Depletion Region Thickness



NOTE: Maximum VBR for silicon is approximately 10kV

Junction Termination

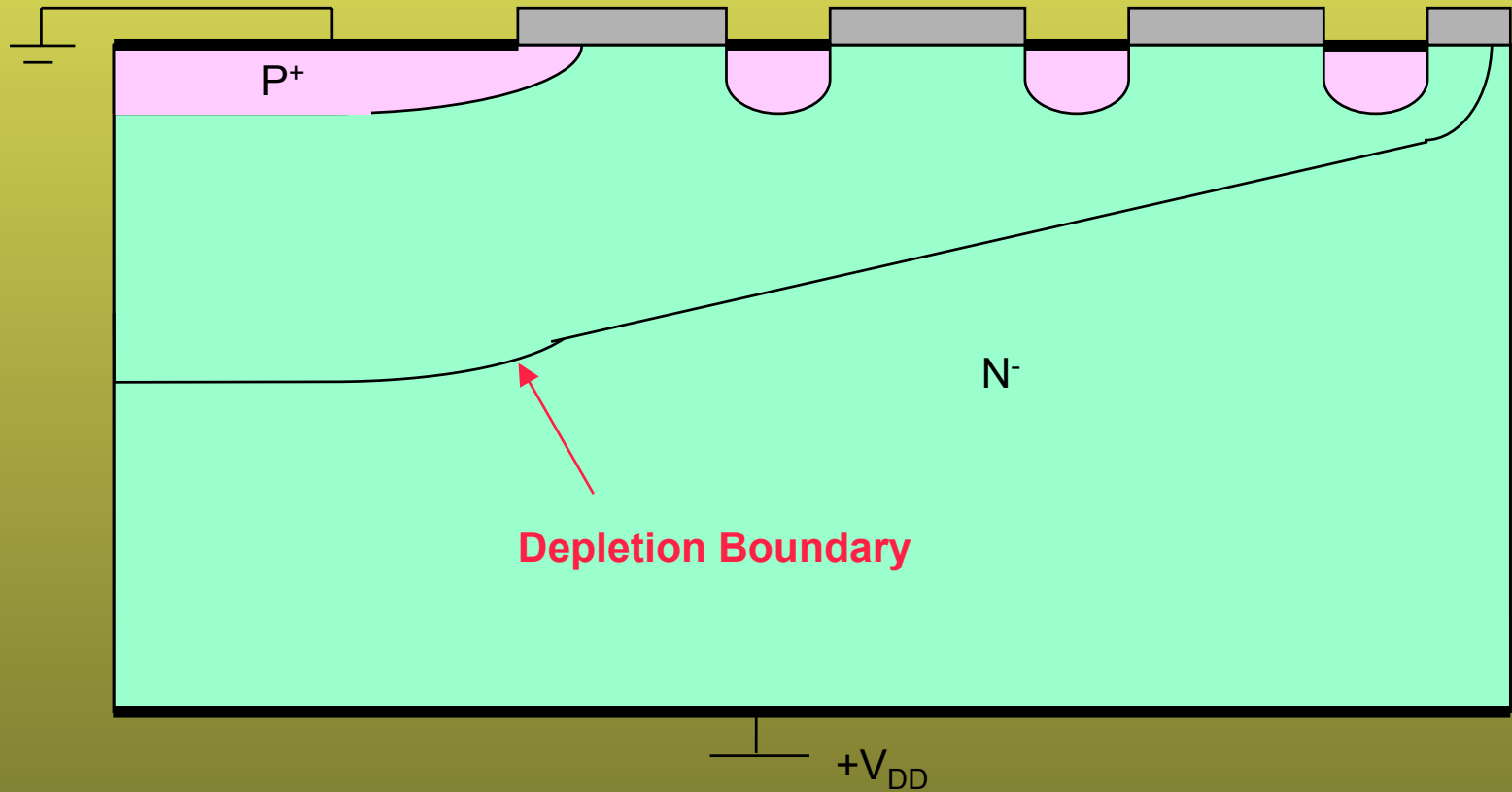
- In real structures the pn -junction will need terminate at some point
 - Thyristor/GTO - Edge of Wafer
 - MOSFET/IGBT - Edge of Chip or device



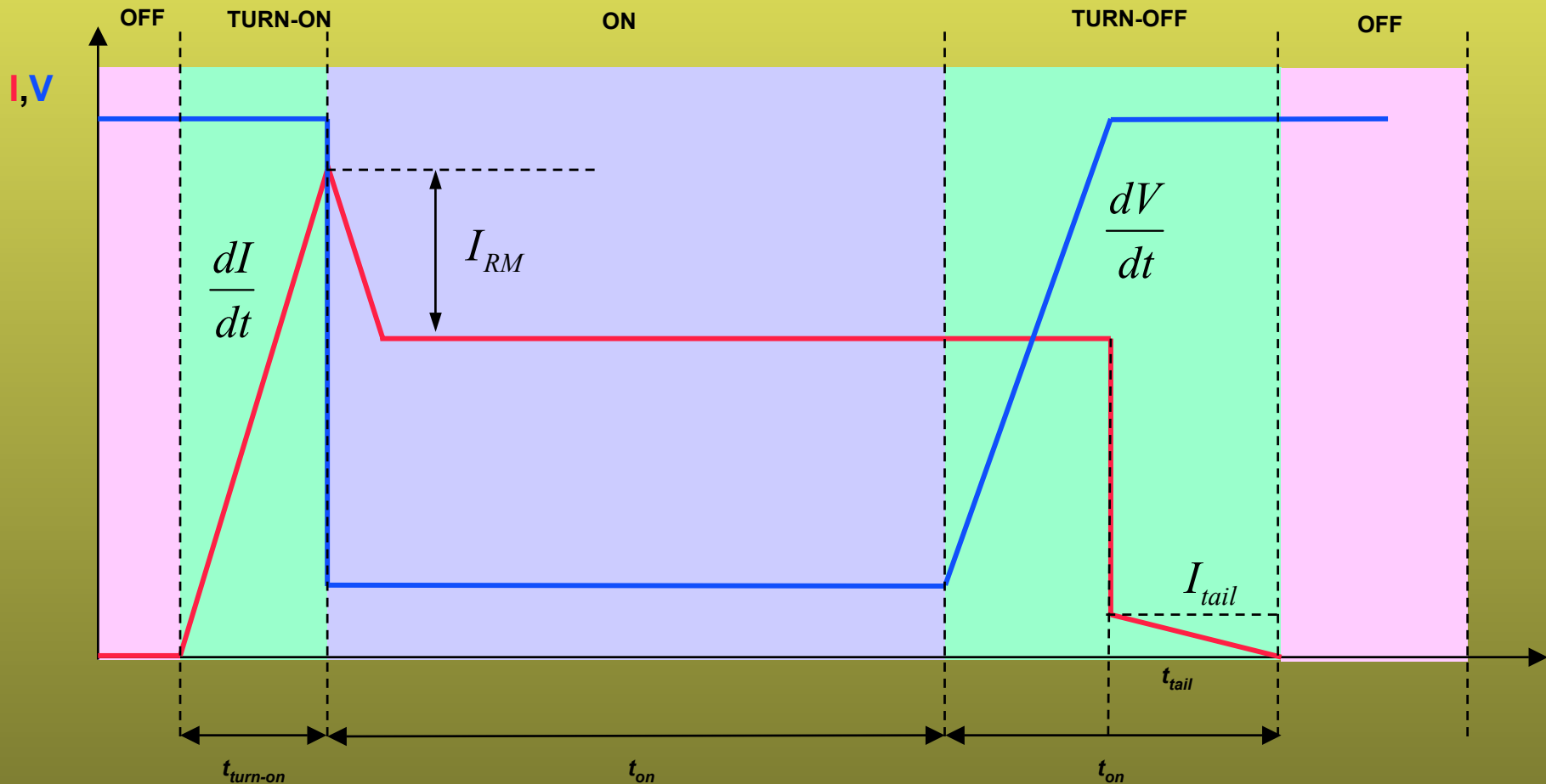
Ideal 1-D Breakdown

- Tight radius of curvature gives largest fields
- Without proper termination may get $< 50\%$ of abrupt junction breakdown voltage
- Termination is used to add extra charge on the surface to spread out the field lines
- Usual techniques
 - Floating rings
 - Field Plates
 - Junction Termination Extension (JTE)
 - SIPOS, DLC – Very high voltage devices

Floating Rings



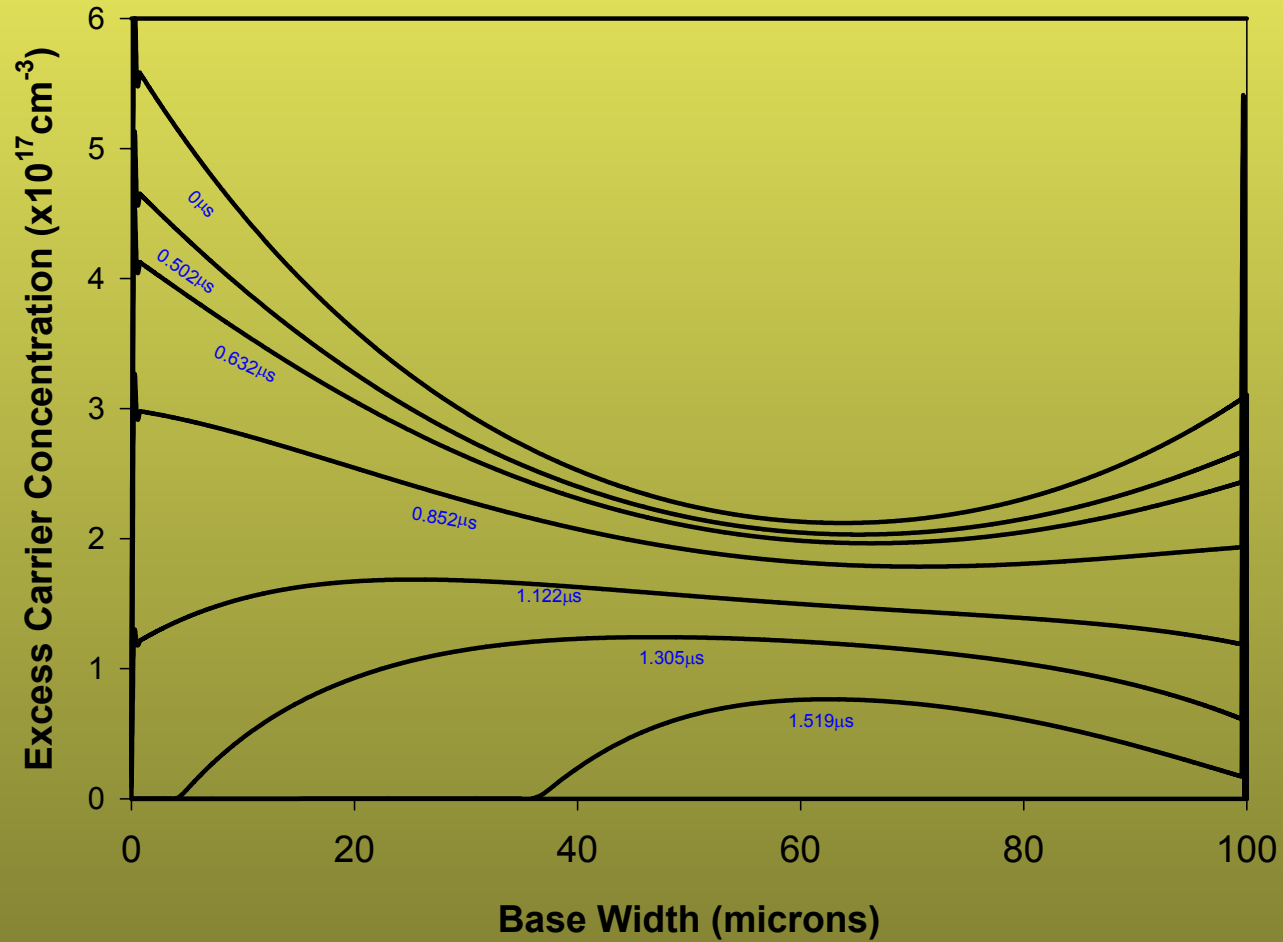
On-state and Switching losses



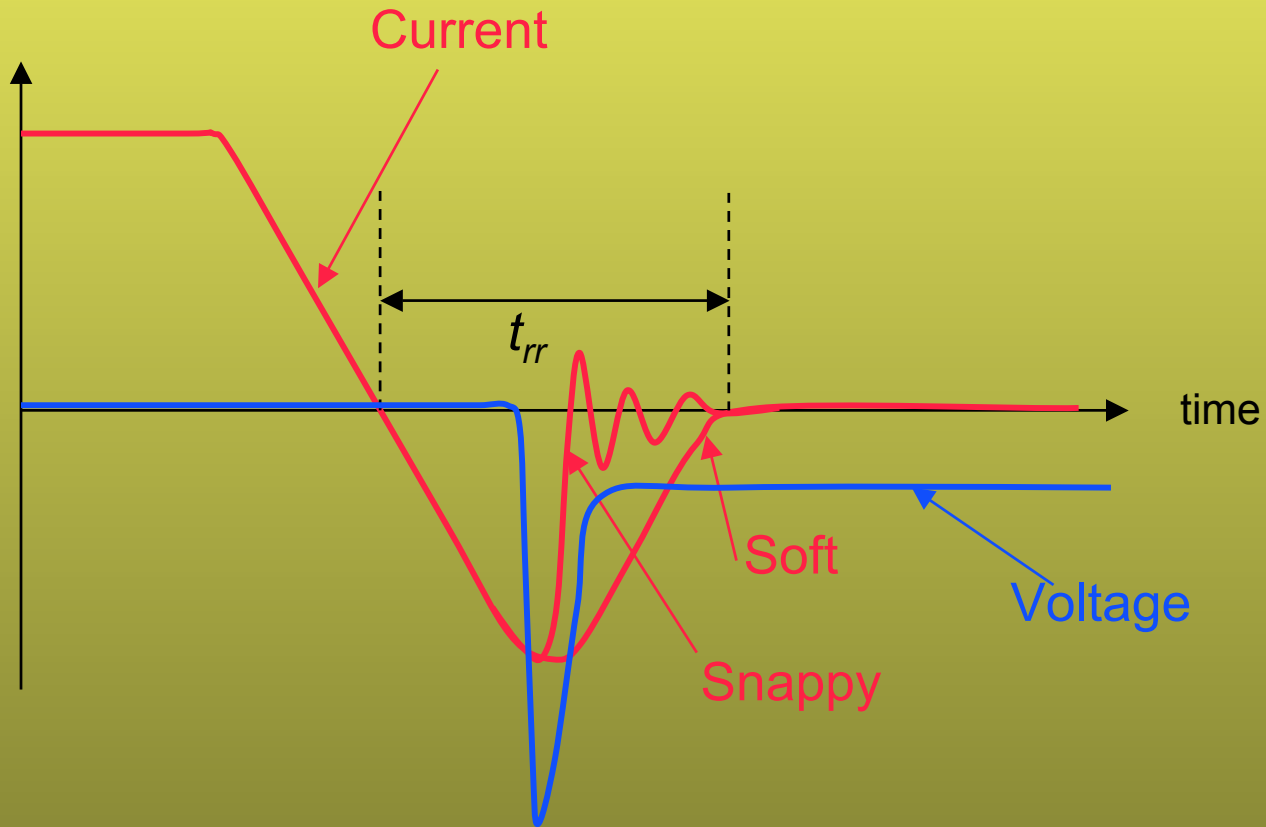
Bipolar Devices

- A bipolar device is defined as one in which both electrons and holes take part in the current conduction process.
- Bipolar operation is essential in all high voltage devices (>800V)
- Bipolar operation is much slower than Unipolar, hence devices based on this tend to be used at lower frequencies.

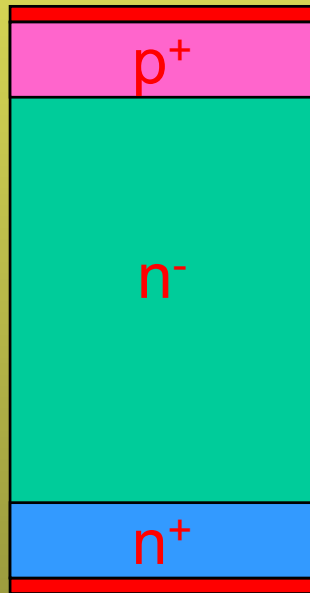
Bipolar switching Devices



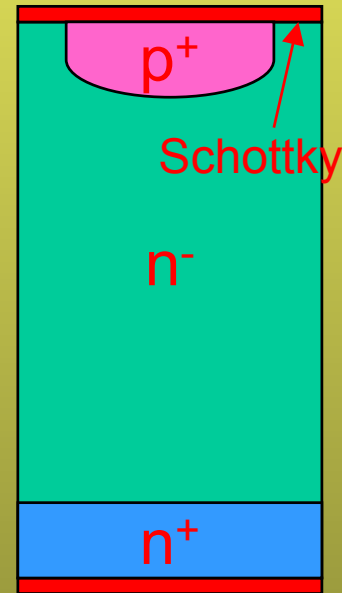
Recovery Definitions



Diode Structures



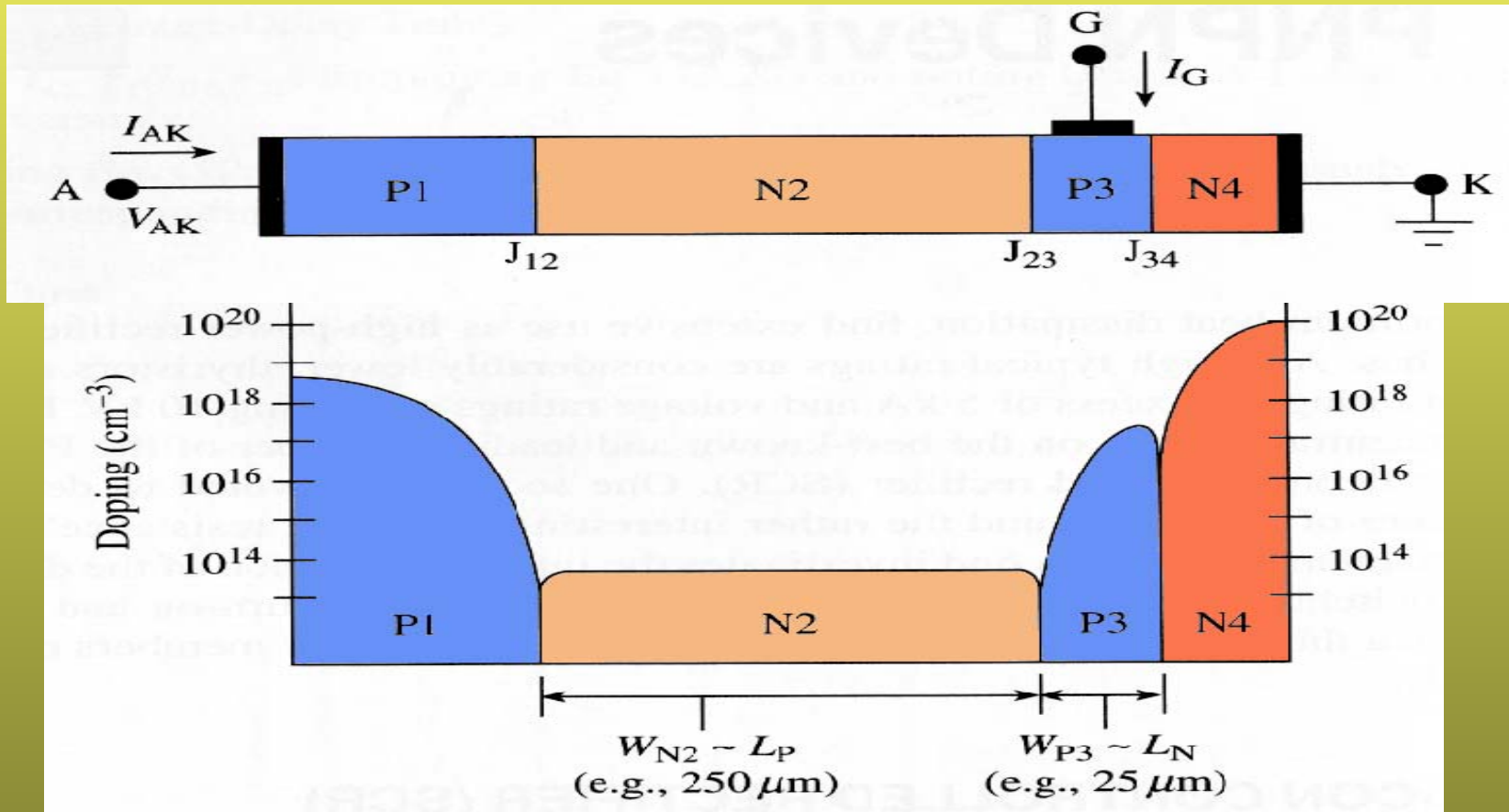
PiN



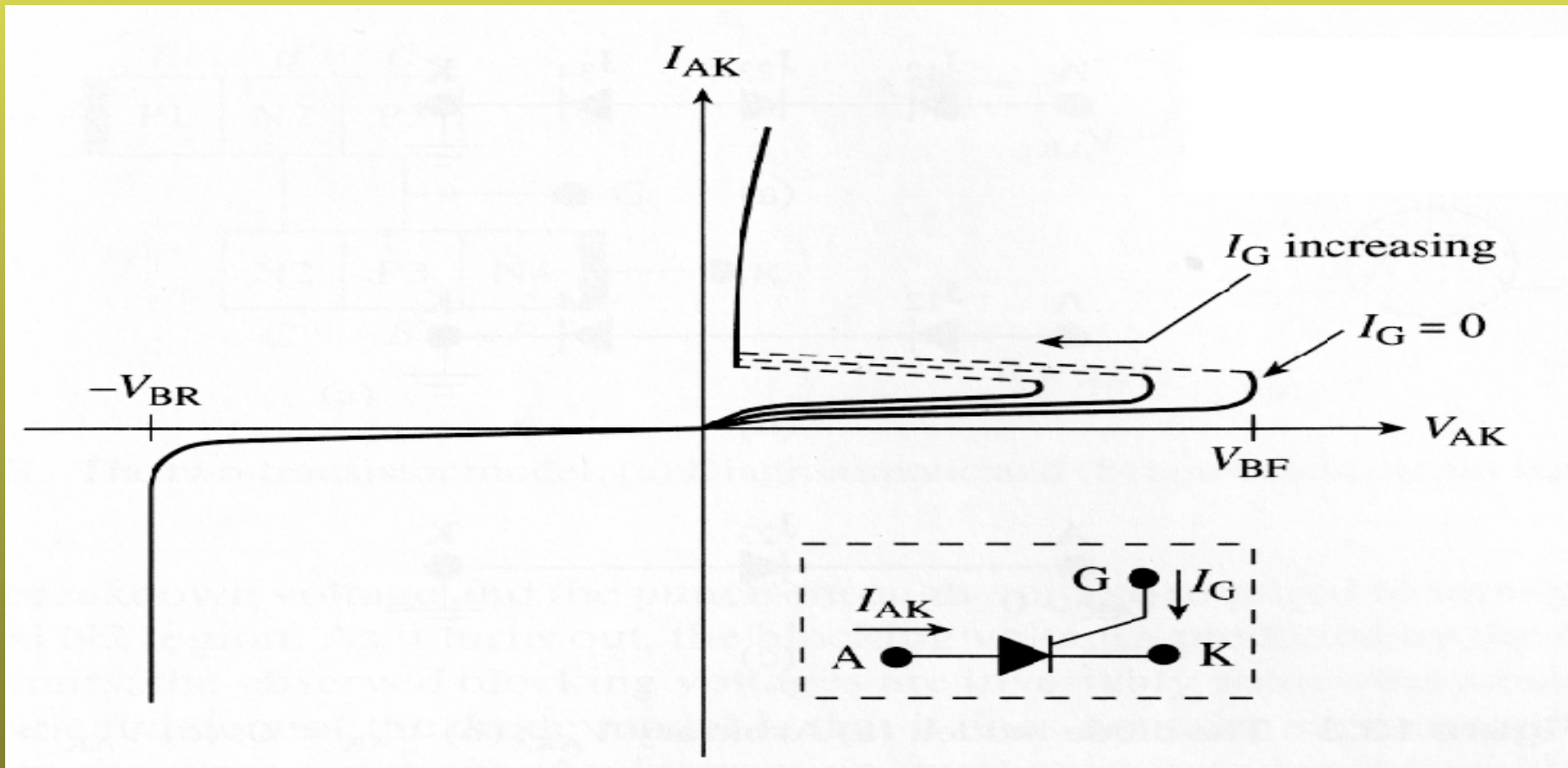
MPS

Merged Pin Schottky

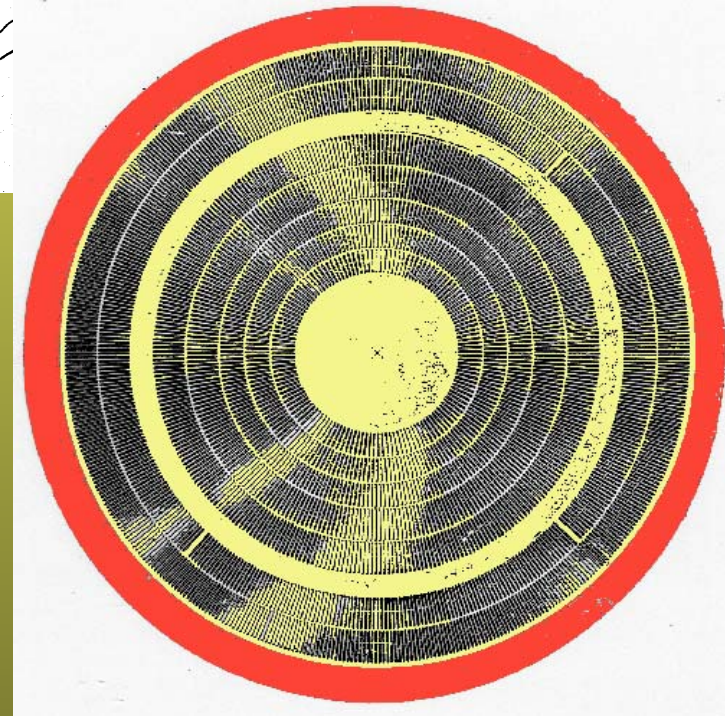
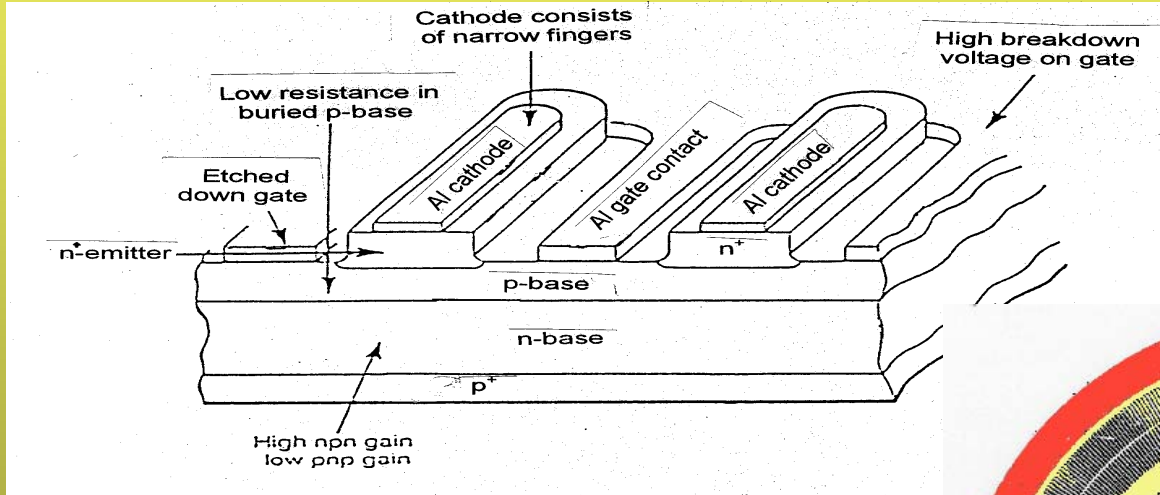
Thyristor Structures



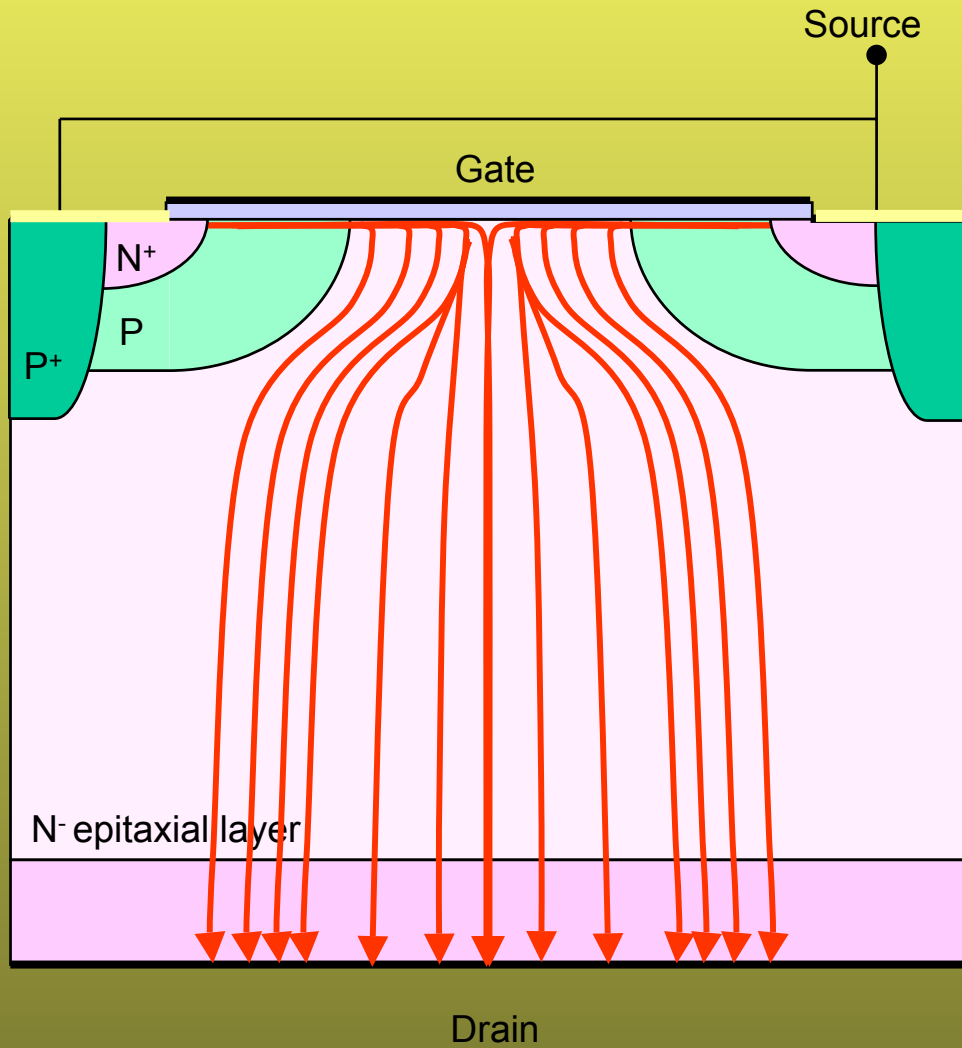
Terminal Characteristics



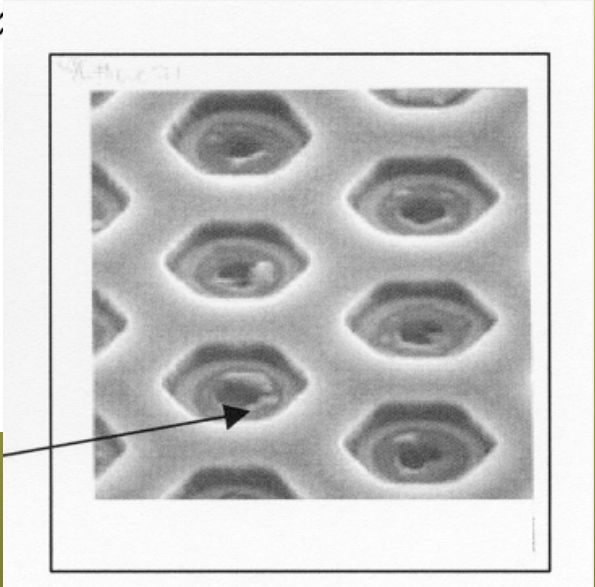
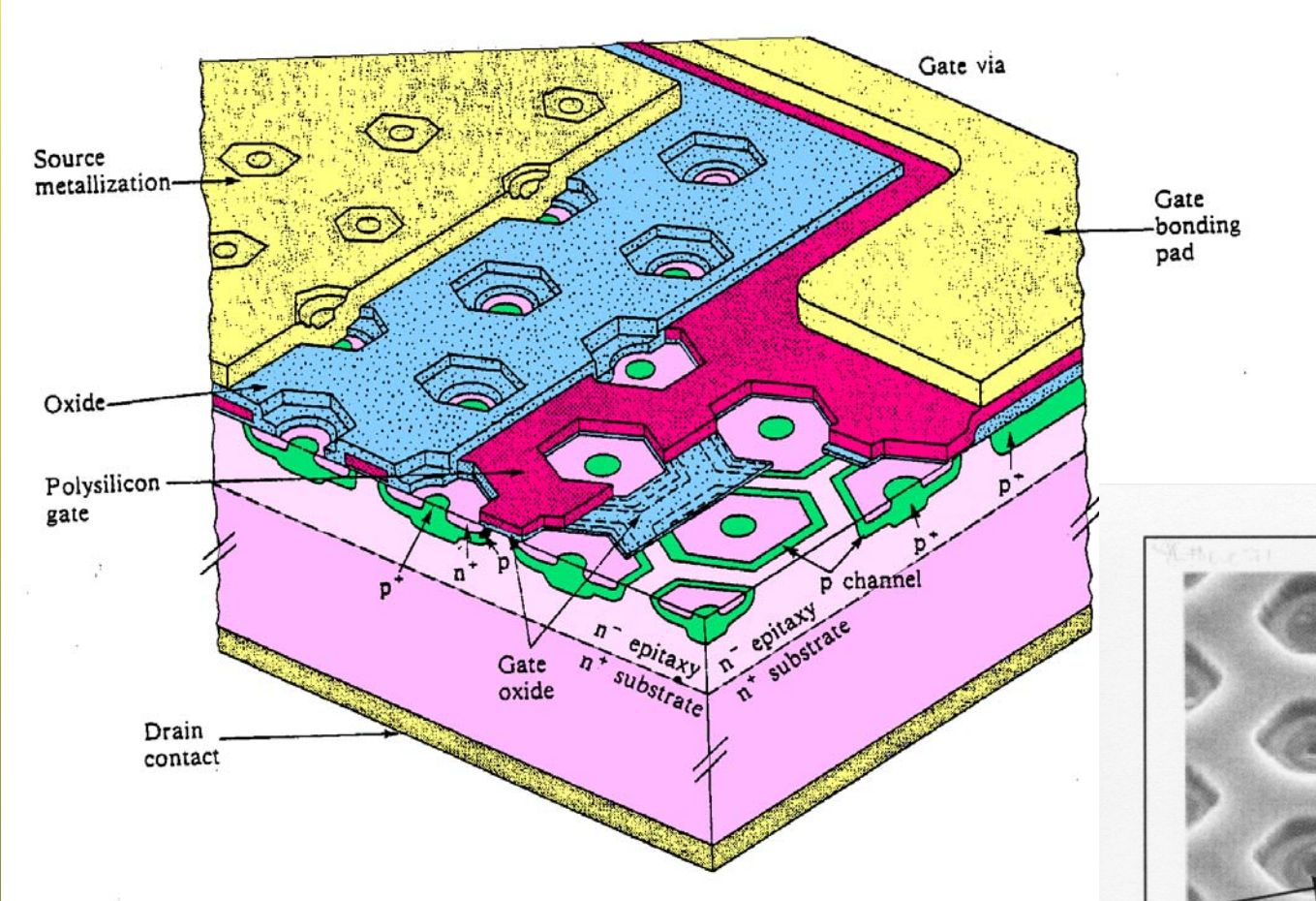
Gate Turn-off Thyristors (GTO)



DMOS



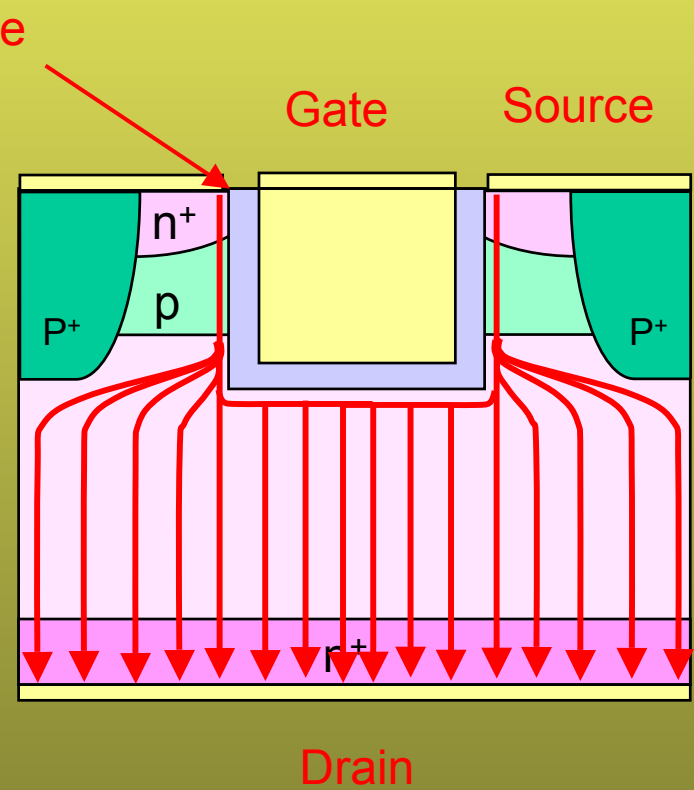
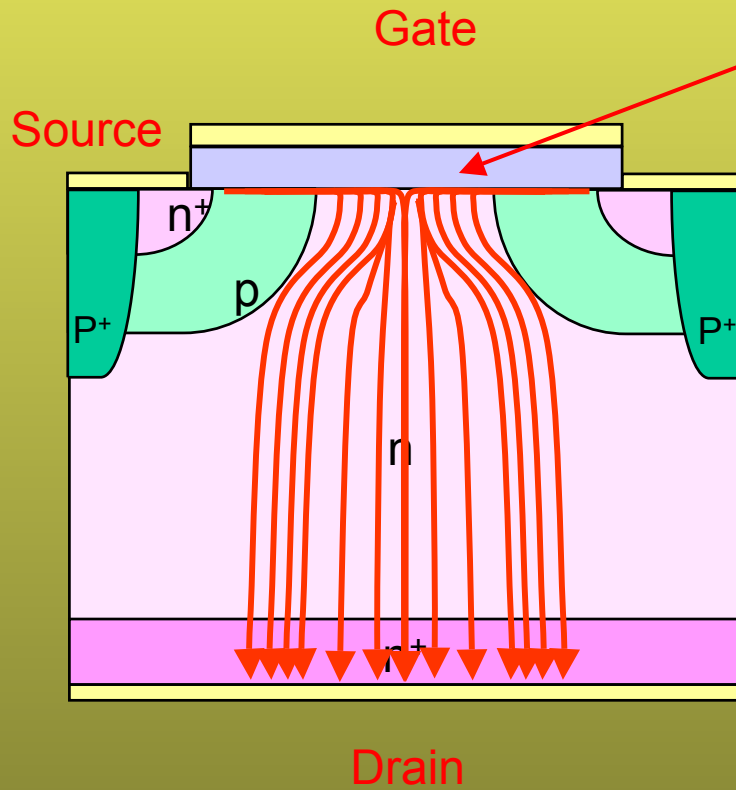
Cross sectional view of HEXFET



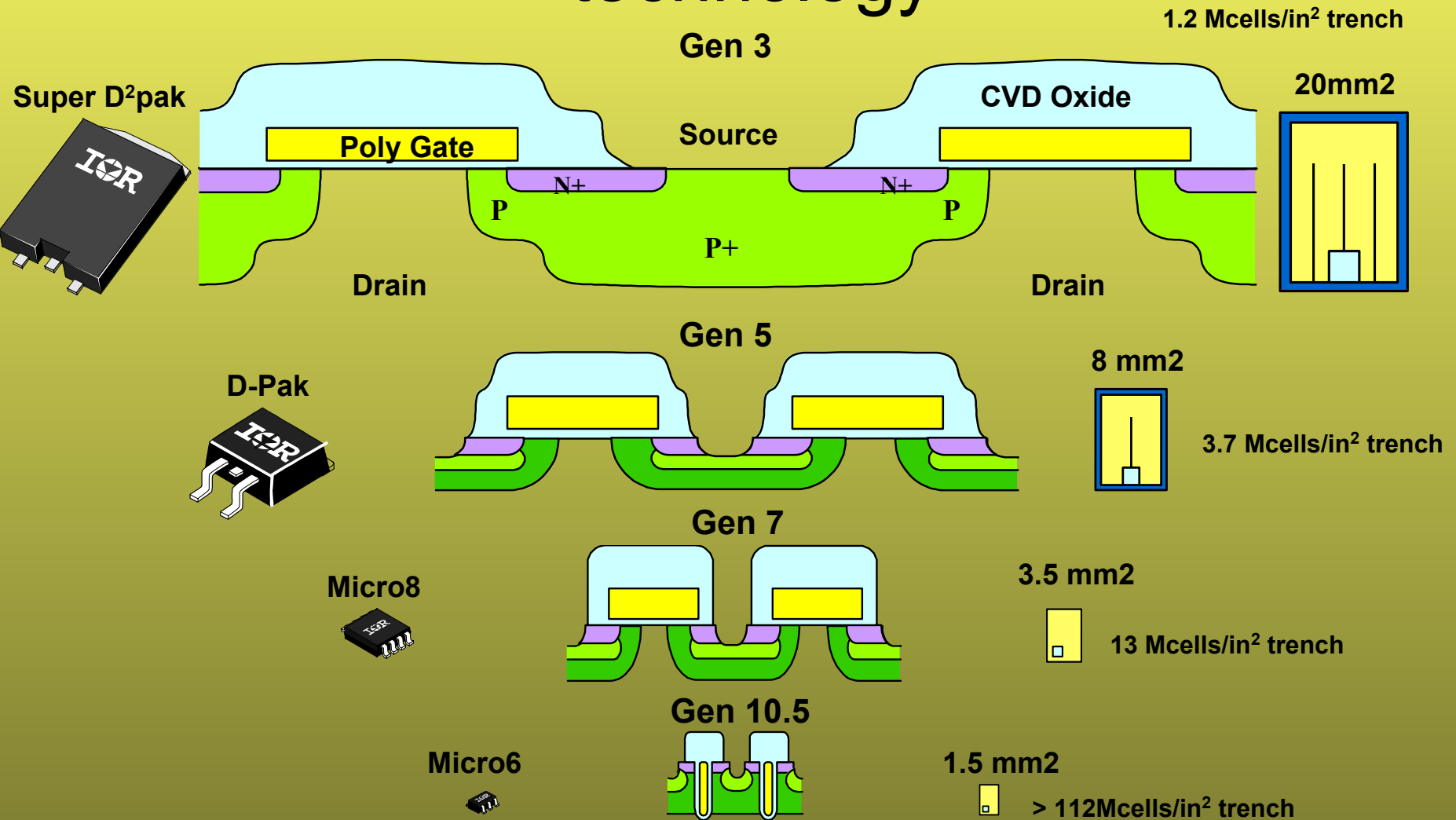
Comparison of Structures

DMOS Structure

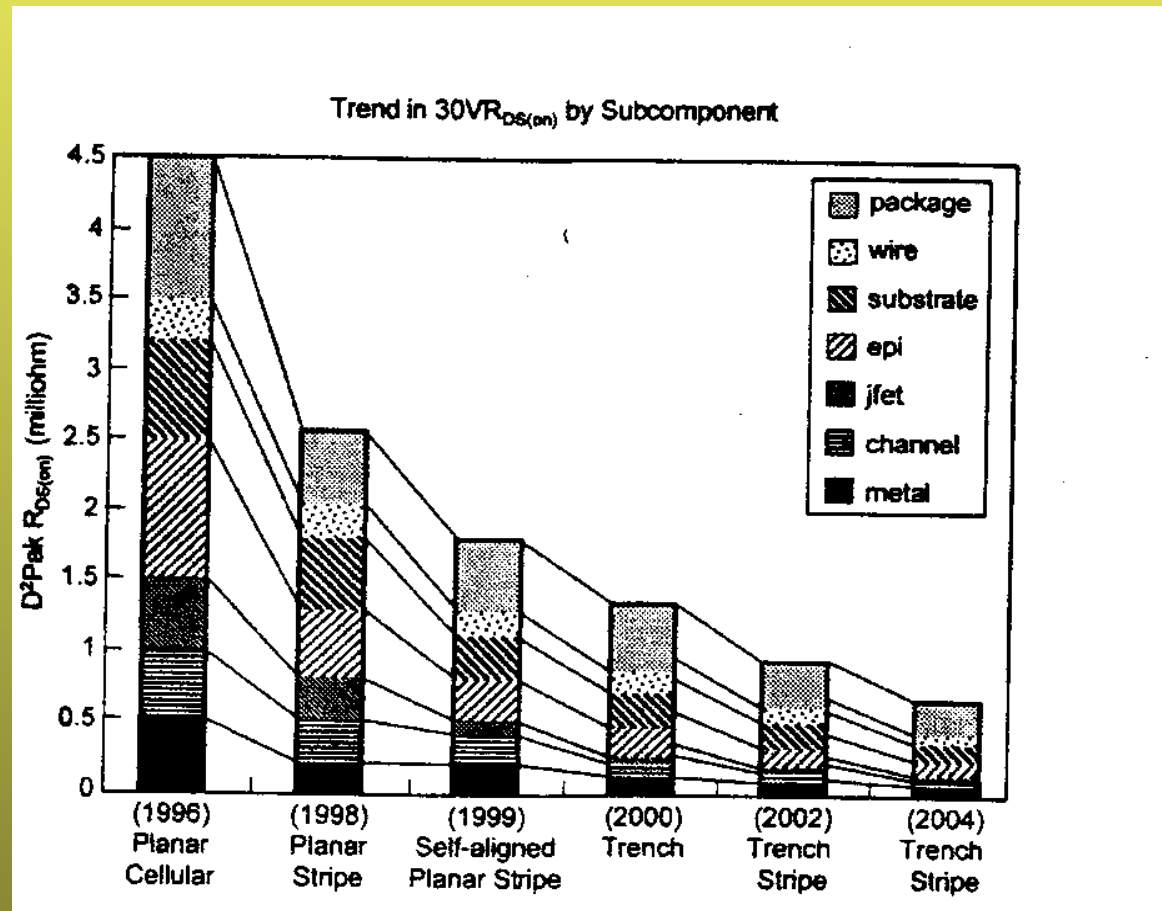
Trench Structure



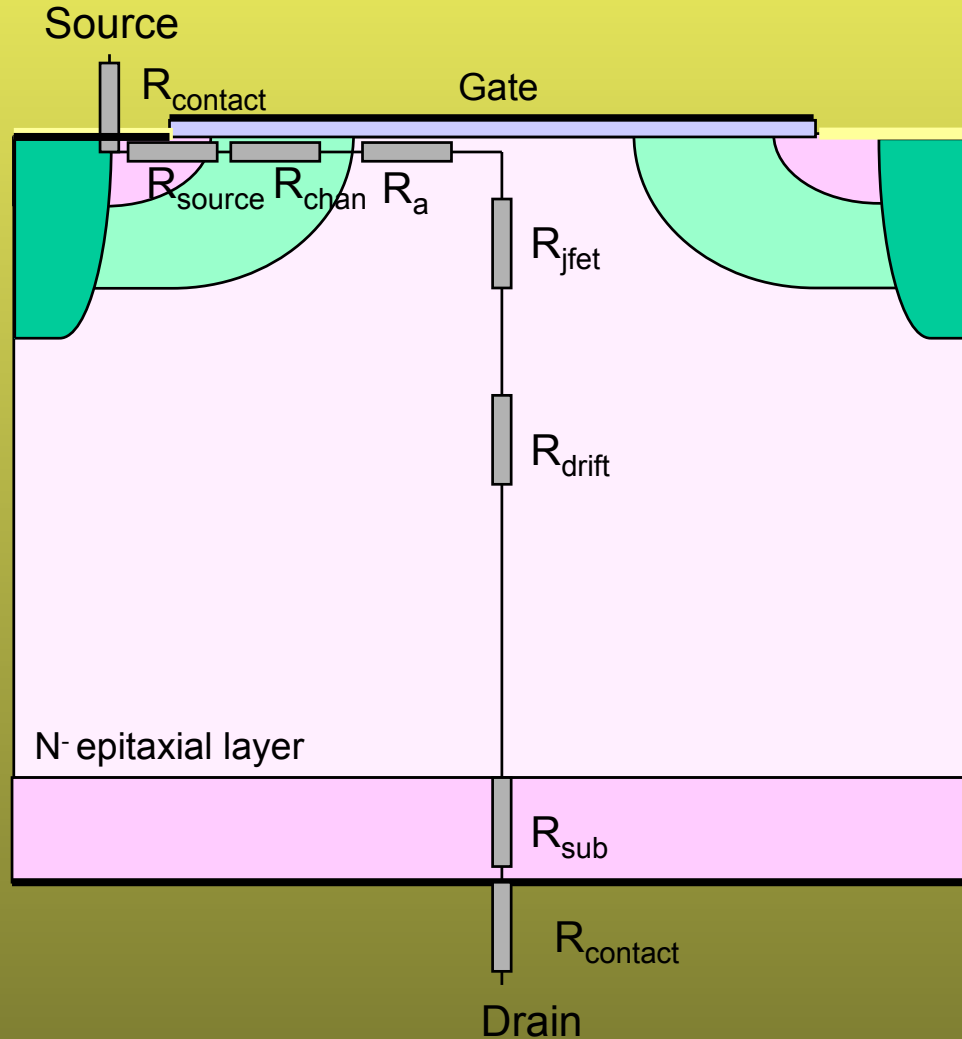
Trend in low voltage MOSFET technology



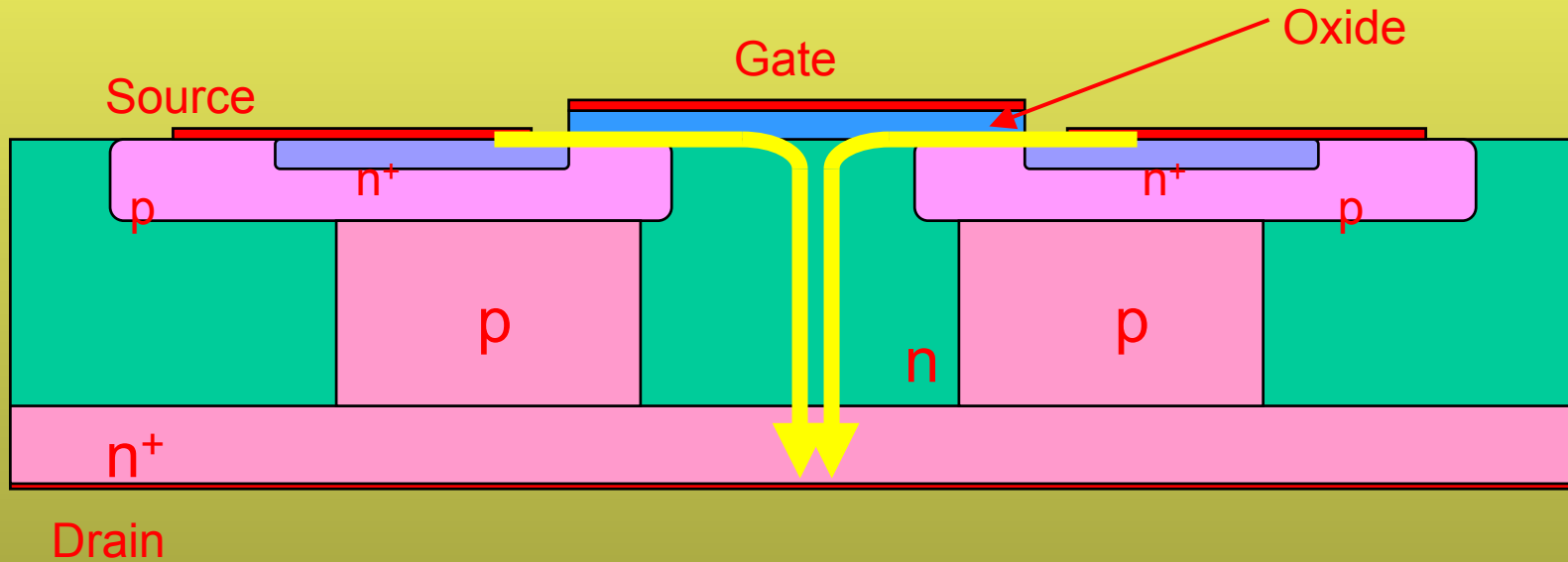
Trench Road-map (30V)



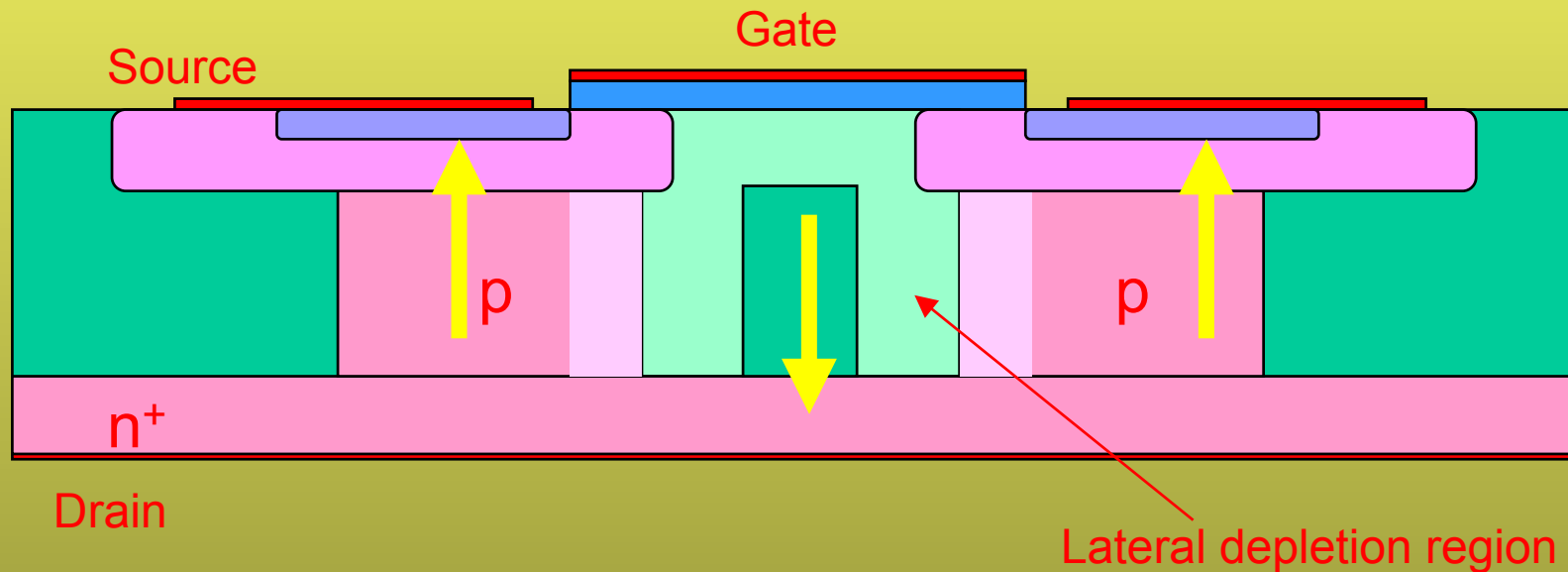
On-State Resistance



Charge Compensation (COOLMOS)



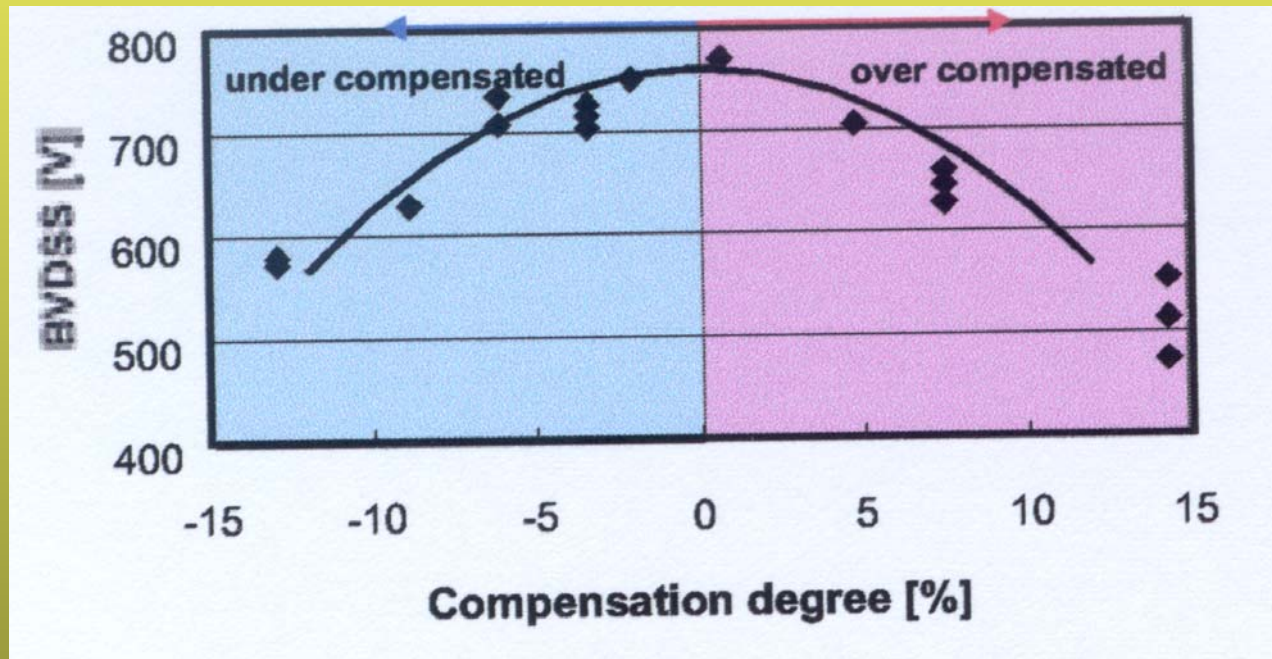
Charge Compensation (COOLMOS)



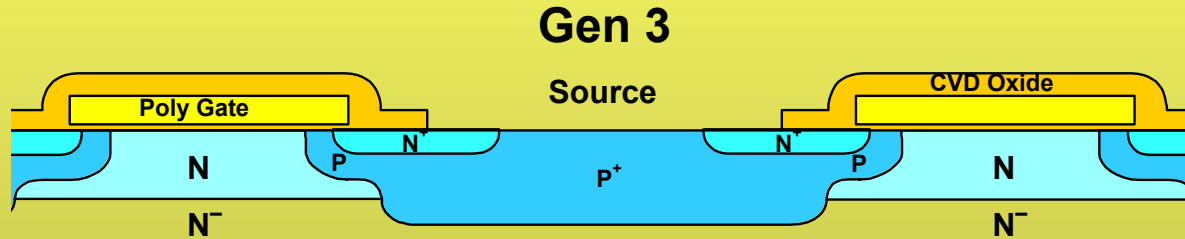
600V, 40A/cm²

Reduce R_{epi} to 20%

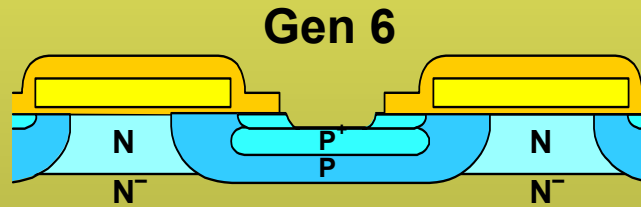
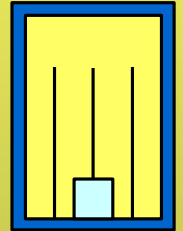
Compensation balancing act



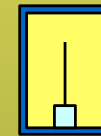
Trend in 400 – 600V FET technology



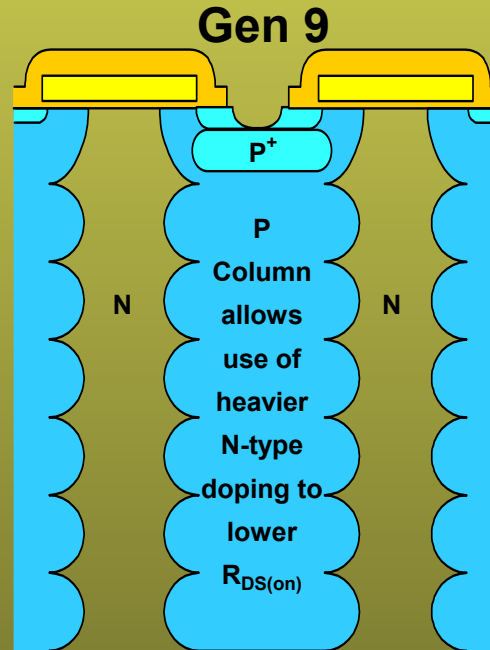
40mm²



25 mm²



High density planar process

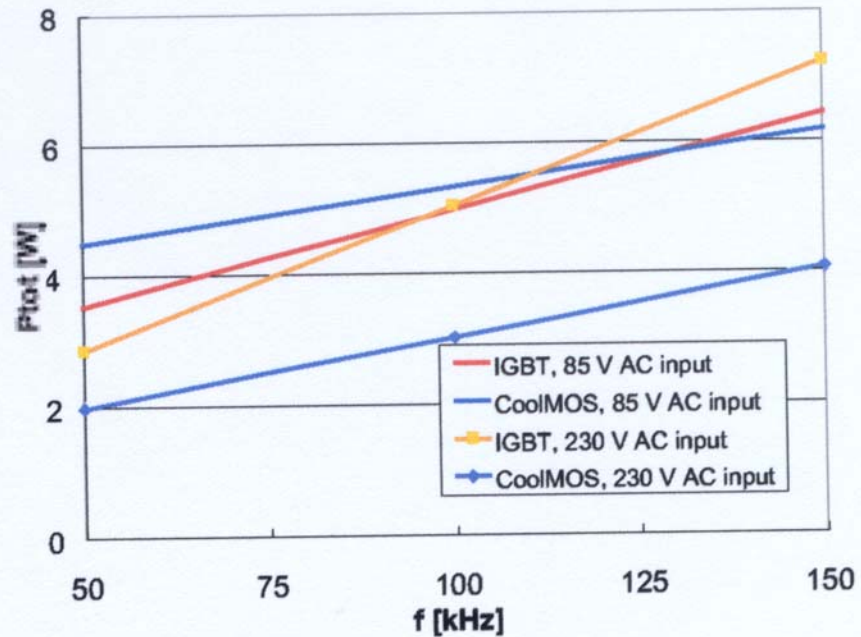


10 mm²



3x R_{DS(on)} reduction
High conductivity drift region

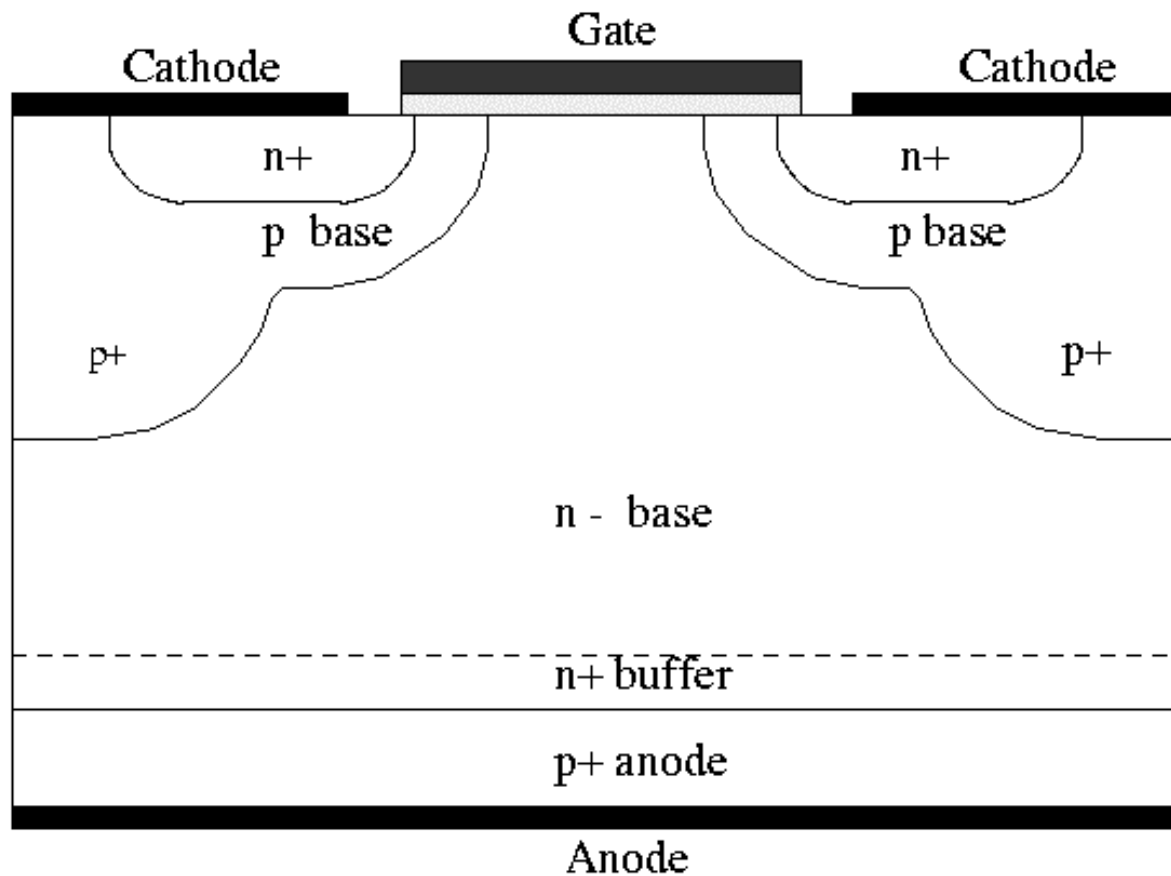
CoolMOS performance



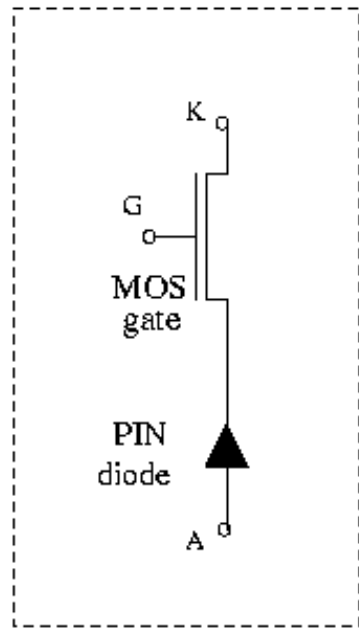
Comparison of the power losses of a 600 V high speed IGBT versus CoolMOS™ in a 70 W flyback converter.

Note: Patent filed by Professor XB Chen!

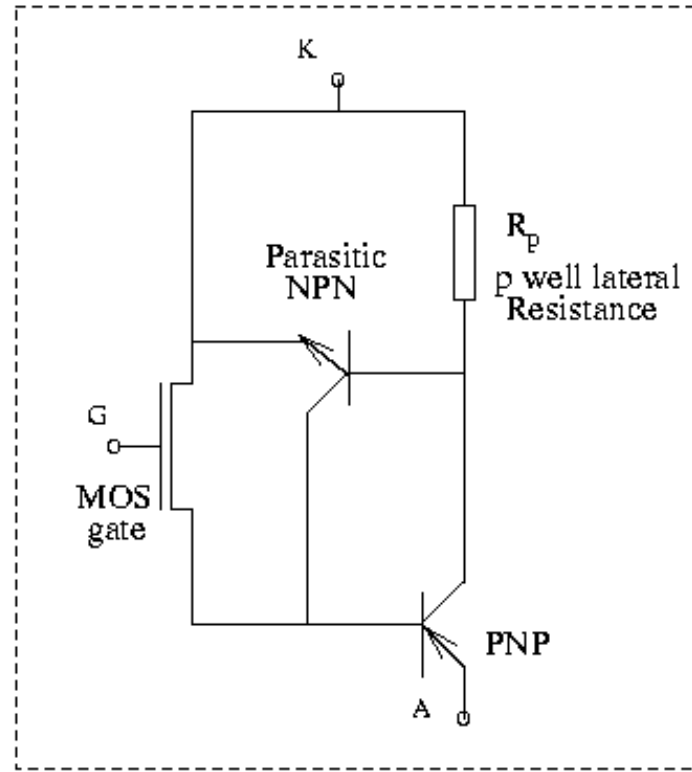
IGBT



The IGBT equivalent circuit

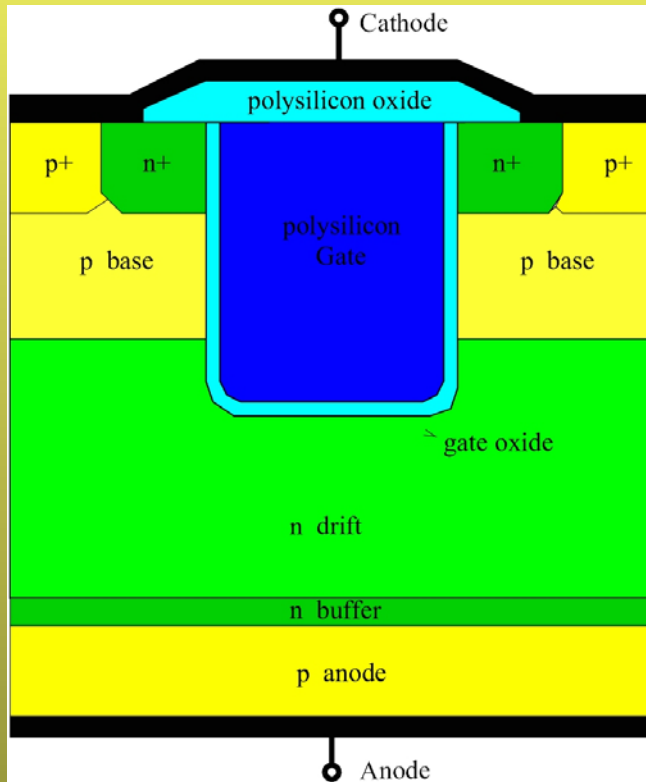


(a)

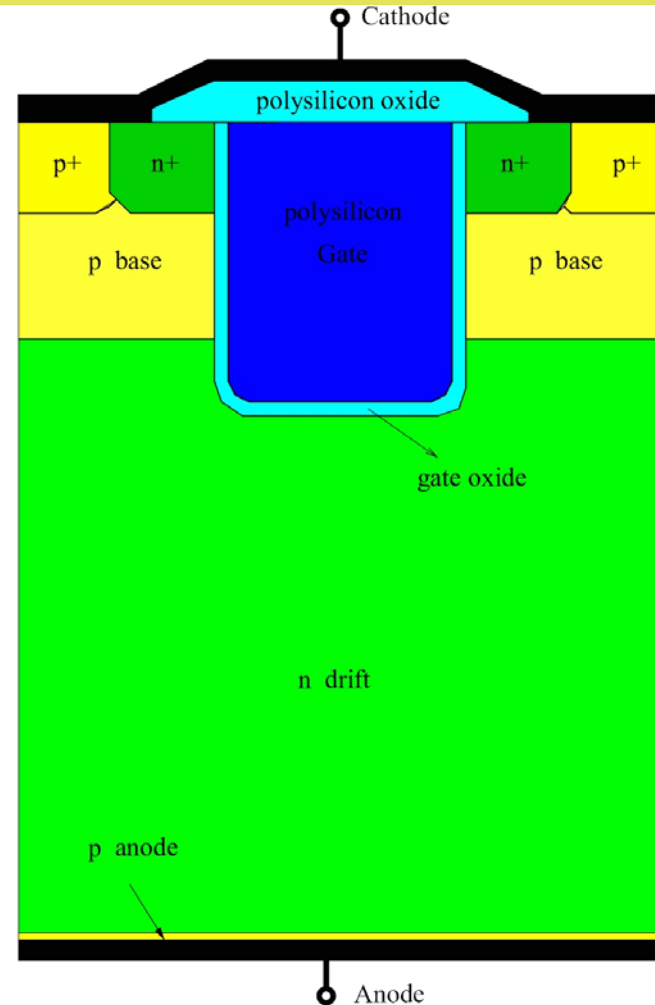


(b)

PT & NPT IGBT structures

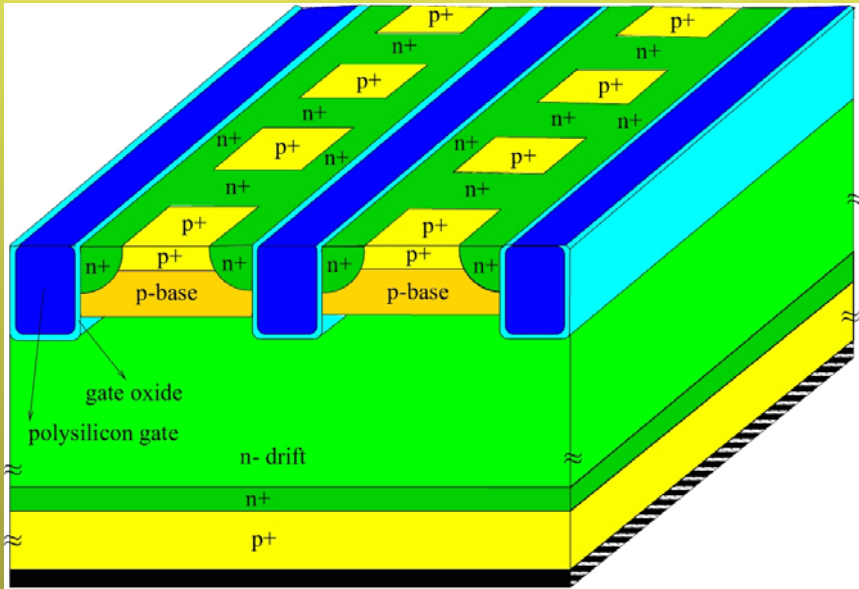


b) Punch Through (PT) IGBT



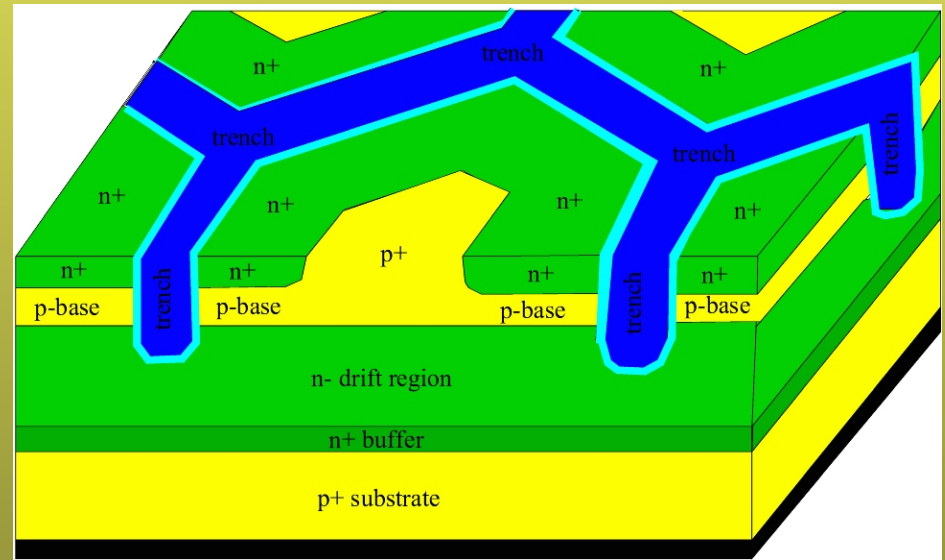
b) Non Punch Through (NPT) IGBT

Trench IGBT Layout- Stripe or Hex ?

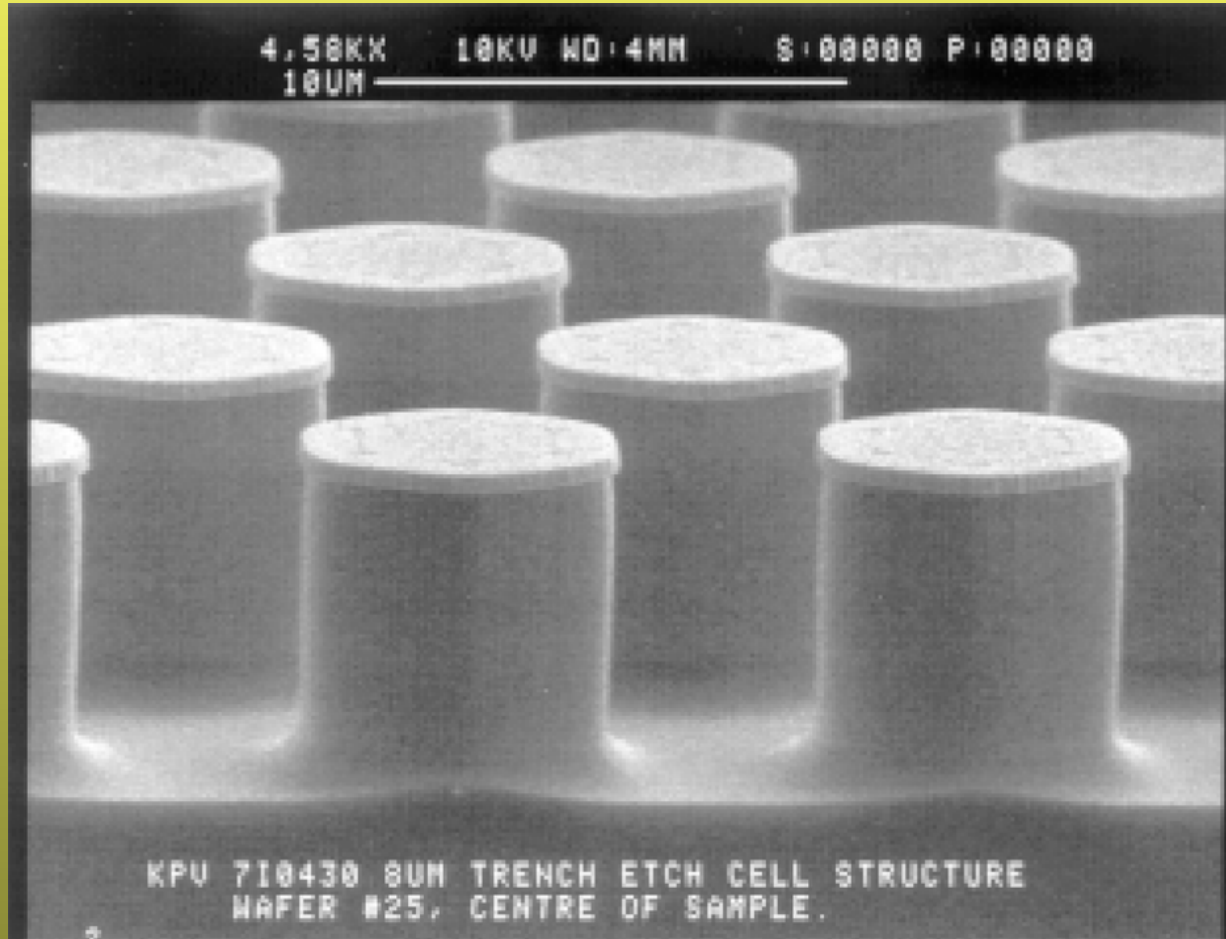


Stripe IGBT

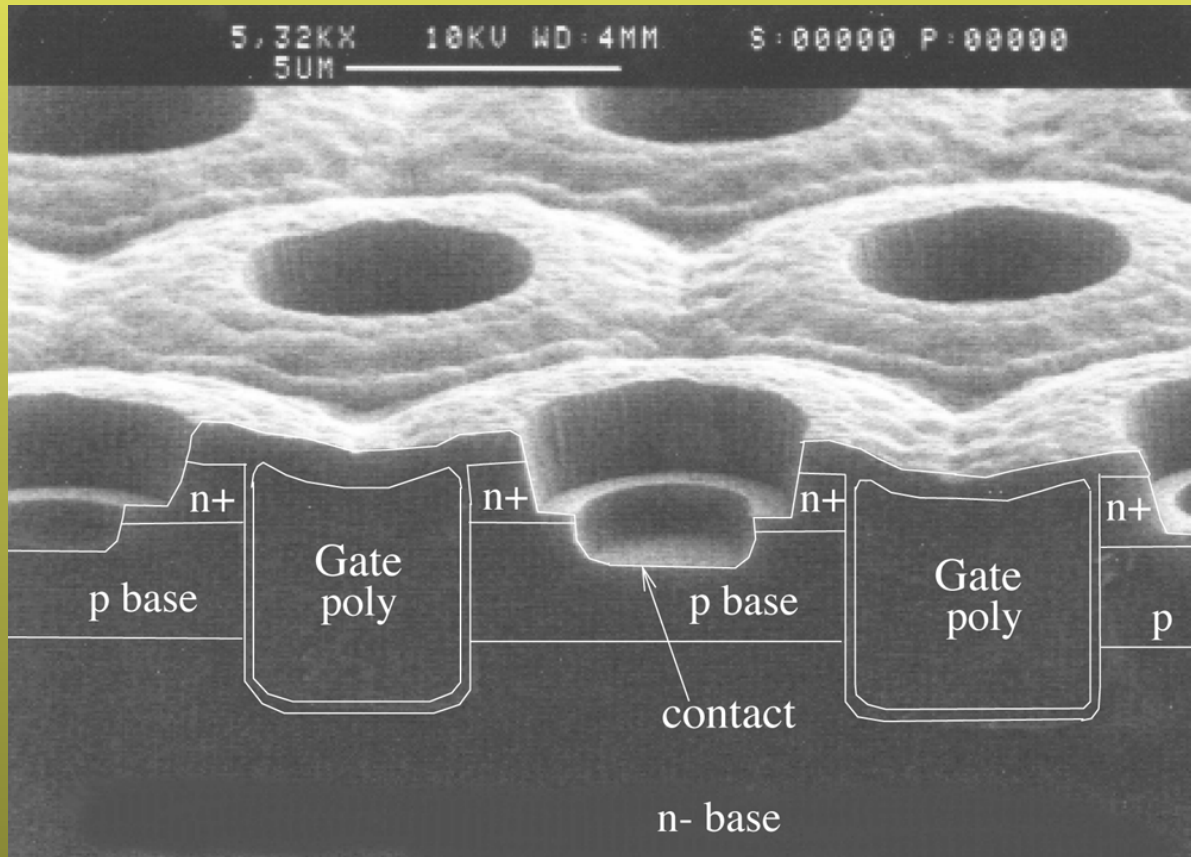
Hexagonal IGBT



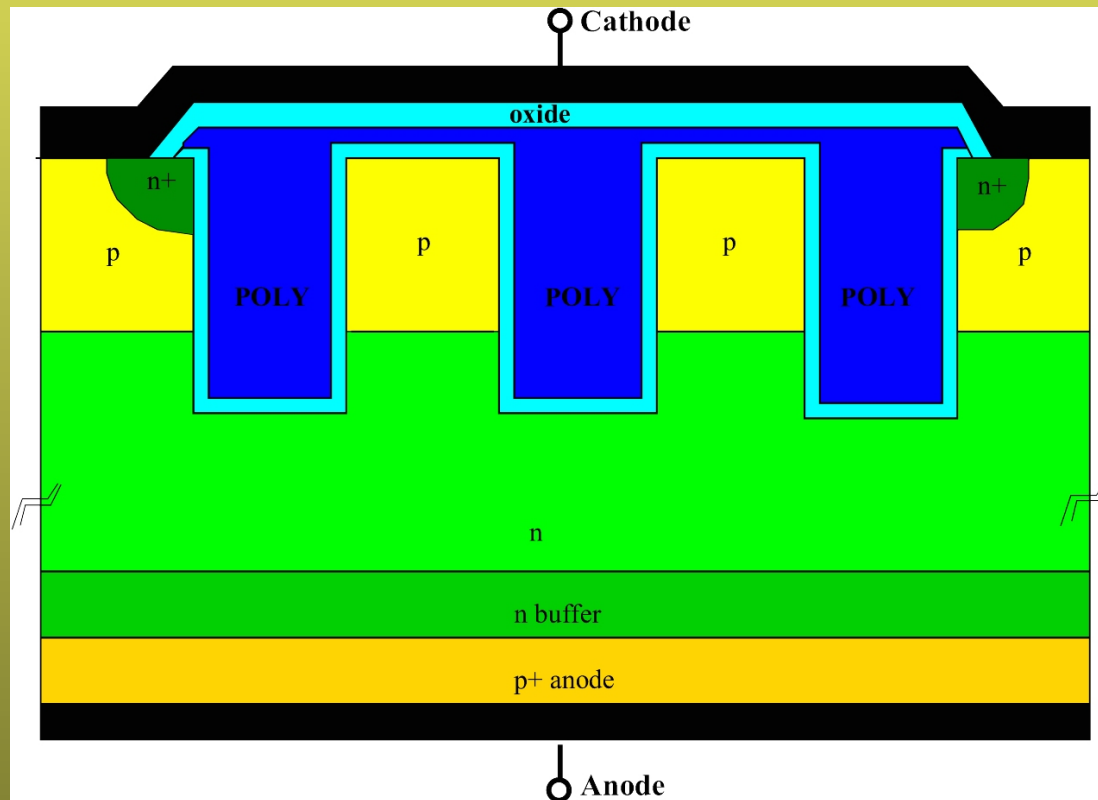
The Hexagonal Trench



Trench IGBT Showing Active Trench

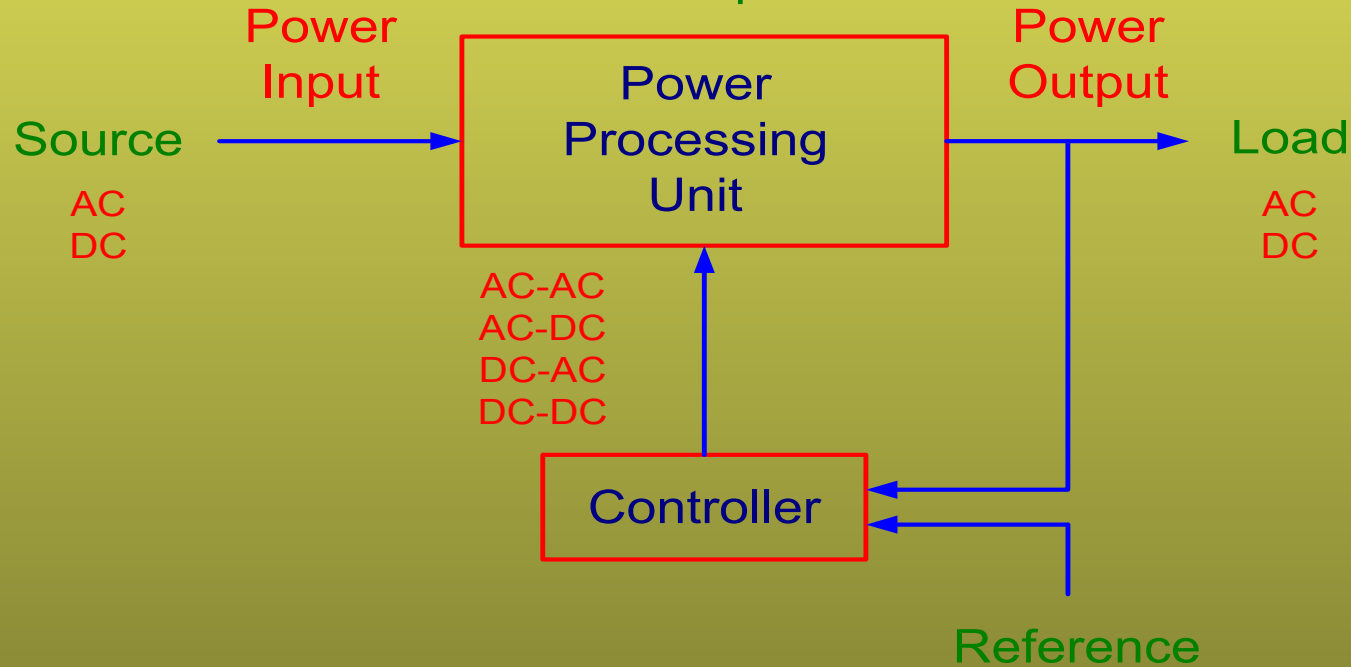


The Injection Enhanced Gate Transistor (IEGT)



Power Electronics Systems

Changes any electrical power source to any desired form voltage, current, and frequency output

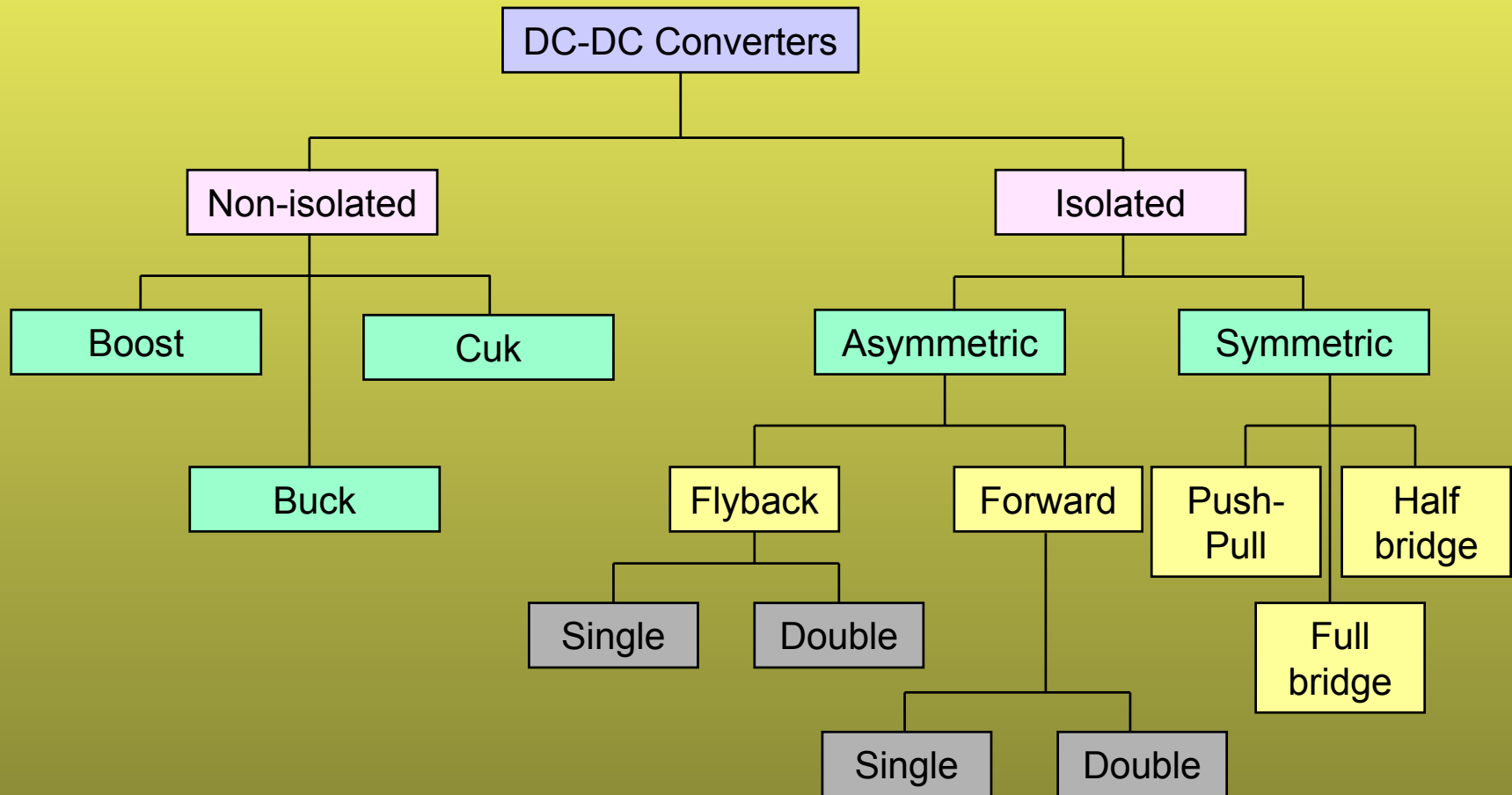


Power Electronic Circuits

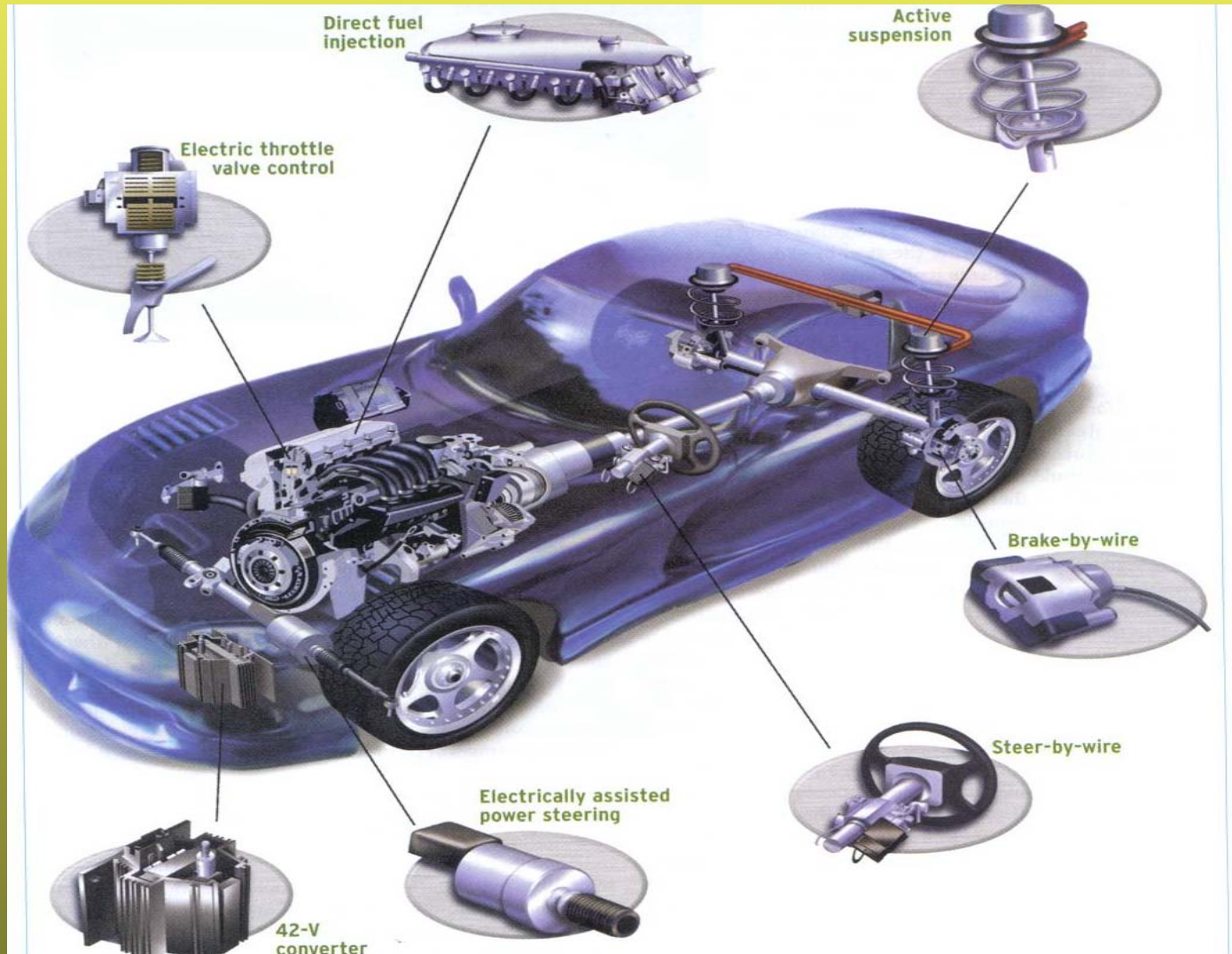
The power electronic circuits can be classified into the following types:

- AC-DC converters (controlled and uncontrolled rectifiers)
- DC-DC converters (dc choppers)
- DC-AC converters (inverters)
- AC-AC converters (ac voltage regulators)

DC-DC Converter Topologies



Automotive

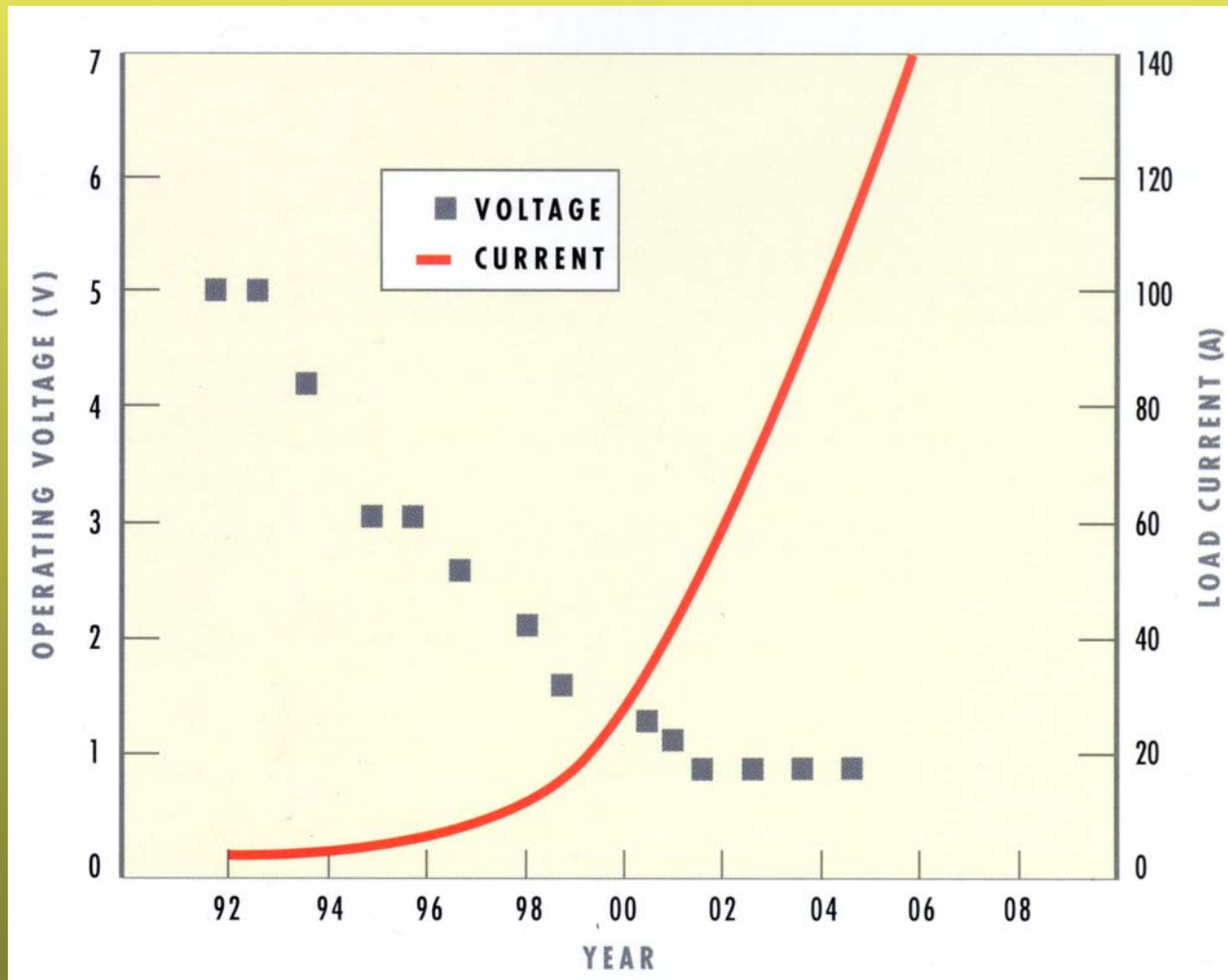


Advanced SynQor Quarter-Brick



- Ultra high efficiency, up to 91% at 3.3Vout
- High current output, up to 40 amps
- Industry standard size (1.45 x 2.3) and pin out
- Low profile, only 0.4" (10.2mm) high
- Low weight, 1.2 oz. (34g)
- No heatsink, baseplate or potting materials required
- Available in 48Vin and 24Vin

Synchronous Rectification

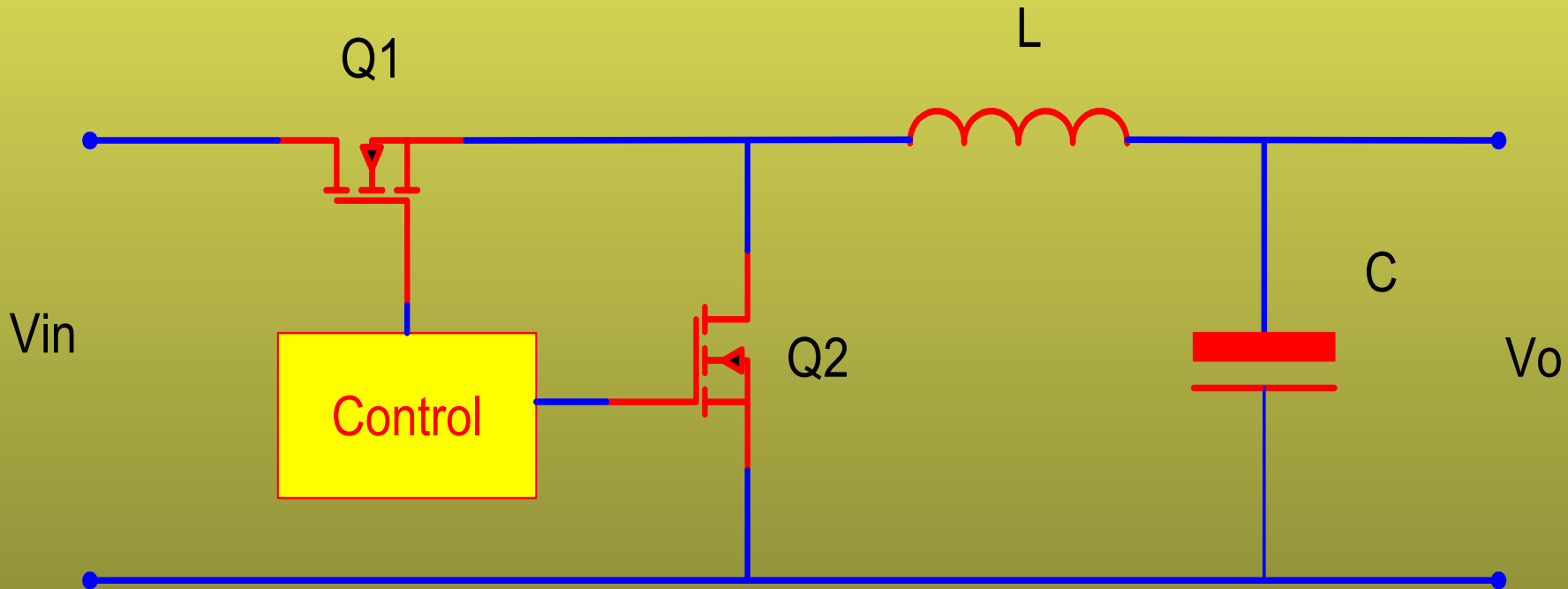


CPU Supply Specs

TABLE 1—INTEL VRM9.0 CPU-VOLTAGE AND -CURRENT SPECIFICATIONS

Symbol	Parameter	Minimum	Maximum	Units
V_{OUT}^{VRM}	VRM output voltage at VRM connector	1.53	1.600 ($=V_{ID}$)	V
V_{OUT}^{VRM}	V_{CC} core voltage at processor socket	1.475	1.600 ($=V_{ID}$)	V
V_{MAX}	Maximum nonoperating voltage		2.1	V
$I_{OUT.MAX}$	Maximal static current		60	A
dl_{OUT}/dT_{MAX}	Output-current slew rate		50	A/ μ sec

Synchronous Buck Circuit



DC-AC Conversion (Inversion)

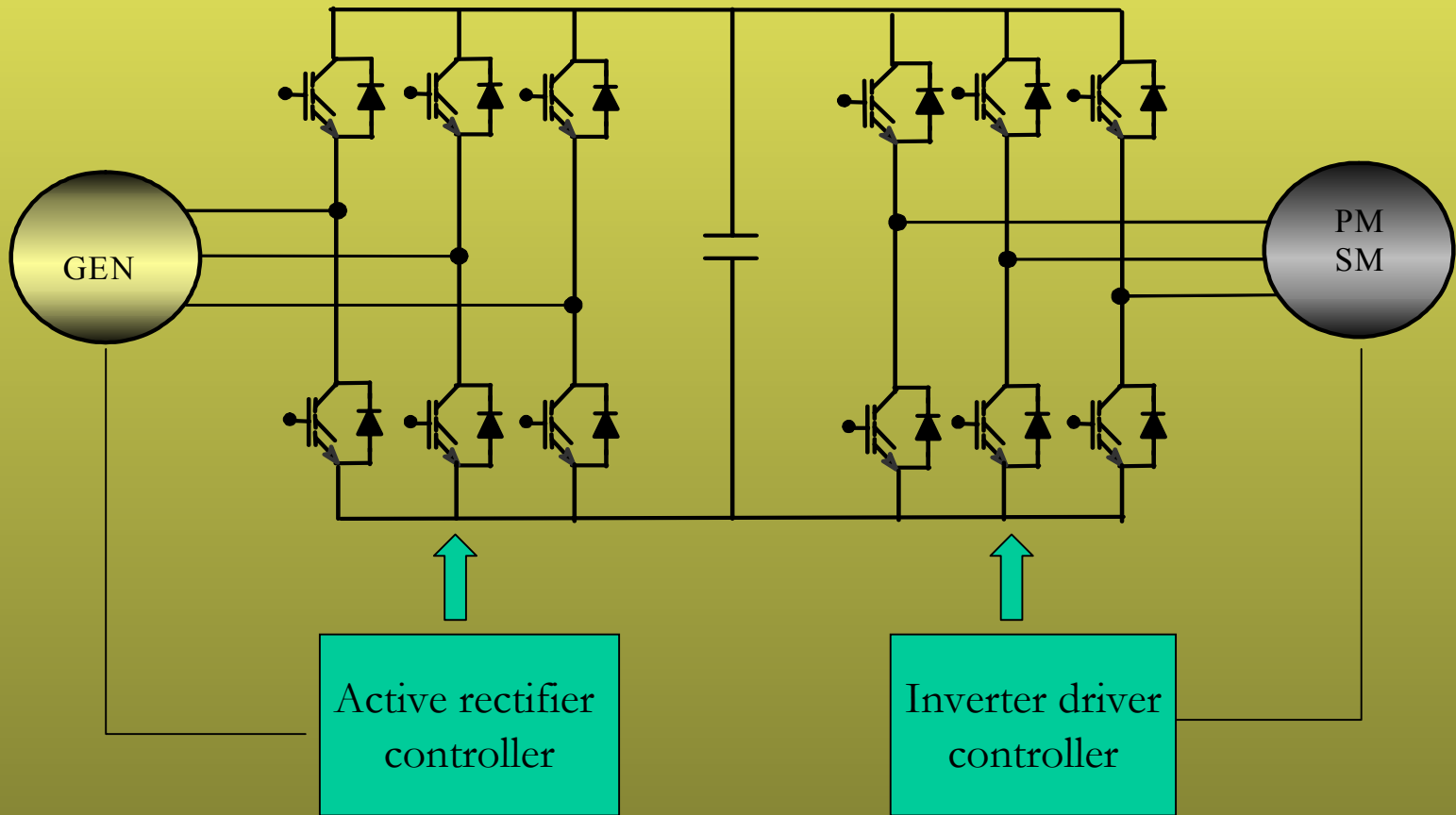


LTT Application in HVDC System

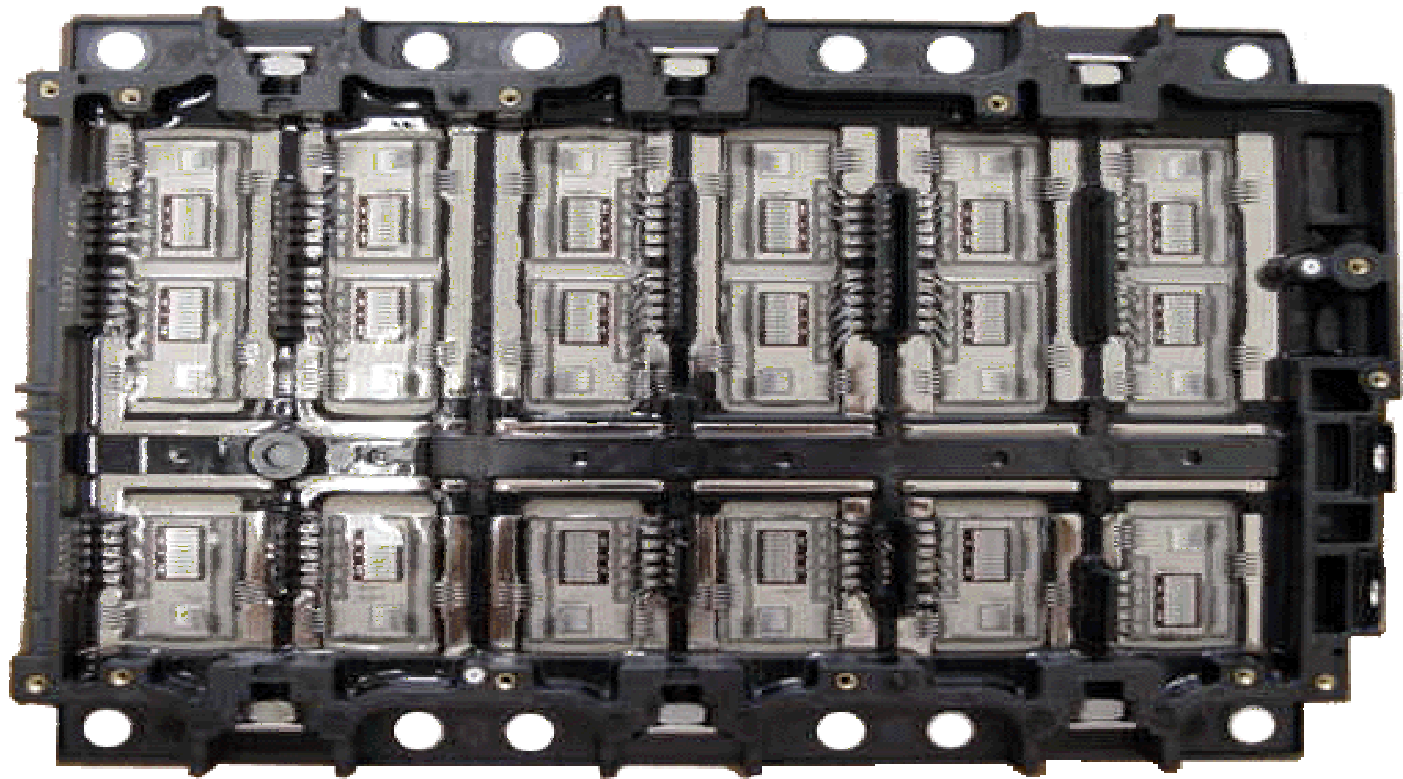


- Over 50% of electricity is consumed by motors
 - Domestic (Washing machine, Refrigerators, air conditioning..) < 2kW
 - Factory Automation – 100kw – MW
- Simple on/off wastes up to 50%

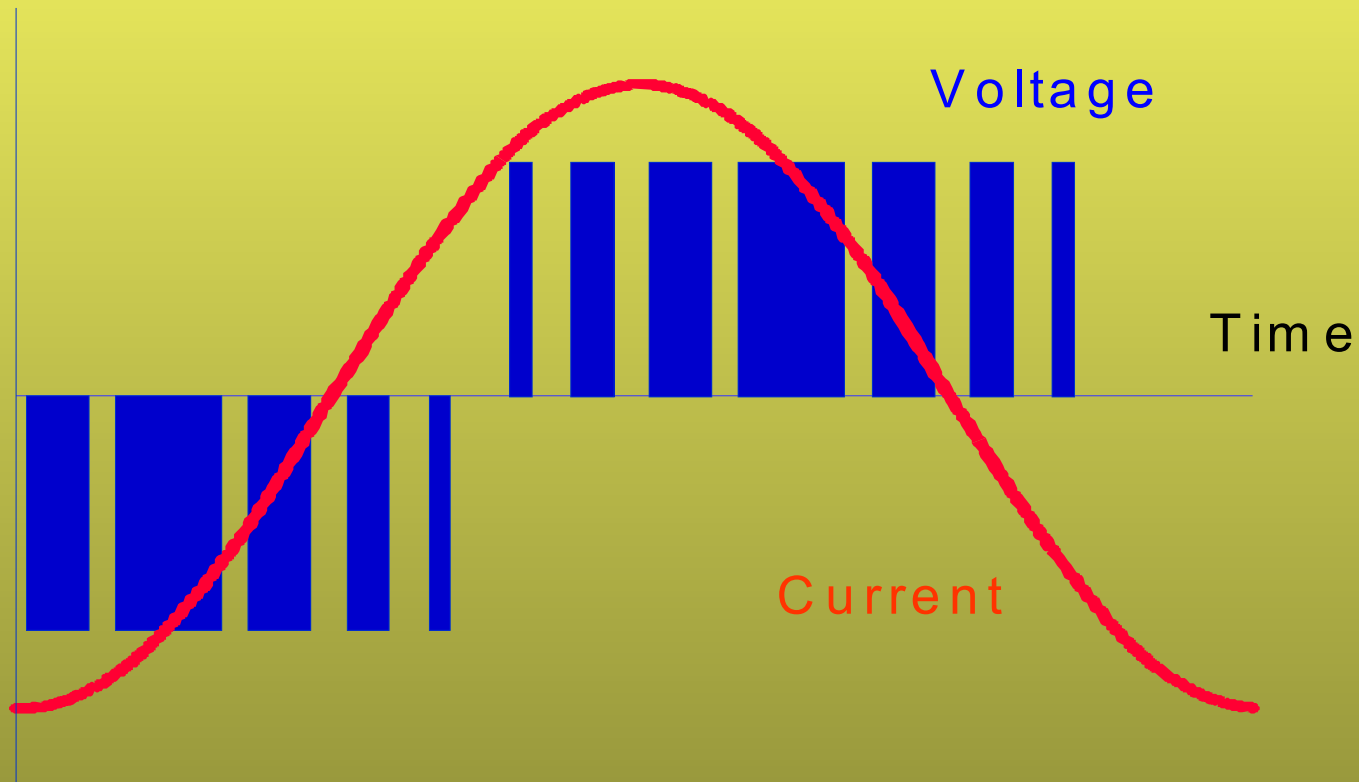
Application	Units/yr	Ave power consumption	% Savings	Power Savings
Fridge/Freezer	77.8M	700kWHr	60%	32.7B kWHr
Air Conditioning	31.5M	750kWHr	60%	14.2B kWHr
Washing Machine	55.6M	930kWHr	64%	33.1B kWHr



IPM

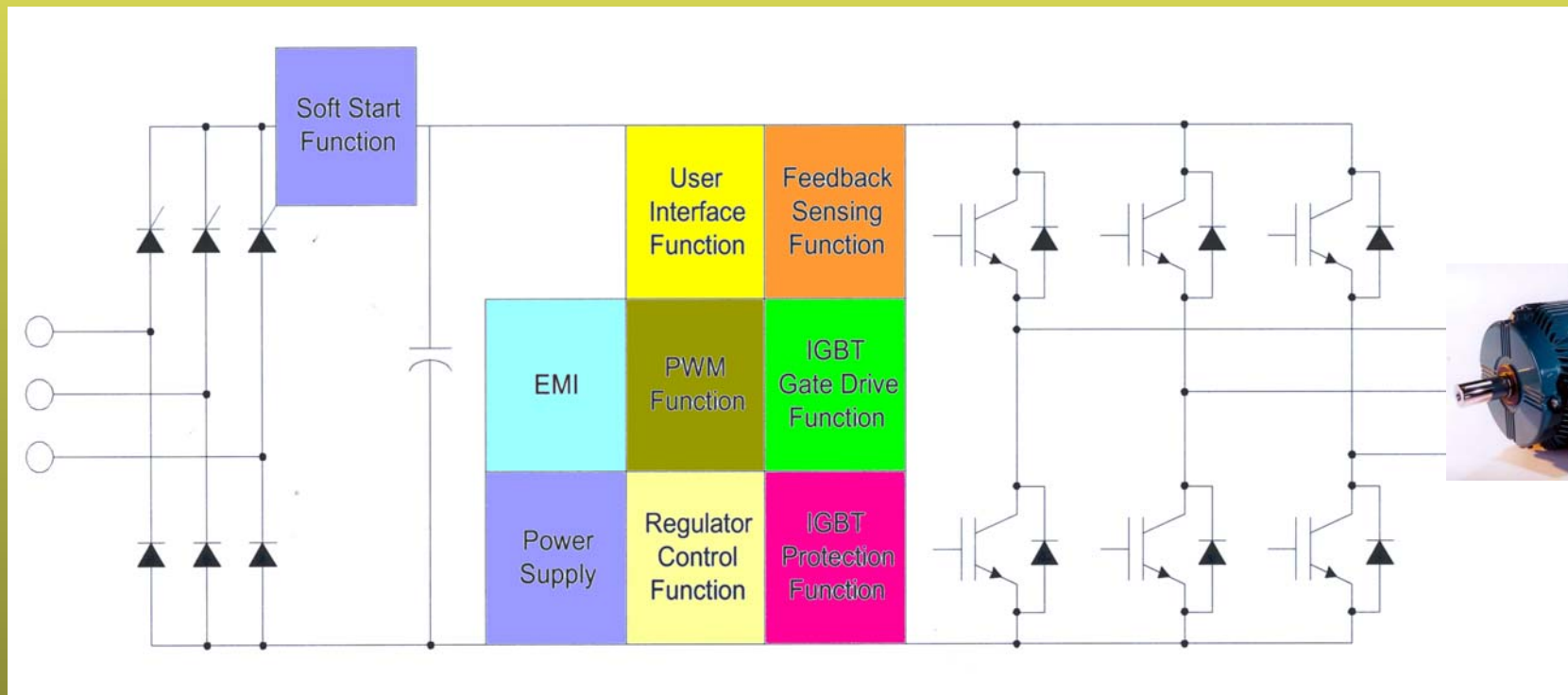


PWM VSI

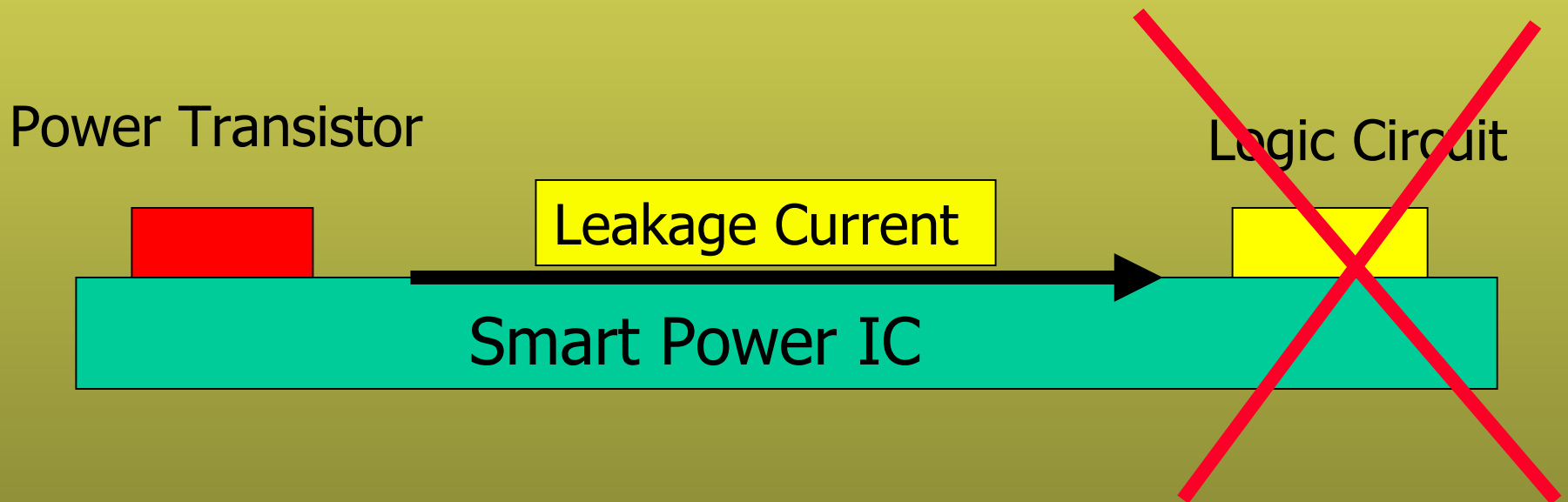


Simplified diagram showing the pulse width modulated output from an inverter drive.

Functional blocks in inverter



Devices and Isolations for PICs



Devices and Isolations for PICs

Power Transistor

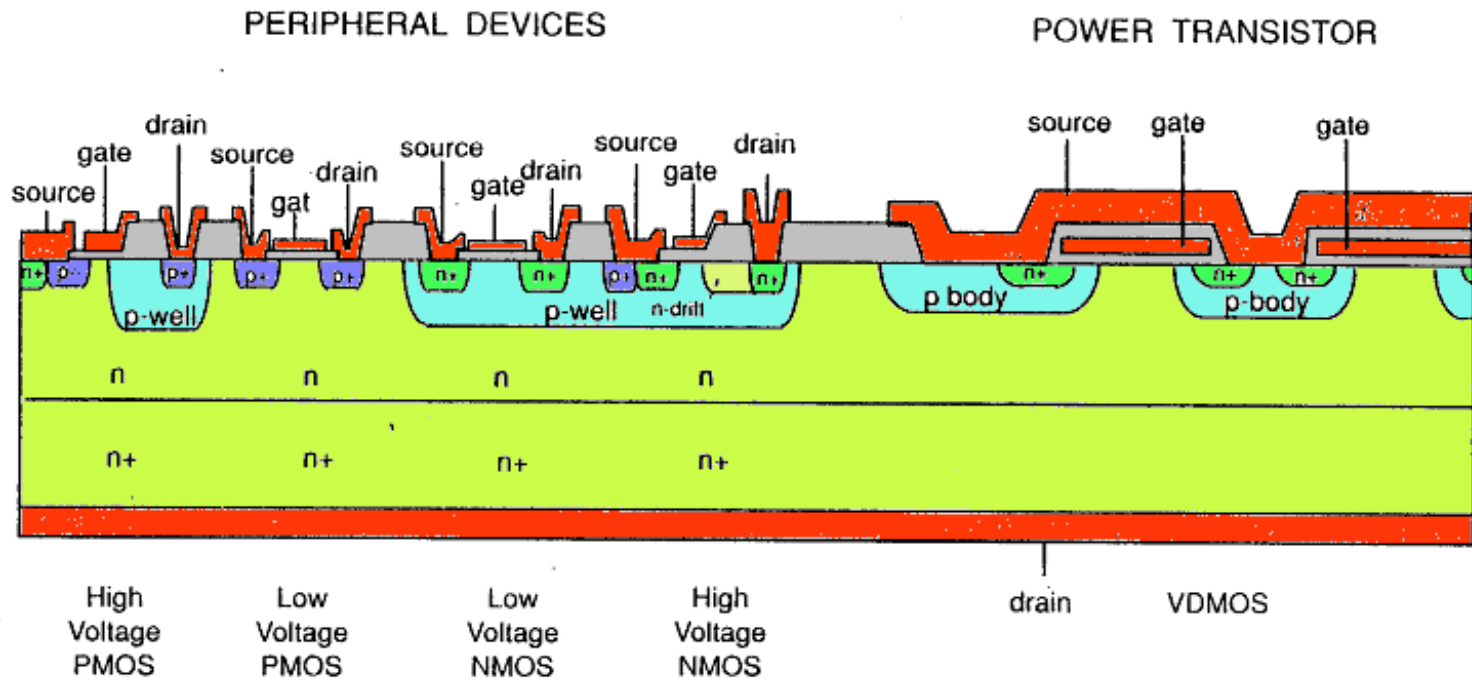
Logic Circuit

Isolation

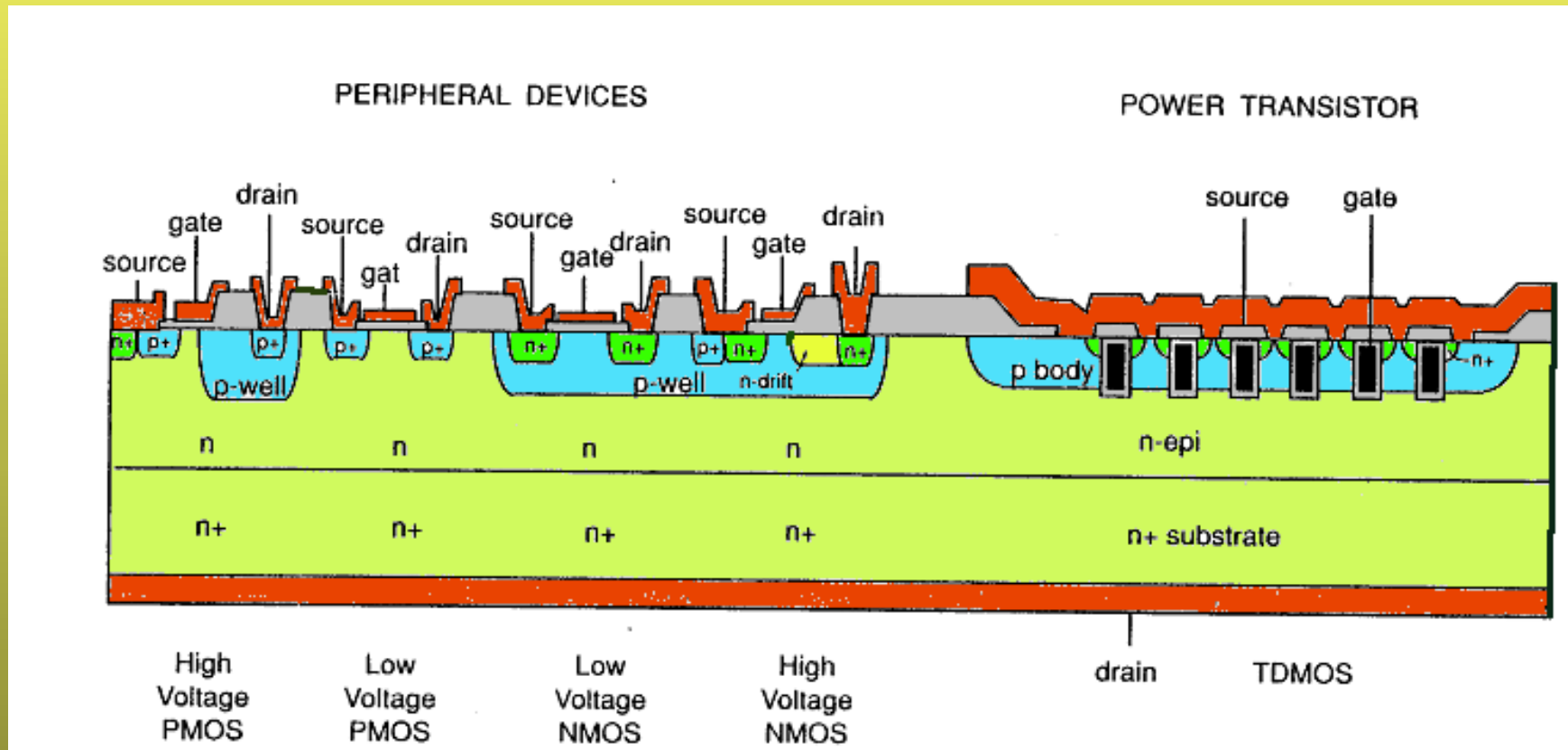


Smart Power IC

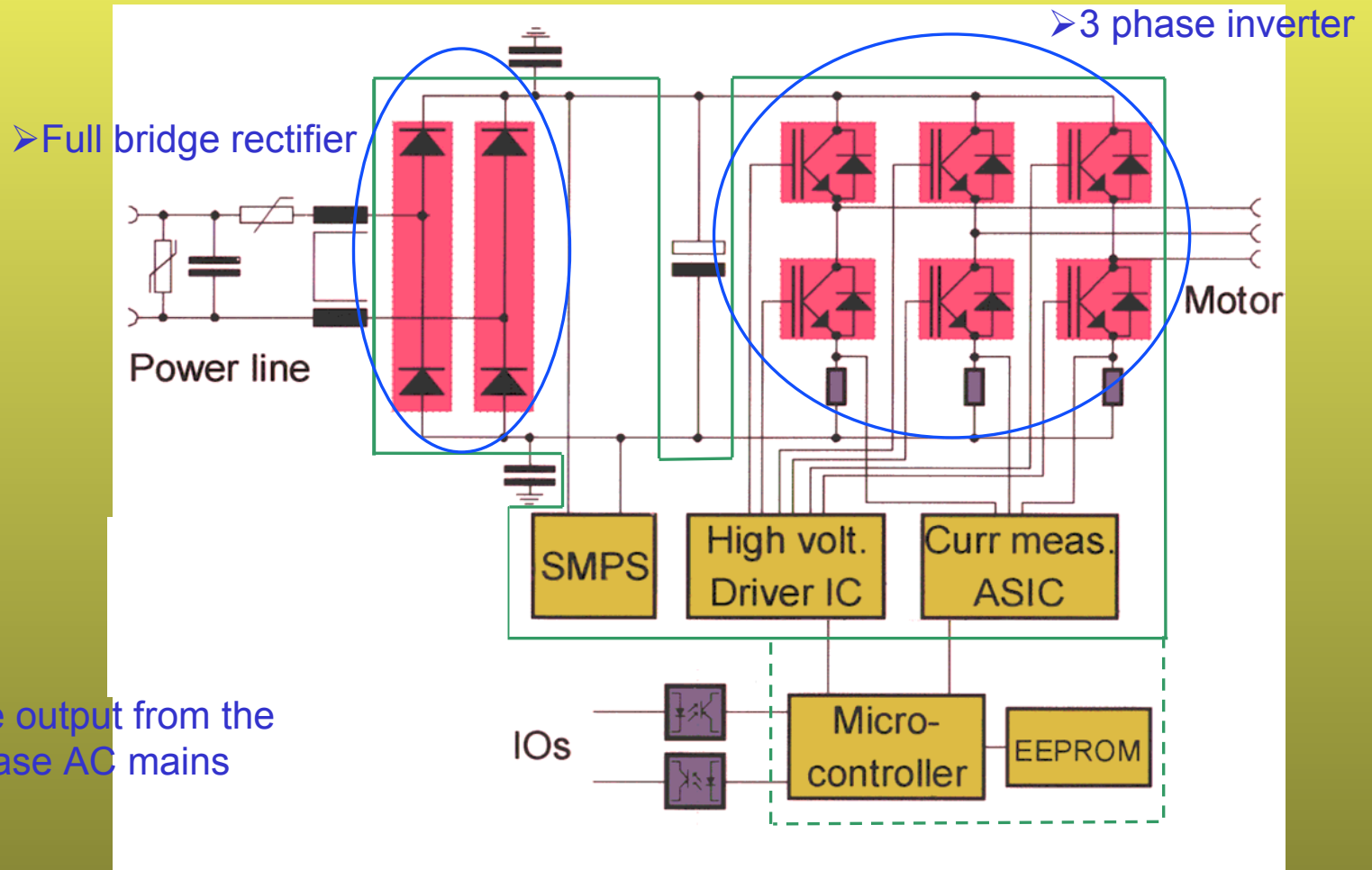
A High Current PIC Process with Dense CMOS and Power Switch



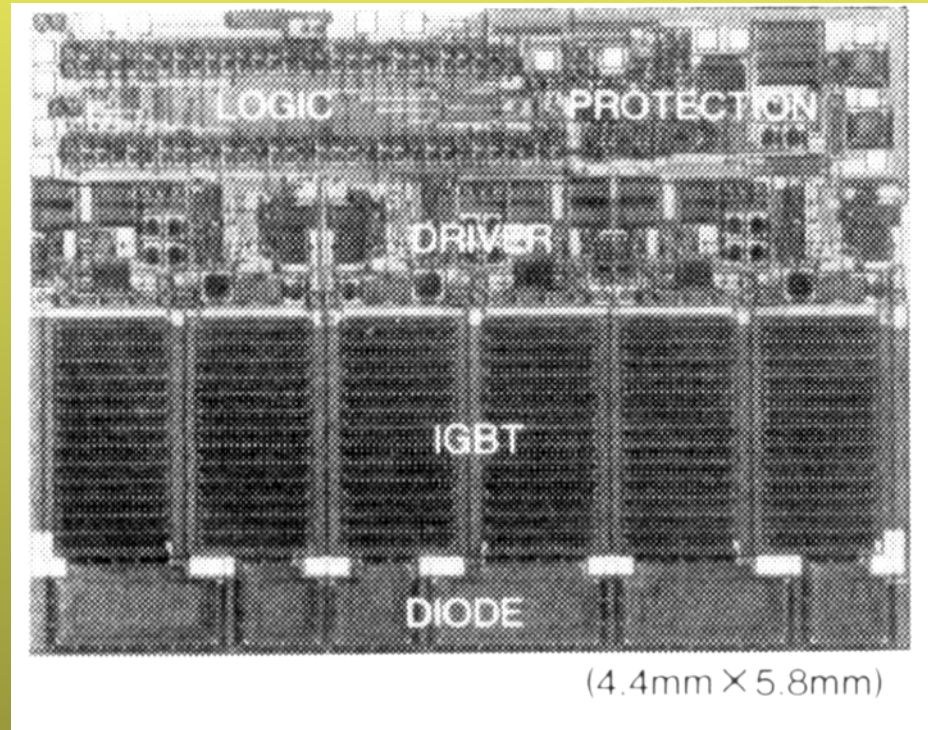
Cross-Section of a High Current PIC Process Incorporating Trench DMOS as the Power Switch



A Variable Frequency Electronic Drive for a 250 - 1kW Rated Electric Motor



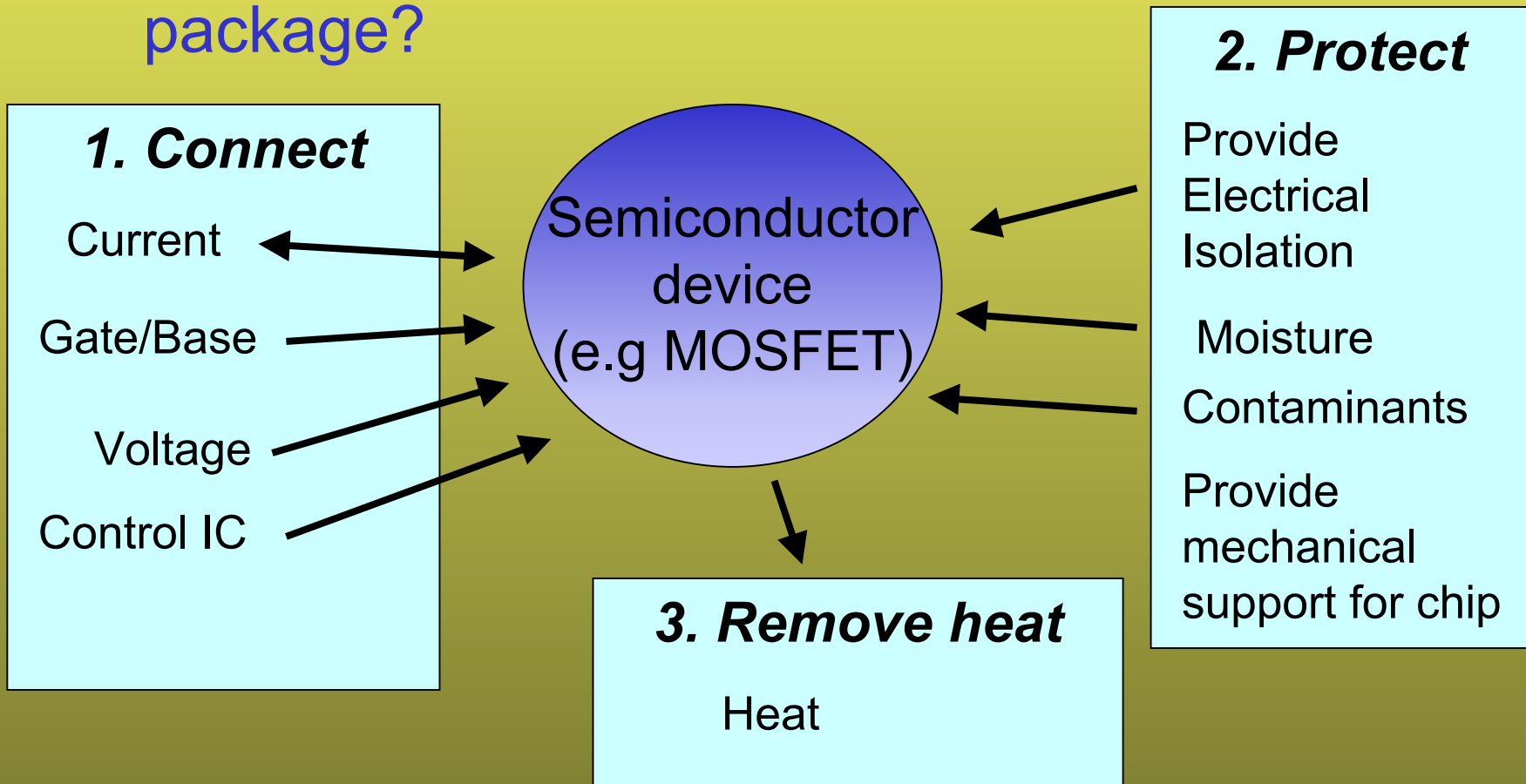
Power Integrated Circuit for Motor Control Marketed by Hitachi (only Available in Japan)



Features: 250V, 1A

Packaging

- What are the key functions of an electronic package?



power electronic package

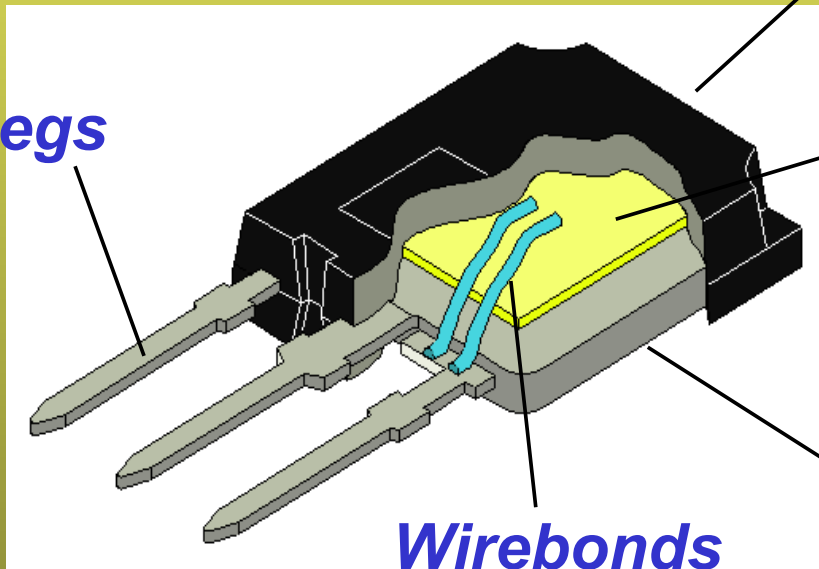
- Plastic encapsulated package

– TO-247

Encapsulant

Legs

Power die

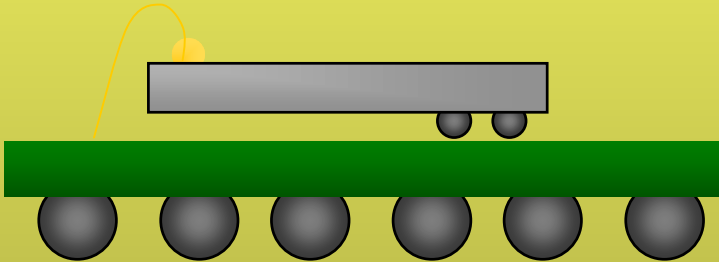


Wirebonds

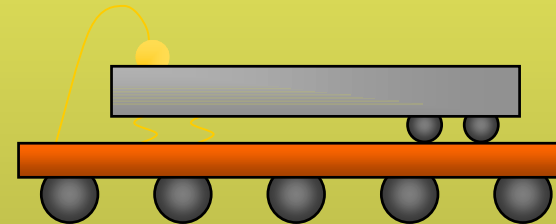
*Copper header
to remove heat*

Packages defined

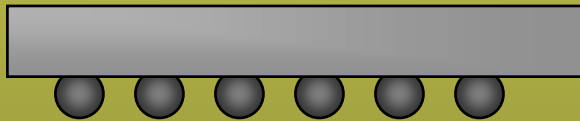
Examples of IC packaging technology



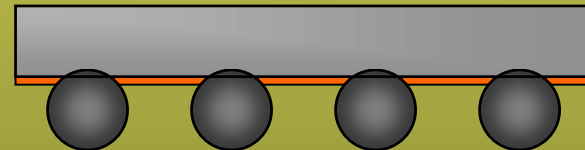
BGA:- Ball grid array



CSP- Chip Scale Package



Flip Chip



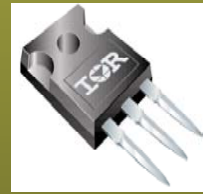
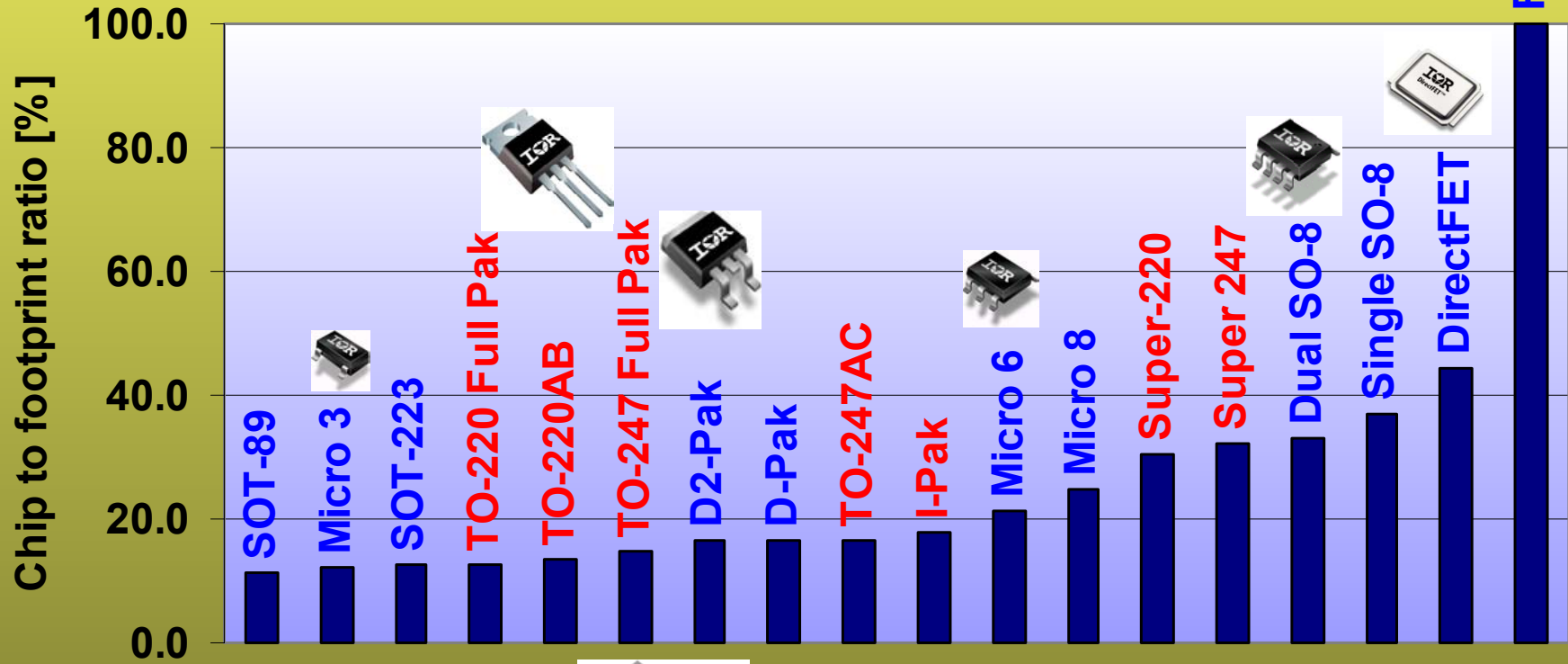
WLP-Wafer level package

Strong focus on high I/O count, space saving and low inductance packaging

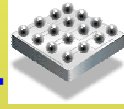
Chip to Footprint ratio for SMD and through hole packages

RED = Through hole device
 Blue = Surface mount device

hole packages

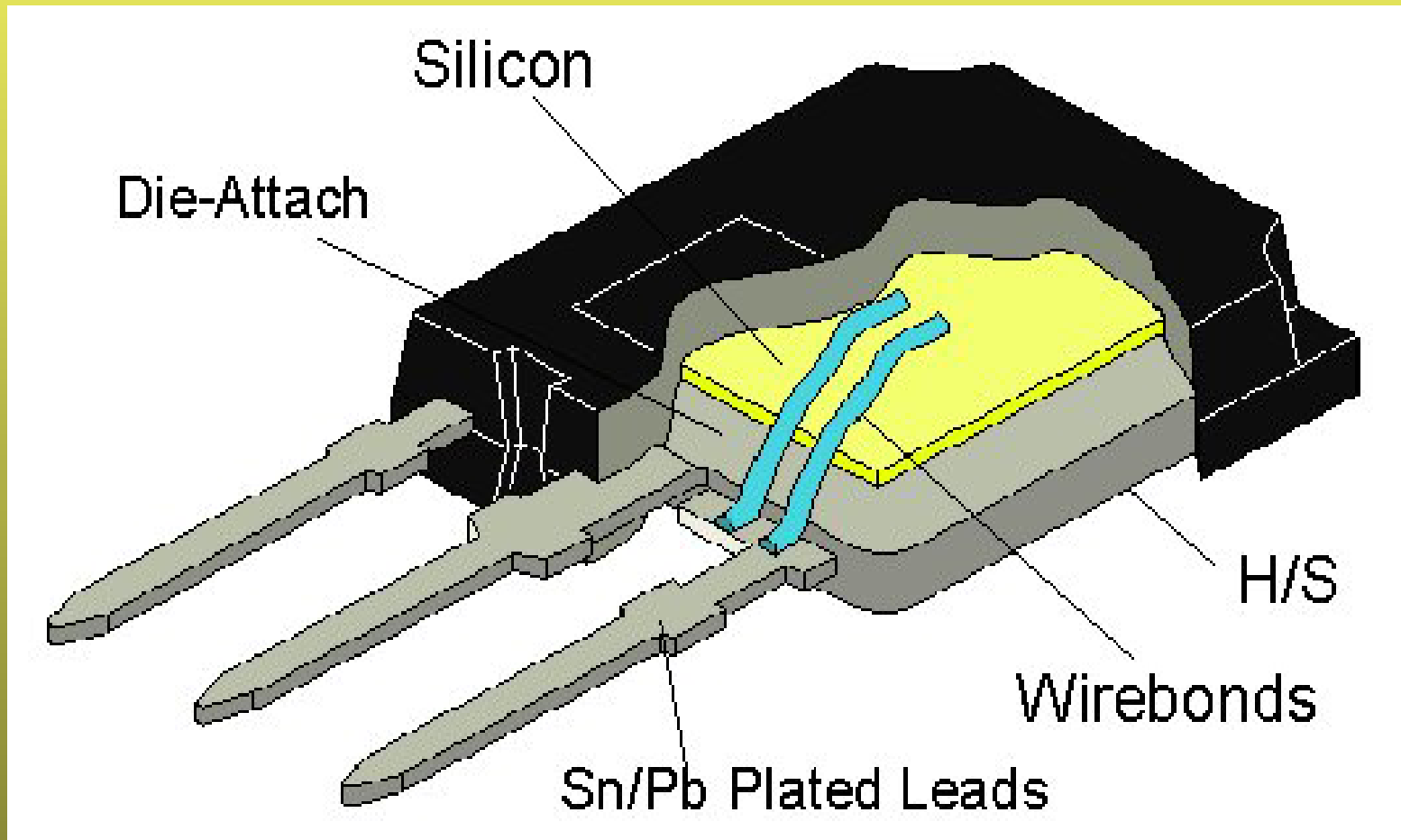


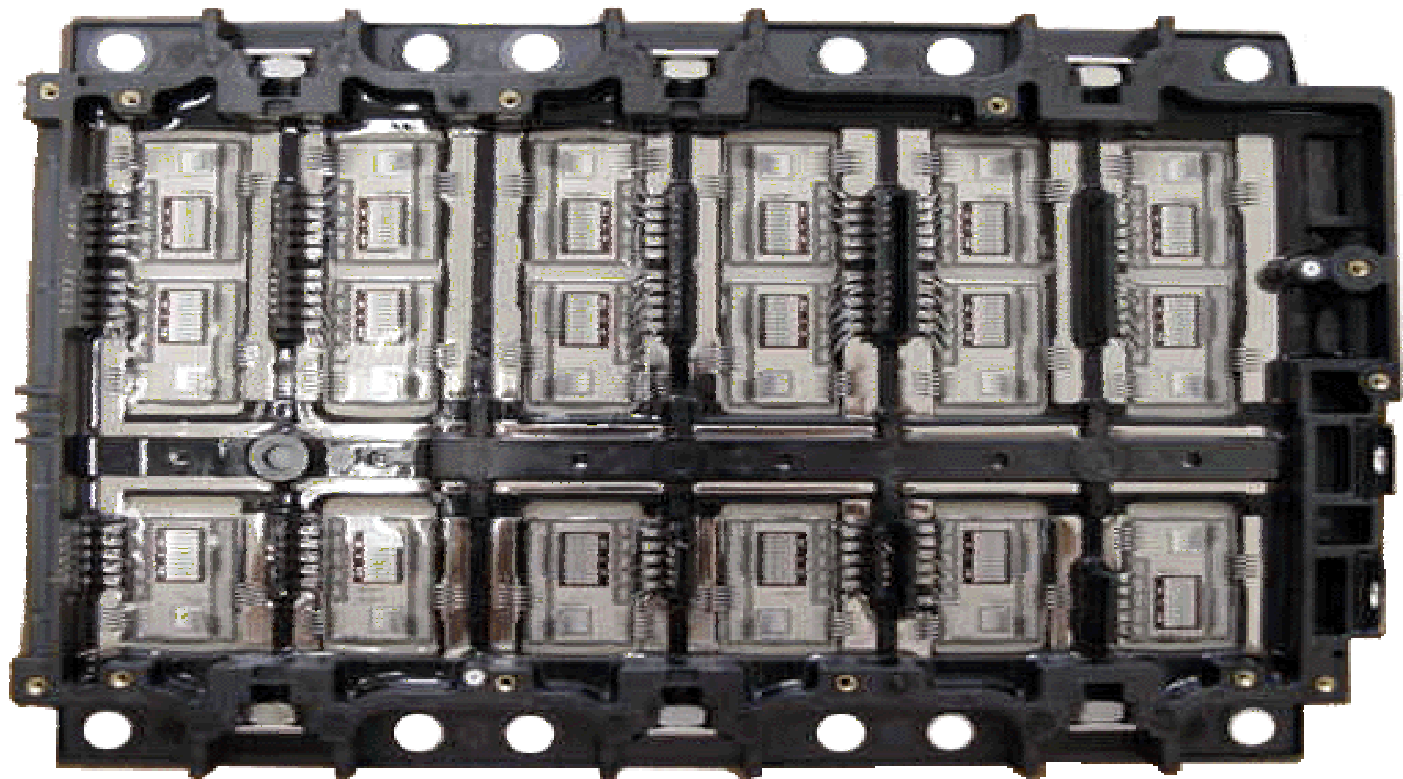
Package type



FlipFET

12. Construction of Power Semiconductors



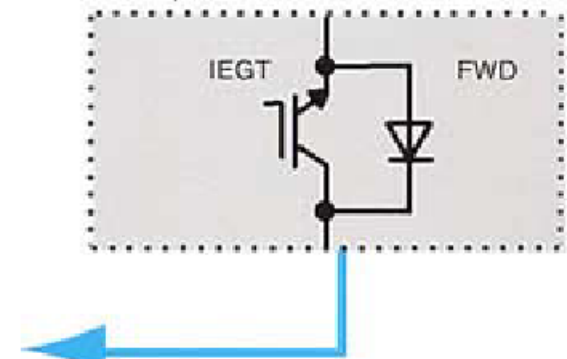


- Low losses with smaller snubber circuit
- Low gate power based on voltage driven MOS (Metal Oxide Semiconductor) gate
- Fast switching speed



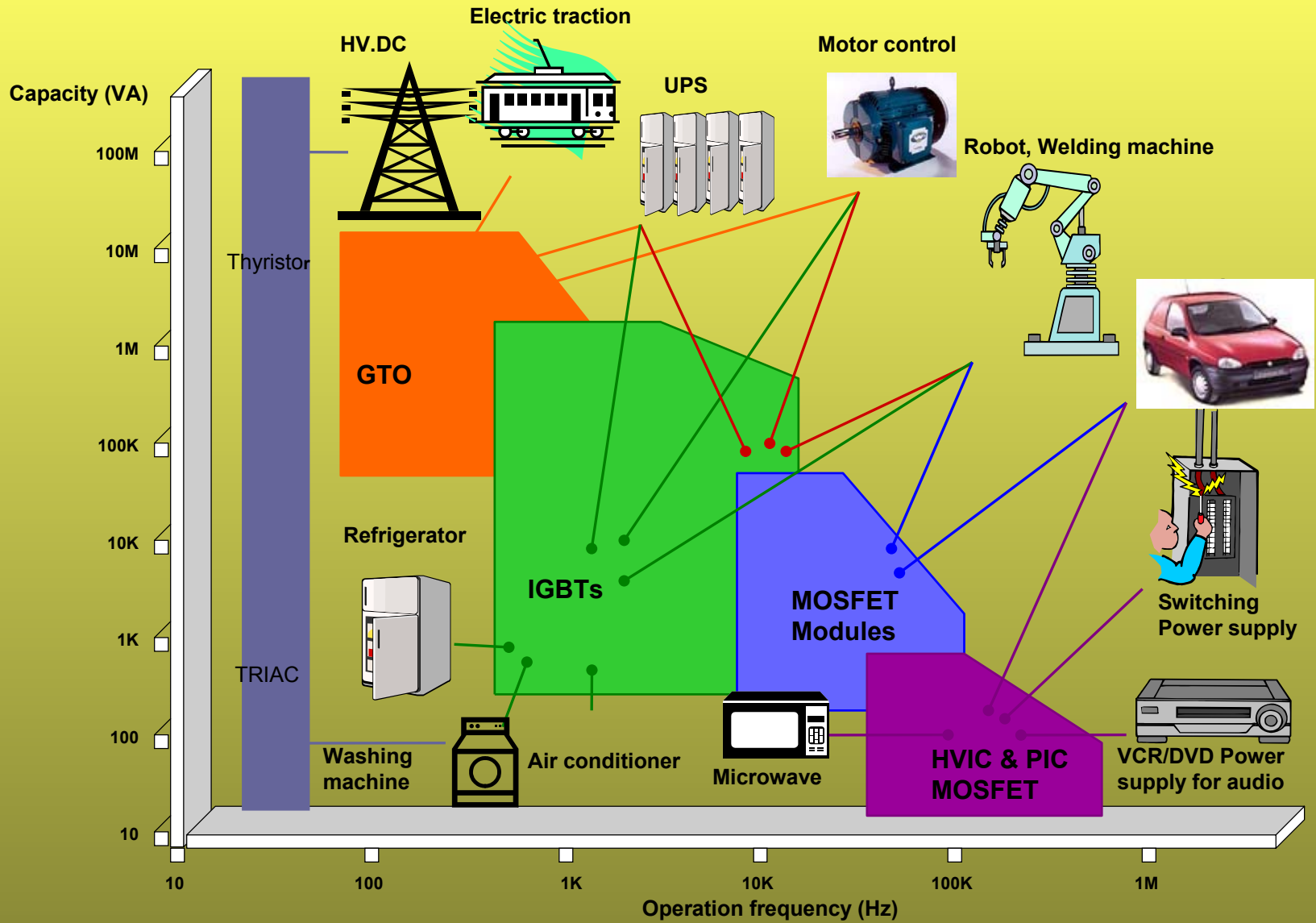
Outside View of IEGT

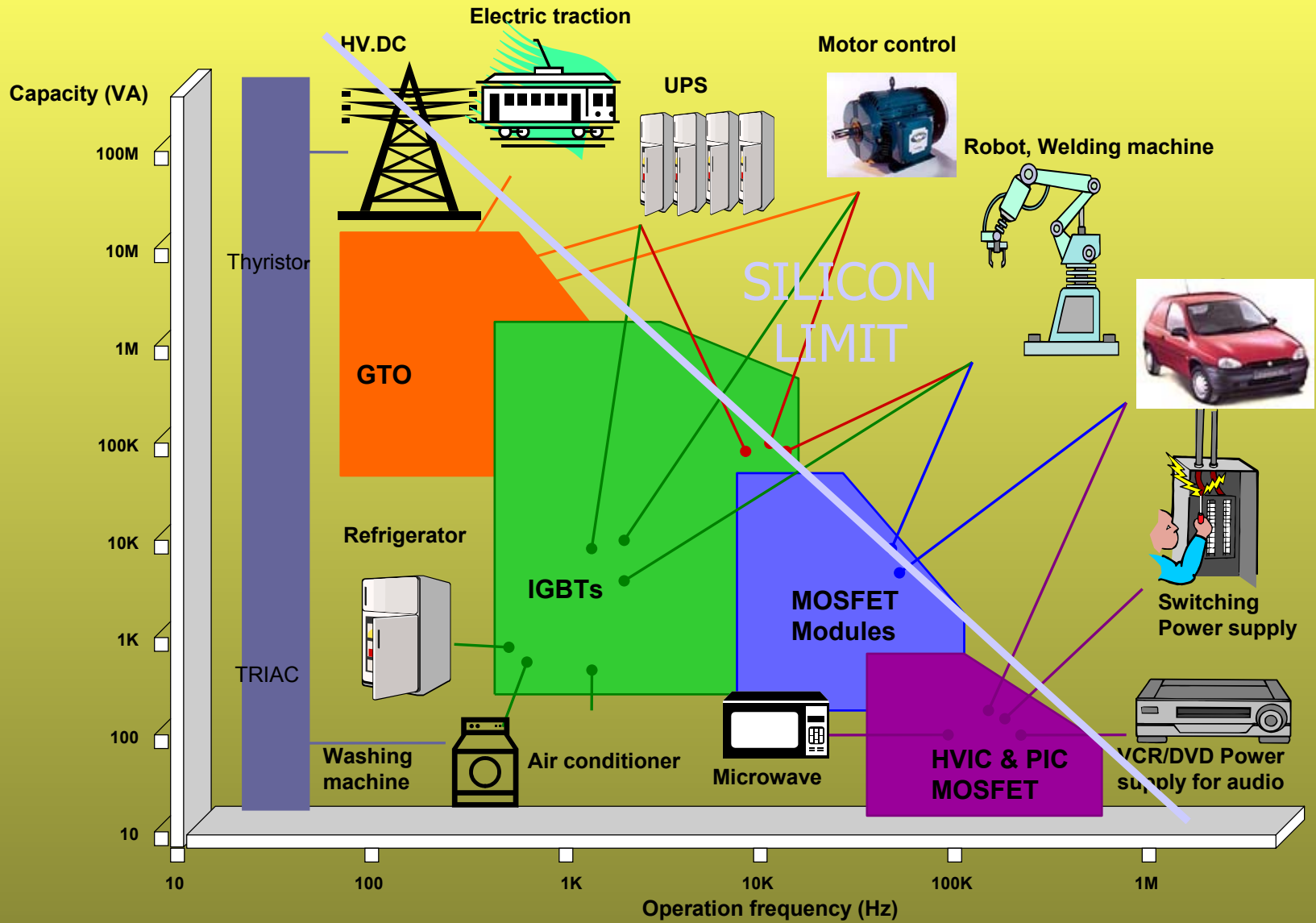
FWD chips are included in the IEGT shell.

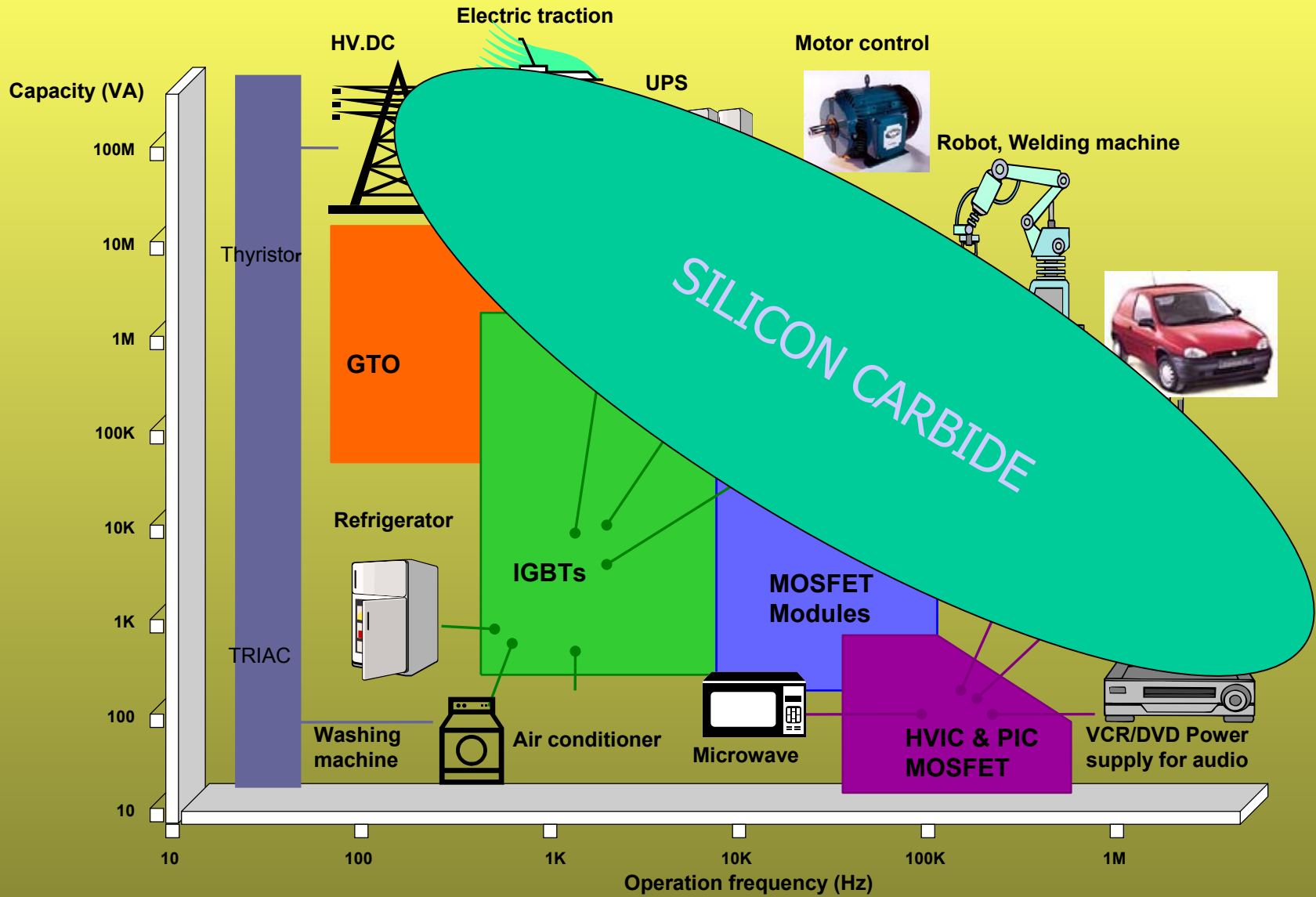


FWD : Free Wheeling Diode

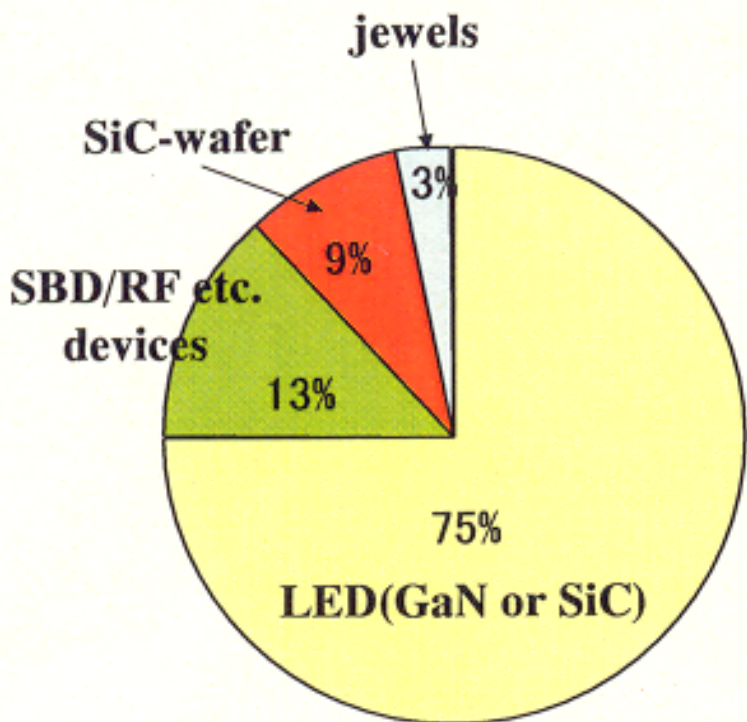
Silicon Carbide Power Devices







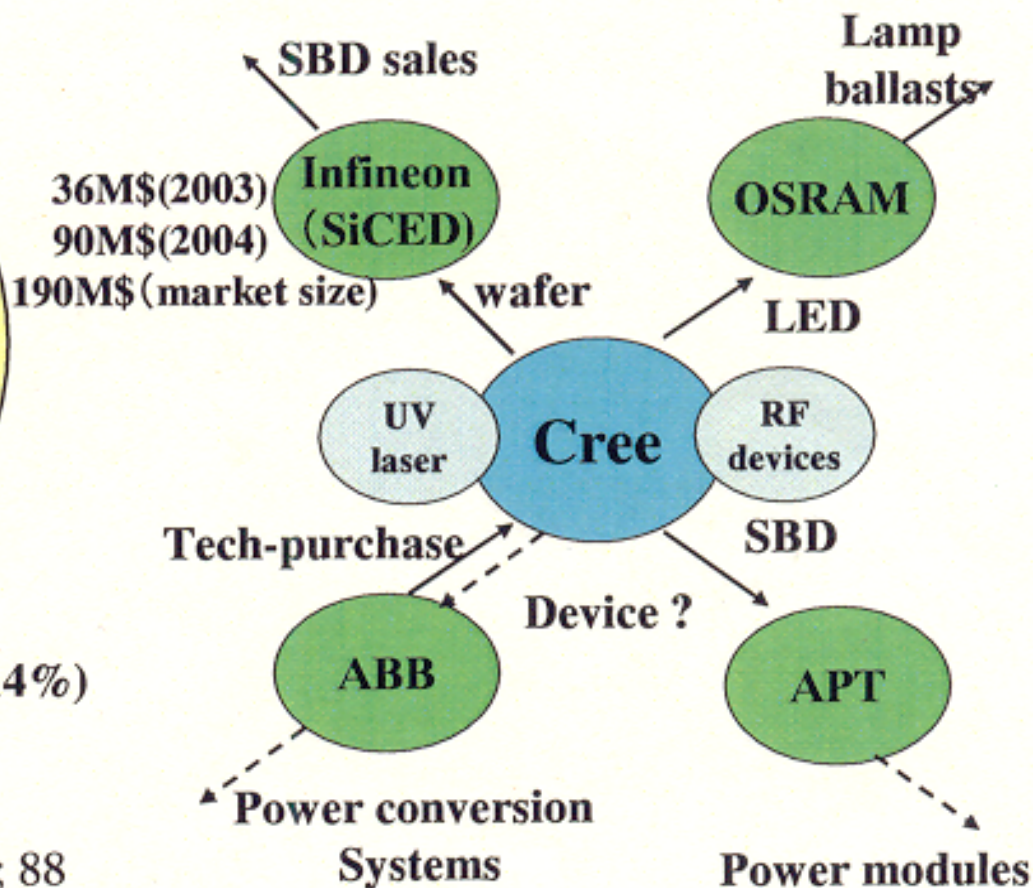
Trends of CREE Co. (2003) <http://www.cree.com>



Sales ; 218M\$ (profit-rate >14%)

Employee ; 1221 people
 products; 865
 research; 168
 business/manage; 88

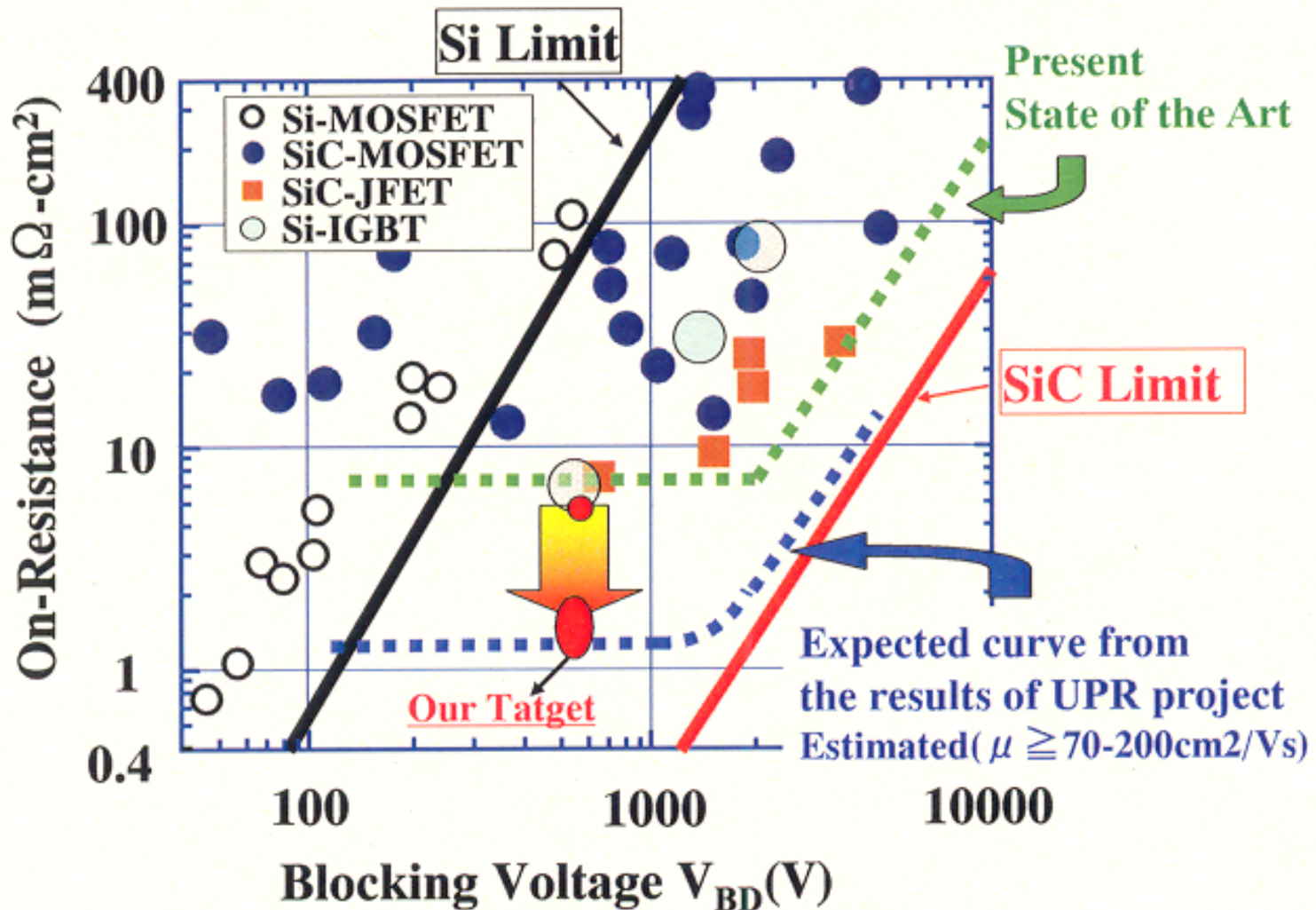
Patents ; 207(USP), 98(Wo)



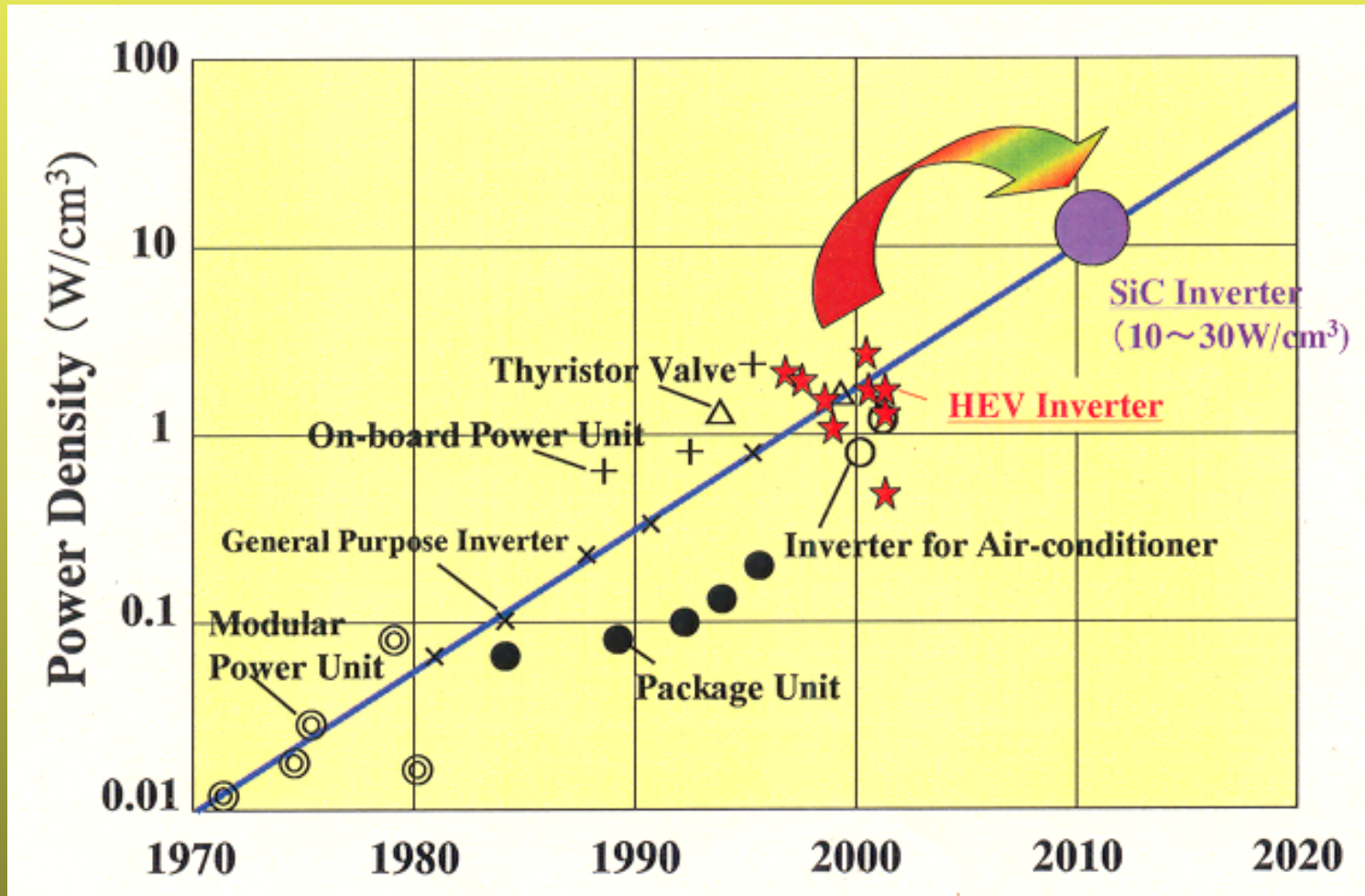
SiC Applications



On-state limit for Switching Devices

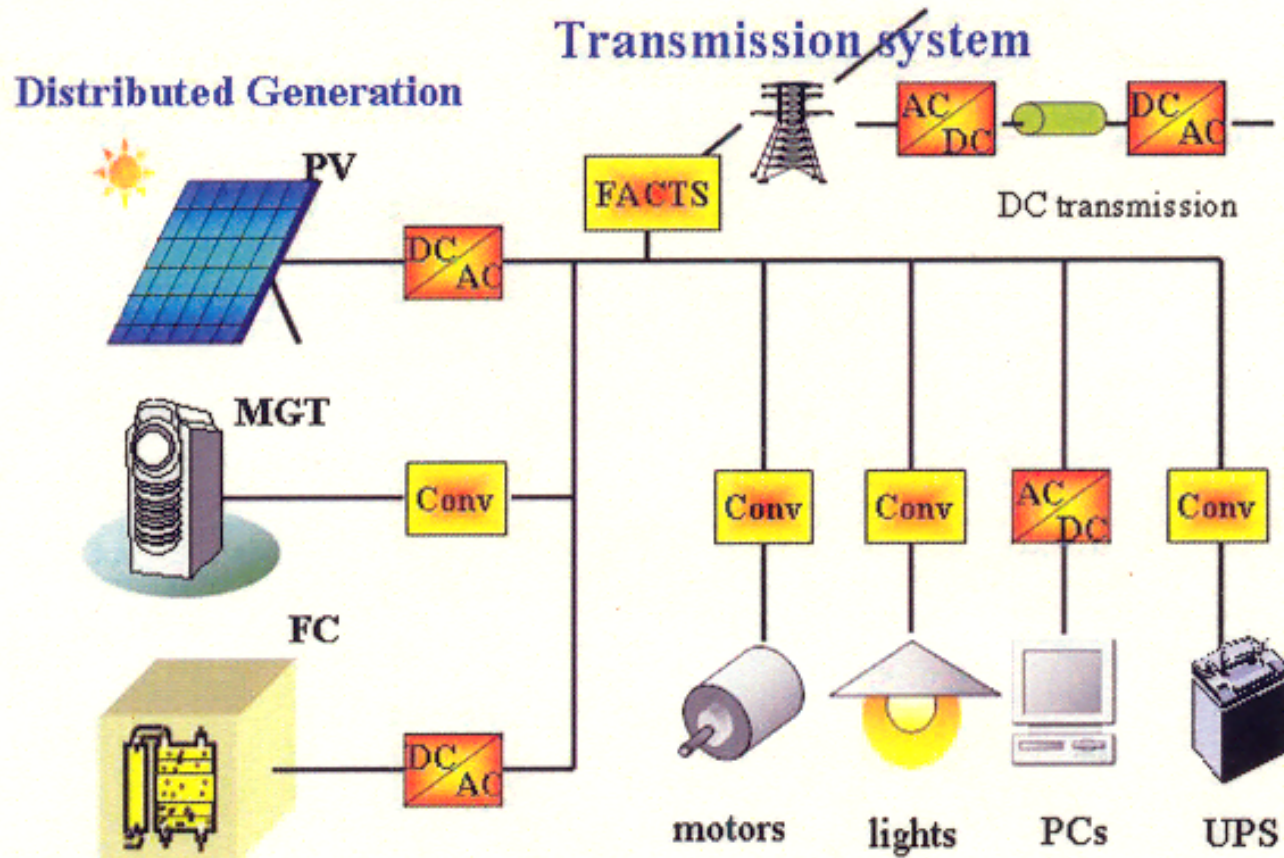


Trend for power density in power converters



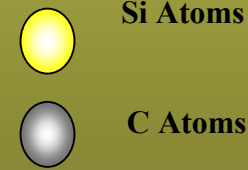
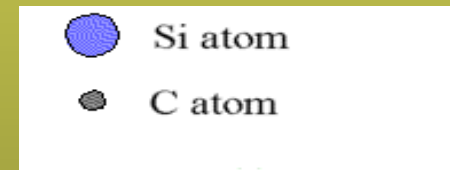
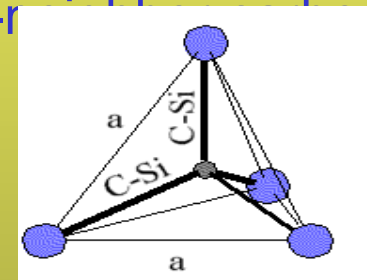
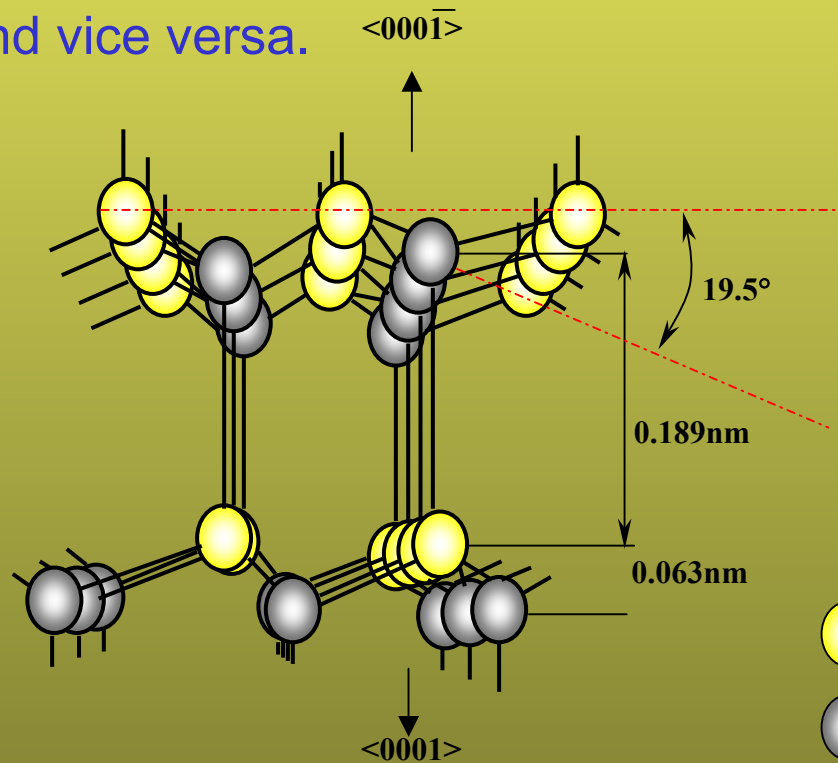
Power Systems in the Future

The new power electronics will play very important role in all part of the future power system.



What is Silicon Carbide ?

- Silicon Carbide (SiC) exists in several hundred forms known as polytypes.
- Each silicon atom bonds to four nearest-neighbor carbon atoms, and vice versa.



SiC Polytypes

- Crystal structure dictates the polytype or form of SiC.
- Difference between polytypes is the stacking order between double layers of carbon and silicon atoms.

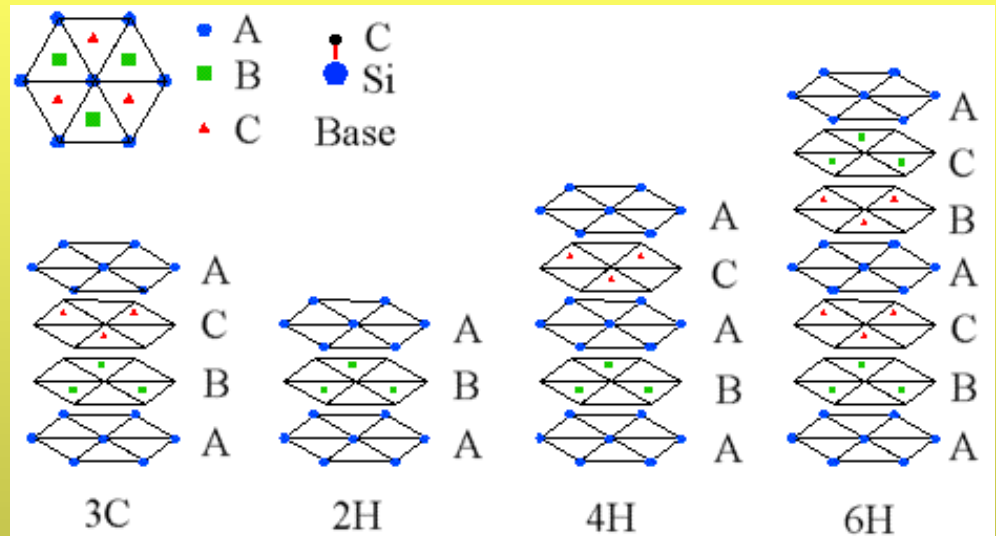


Fig. 5. The stacking sequence of double layers of the three most common SiC polytypes.

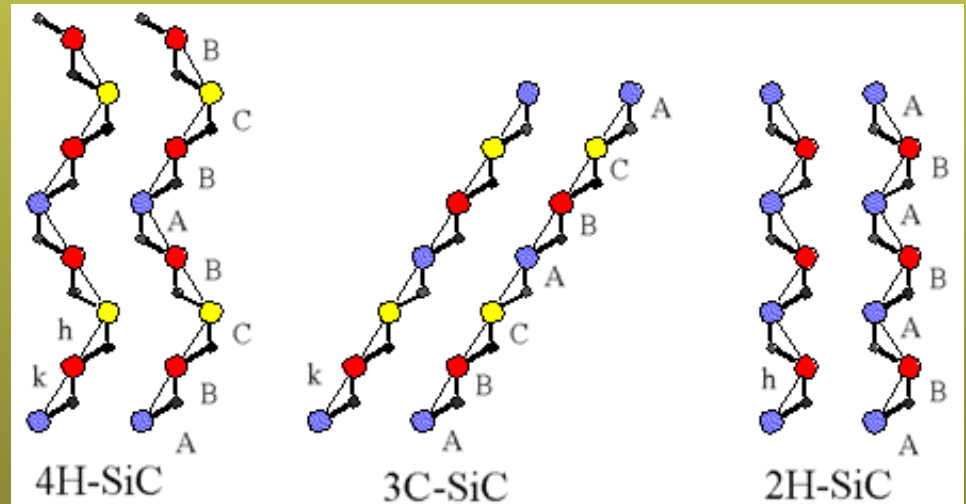
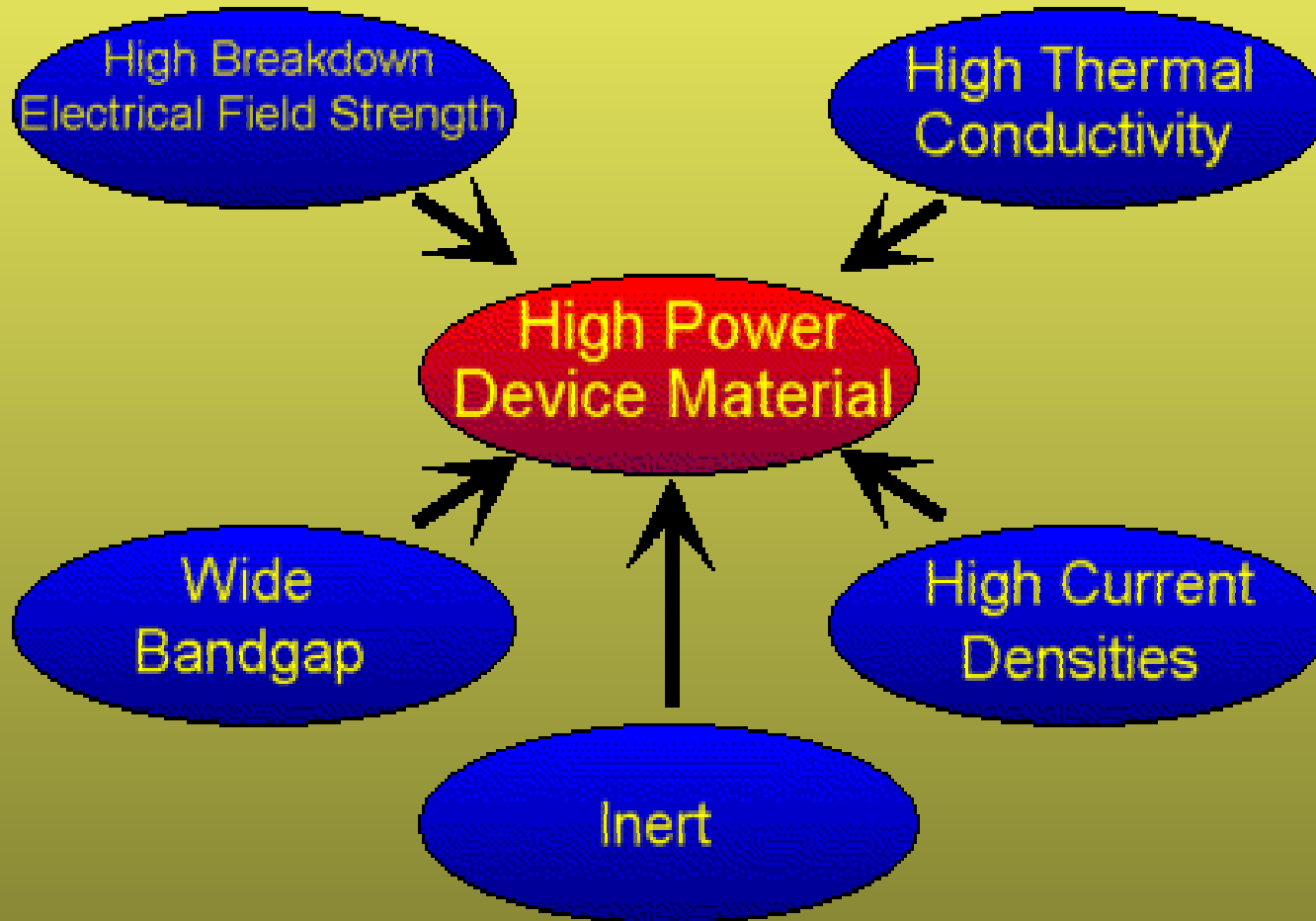


Fig. 7. The [11 $\bar{2}$ 0] plane of the 4H-, 3C-, and 2H-SiC polytypes.

Alternatives to Silicon Technology

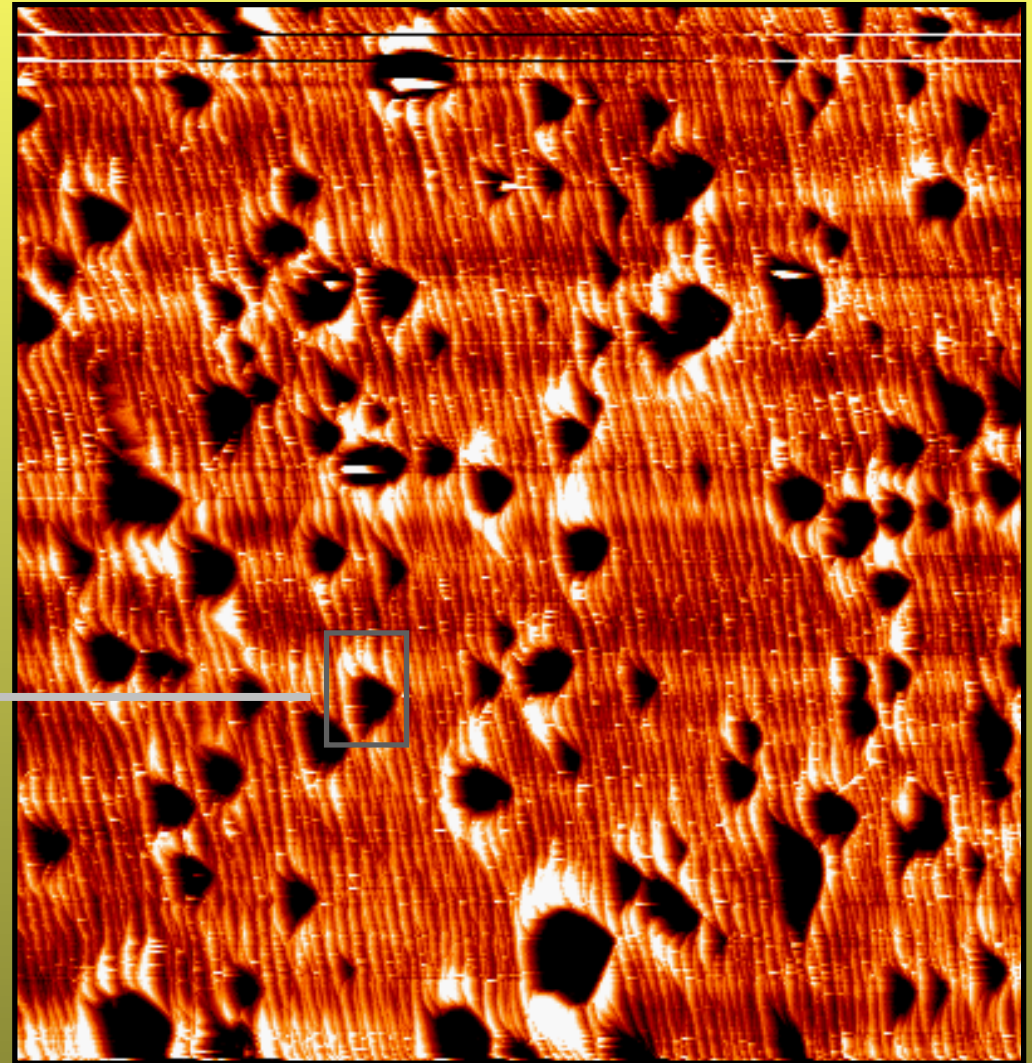
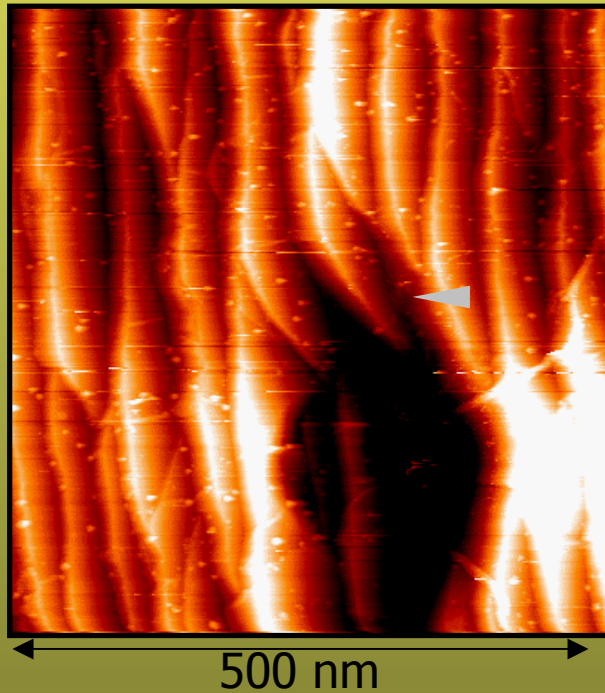
- **Wide Band Gap Semiconductors**
 - Stronger Atomic Bonds
 - Larger Breakdown voltage
 - Lower intrinsic carrier concentration
- **GaN** - poor thermal conductivity, no native oxide, high frequency?
- **C (diamond)** - No established technology at present
 - Other WBG materials like Diamond and III/V nitrides suffer from the lack of suitable substrates for epitaxial growth.
- **SiC** - Relatively mature technology, native oxide, blue light

Properties of SiC



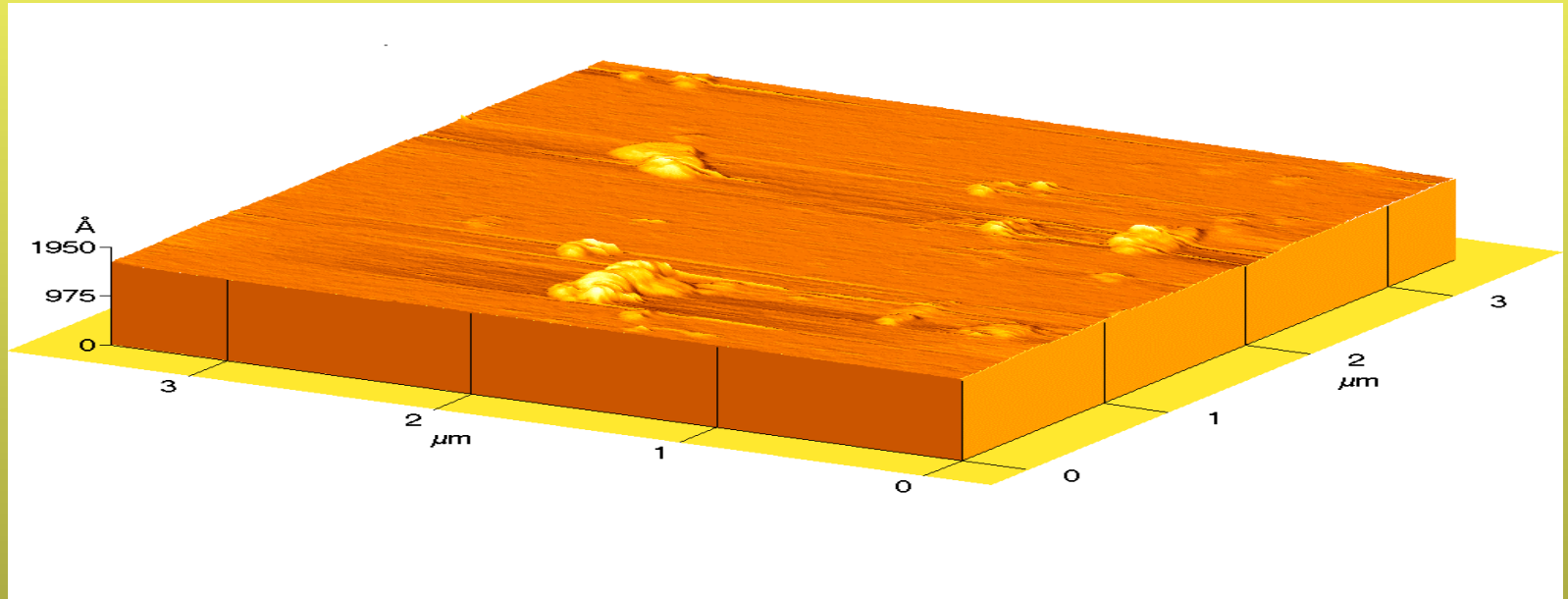
STM images

- STM studies on treated surfaces



5 μm x 5 μm UHV cleaned SiC surface that had been WOS

Surface Studies - AFM

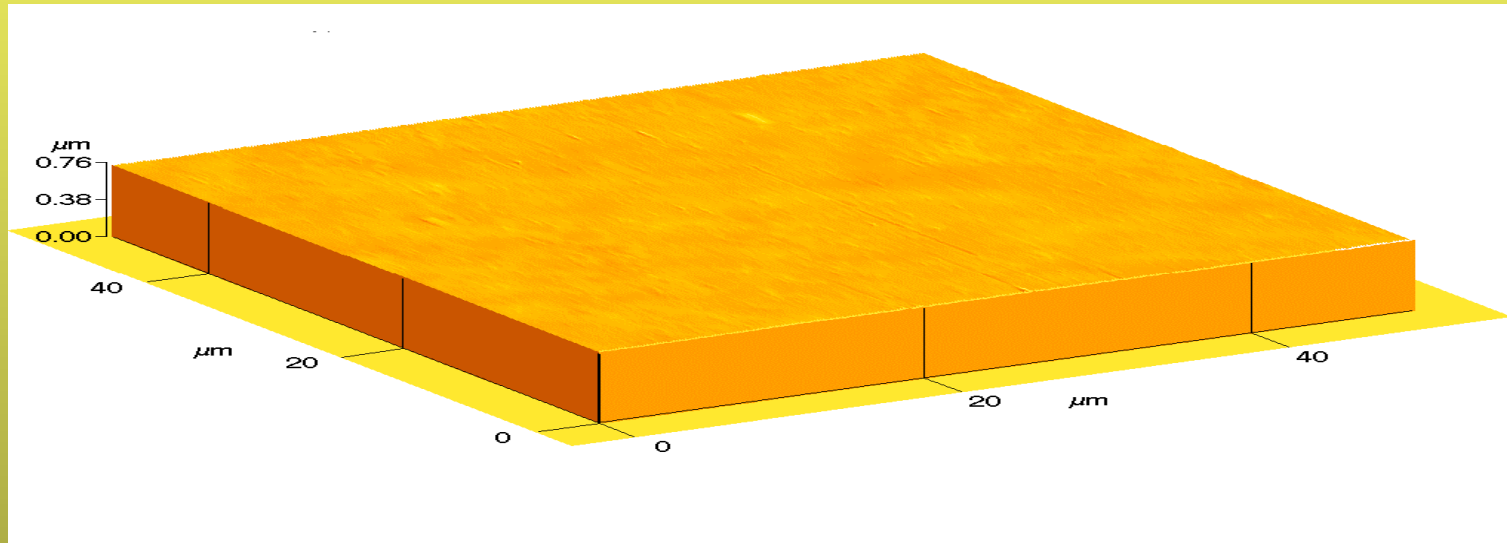


SiC Surface After Removal of Wet Thermal SiO₂

RMS Surface Roughness

23.4Å

Surface Studies - AFM

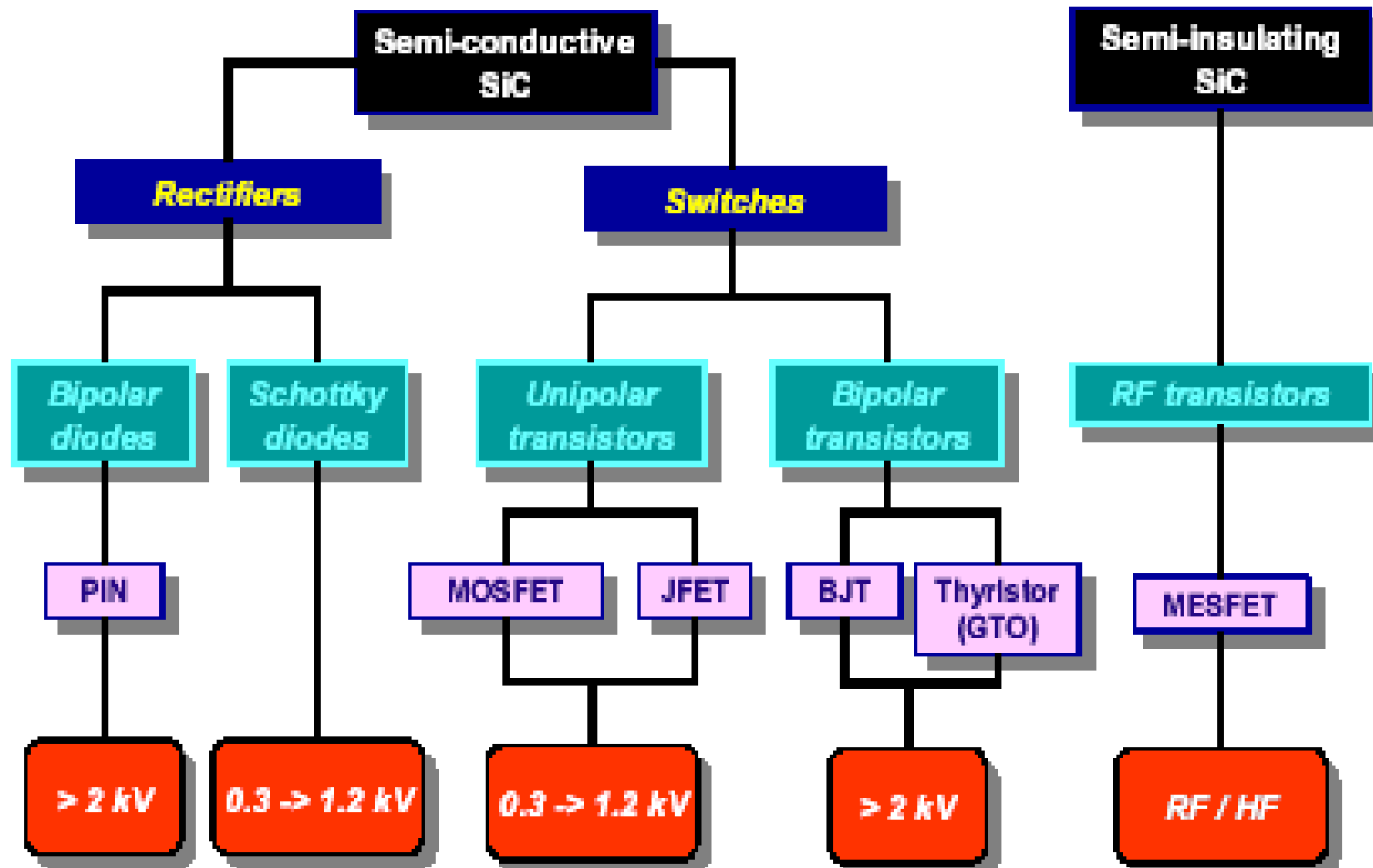


SiC Surface After Removal of SSO Thermal SiO₂

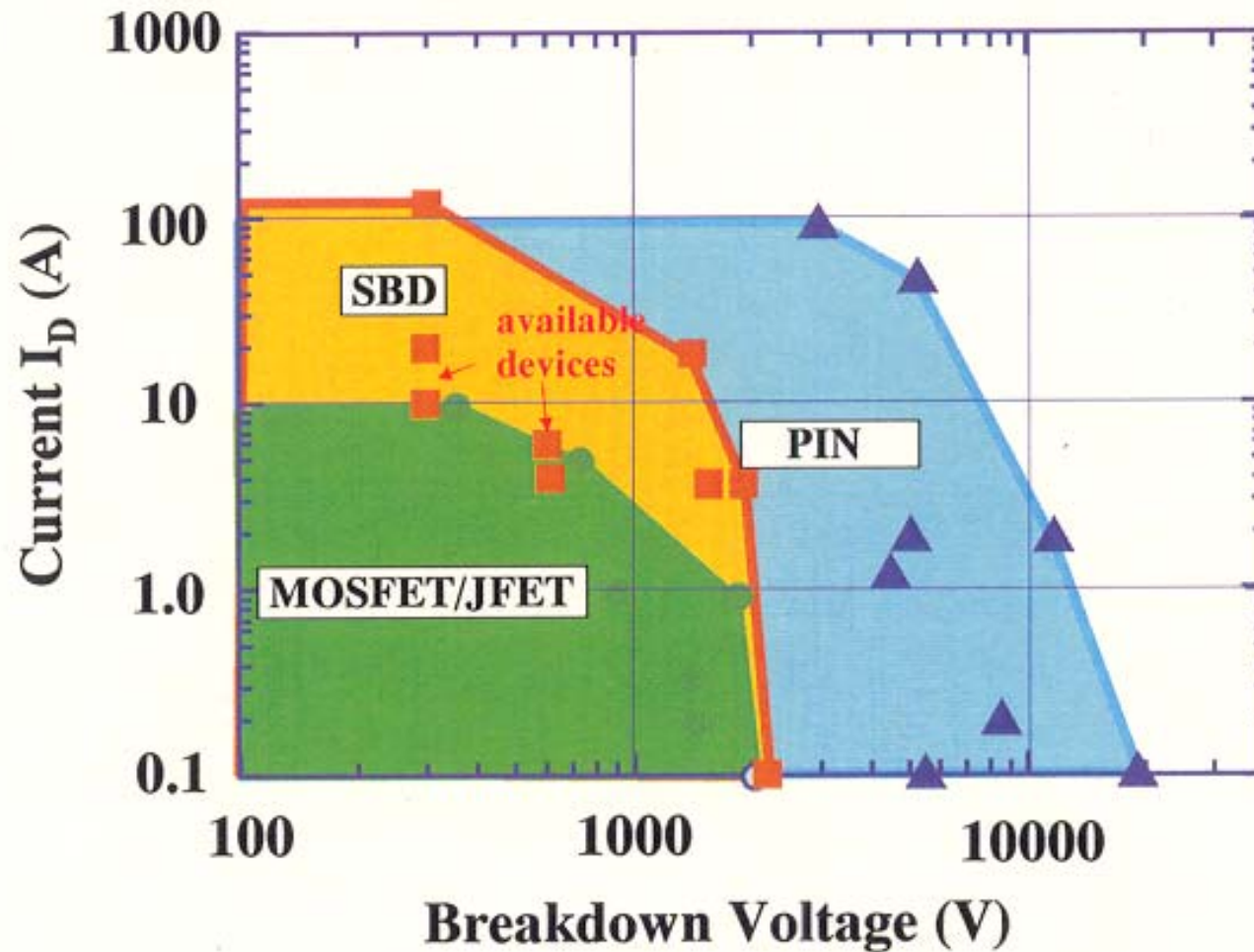
RMS Surface Roughness

11.1Å

SiC Applications – Devices



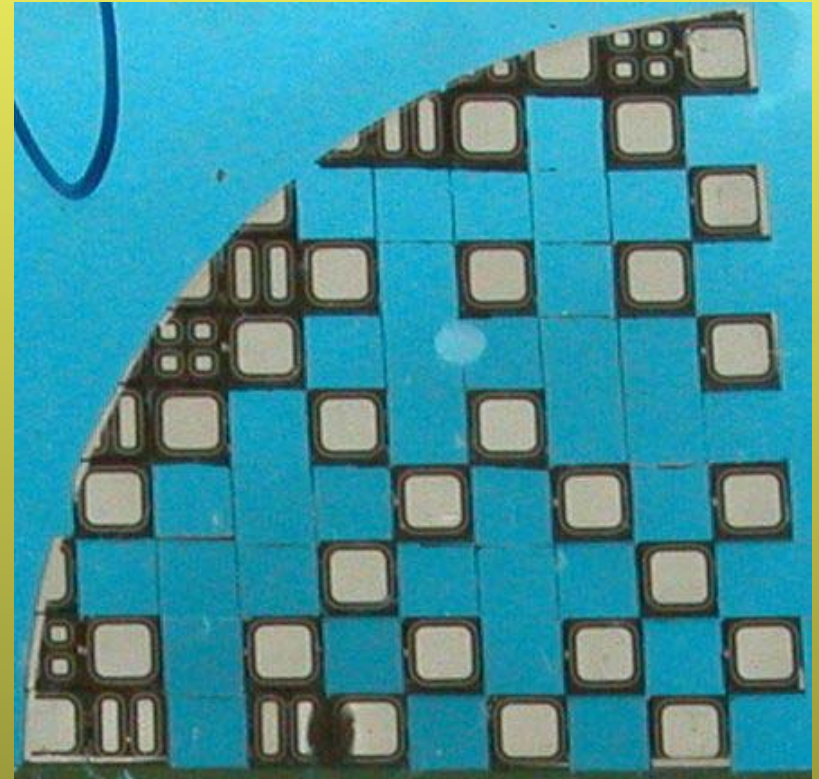
Current -Voltage Capacity of trial fabricated SiC-power devices



from homepage of Purdue Univ.

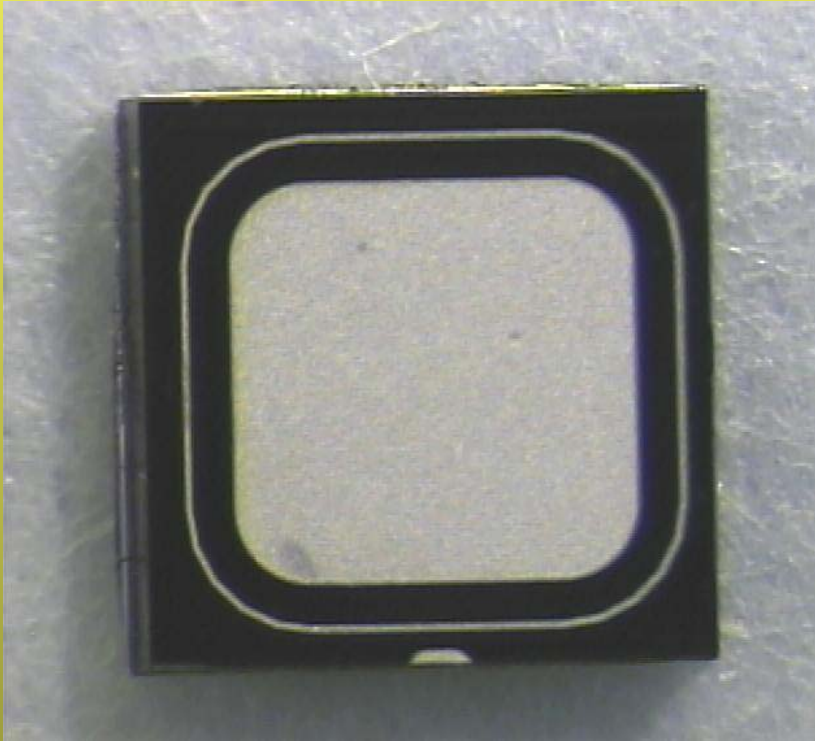
ESCAPEE Diodes

- 3 Different sized diodes
- 2x2mm largest
- 12%, 74% and 86% yield
- 1.2kV rated
- Diced ready for mounting

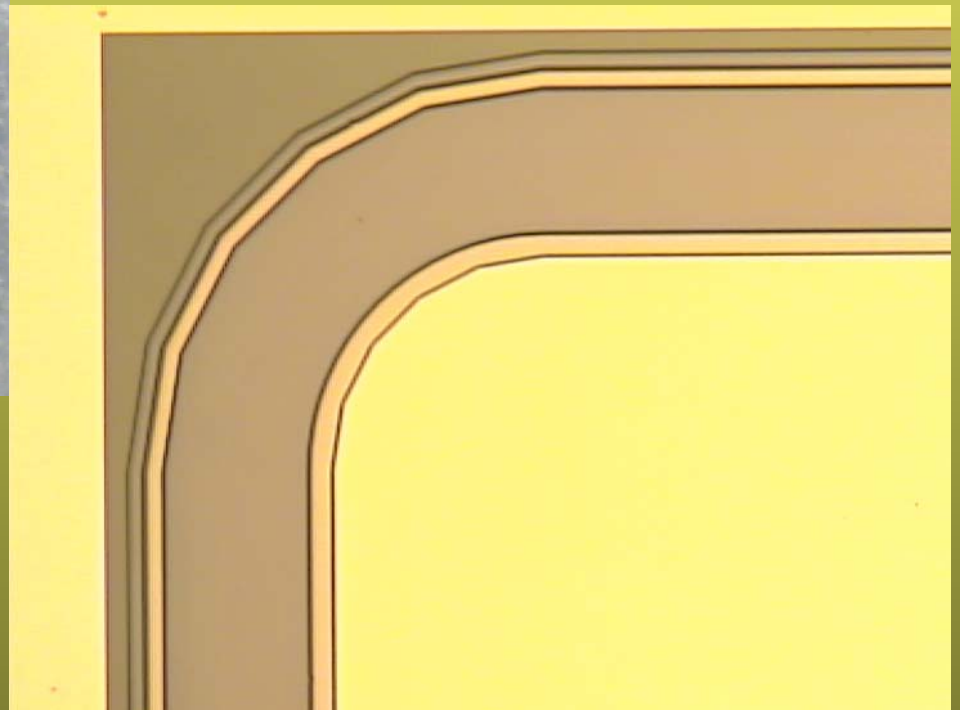


ESCAPEE Diode Die on Foil

ESCAPEE Diodes - fabricated

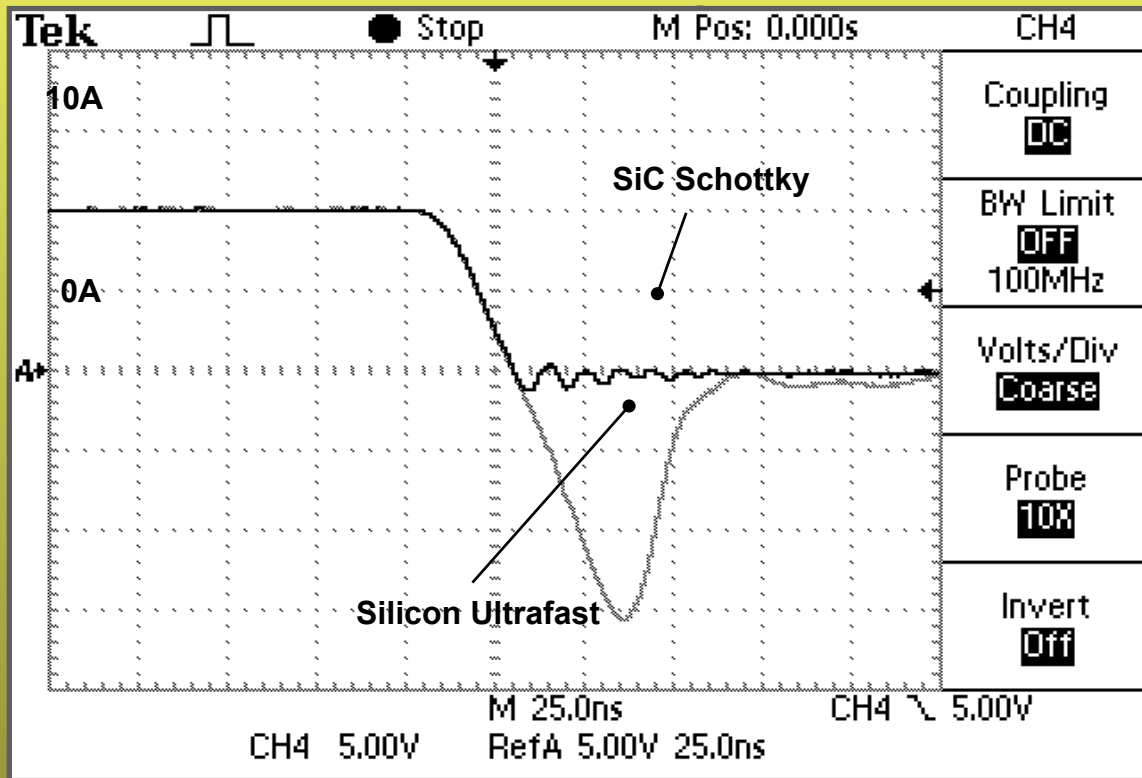


Large area 1.6x1.6 mm²



State of the art SiC Devices

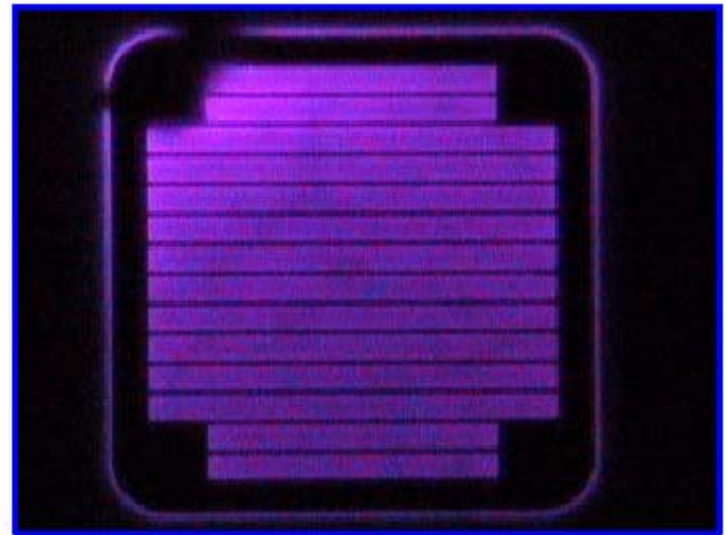
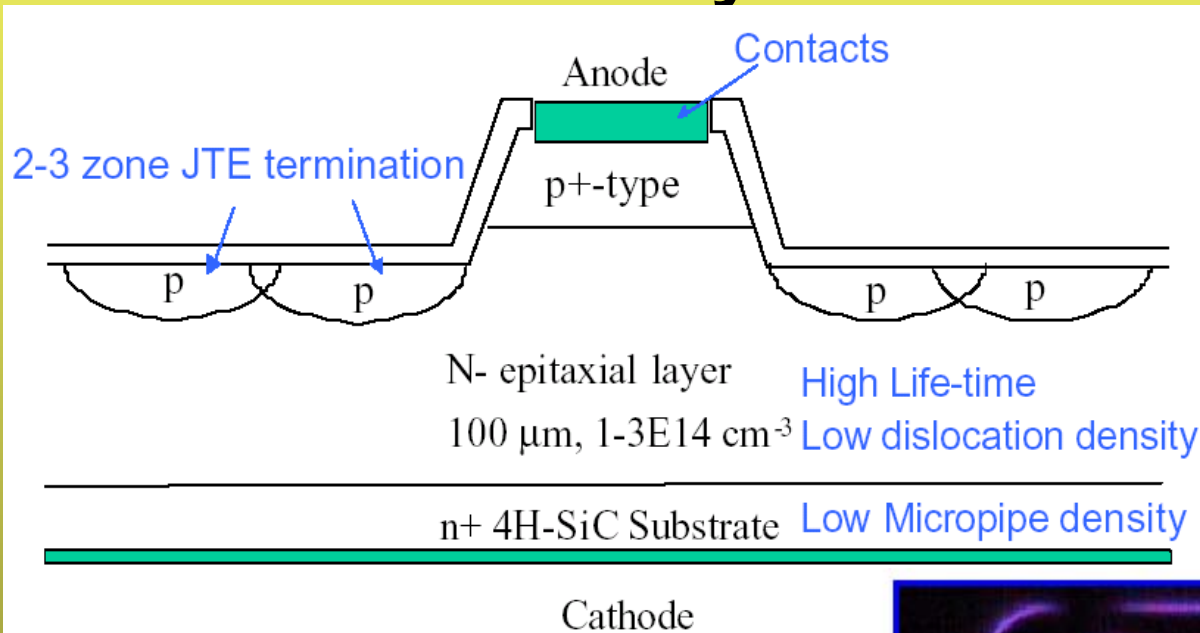
Schottky Diode Switching



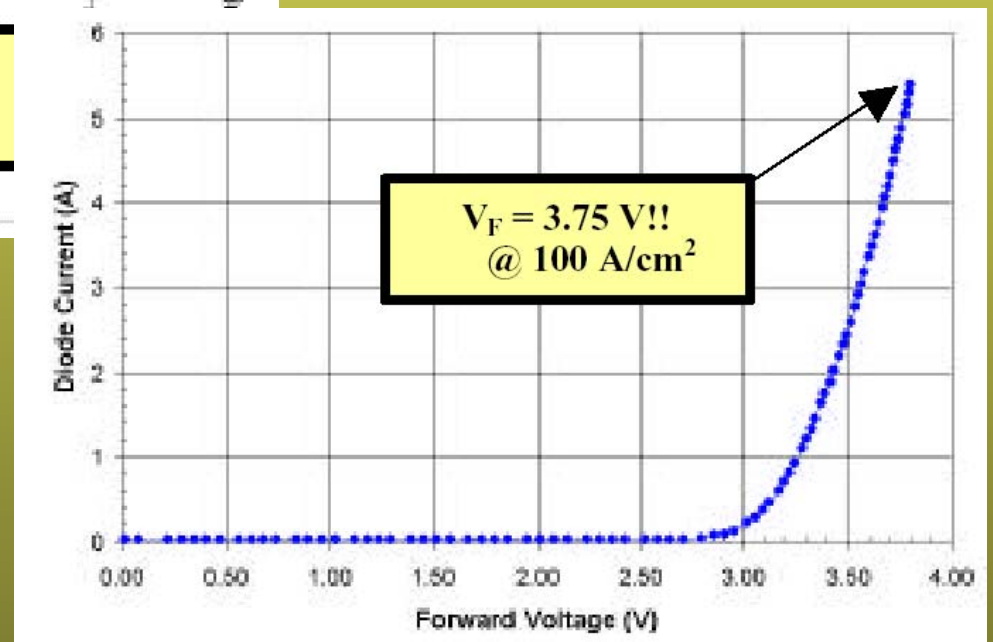
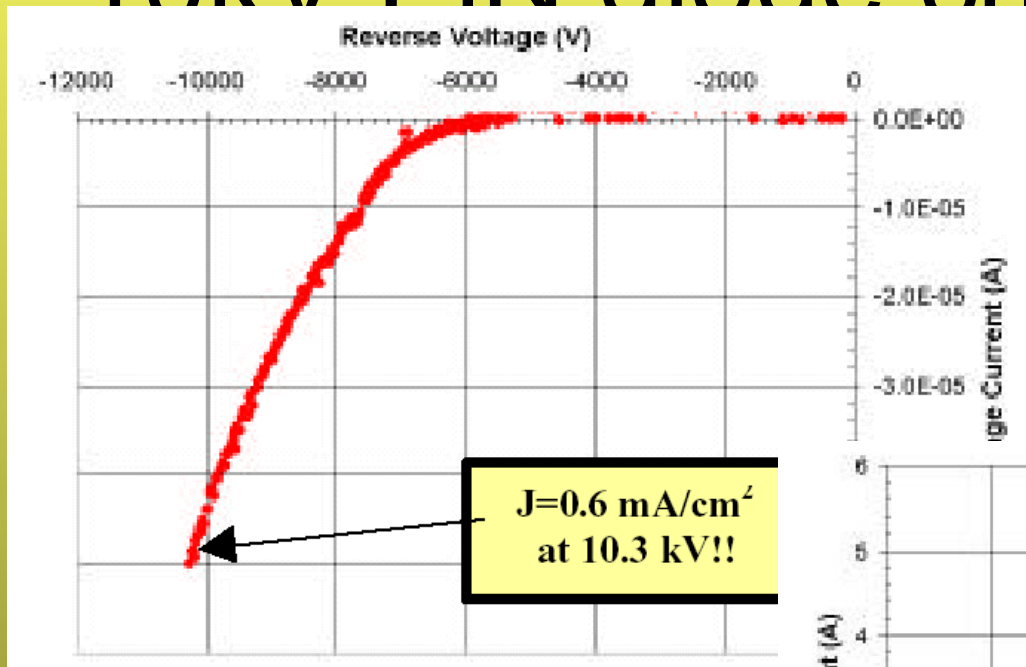
- tics
- Lack of reverse recovery.
 - Minimized switching losses make high pulse frequencies possible
 - Higher efficiency, smaller equipment size

- 1200V 2mmx2mm SiC Schottky diode switching characteristics.
- 1200V 8A Silicon ultrafast diode waveform shown for reference.

10kV PiN Diode with low stacking Fault density – Cree EPE2003



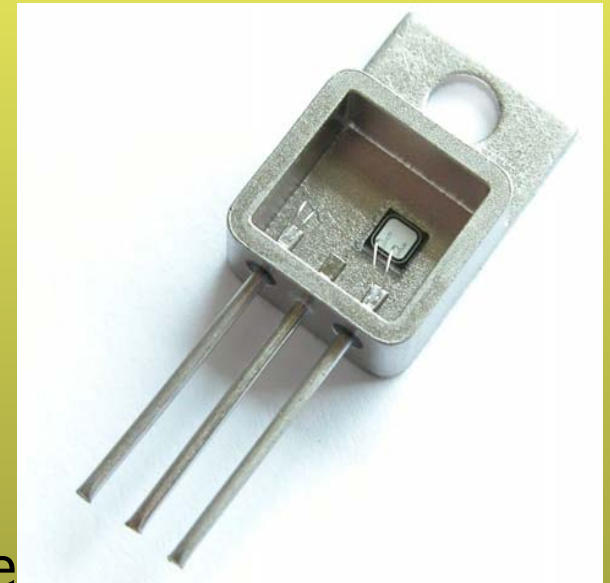
10kV PiN diode characteristics



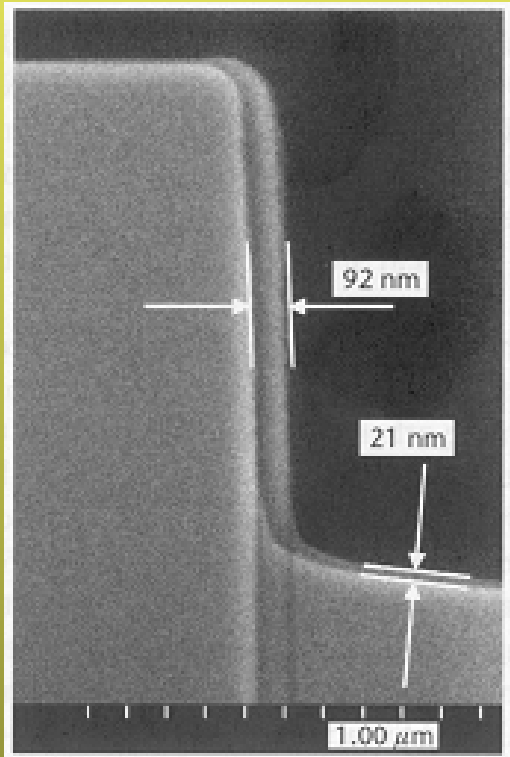
State of the Art SiC Devices

Schottky Barrier Diodes

- **Commercial diodes**
- 600V and 20A , 1.2kV and 10A ratings
- SiCED has realized blocking voltages up to 1700 V. Expected to extend this to 3300 V
- Expected to dominate market for blocking voltages below 3000V
- Capable of replacing Si junction rectifiers in medium power motor drive electronics modules



Trench MOSFET



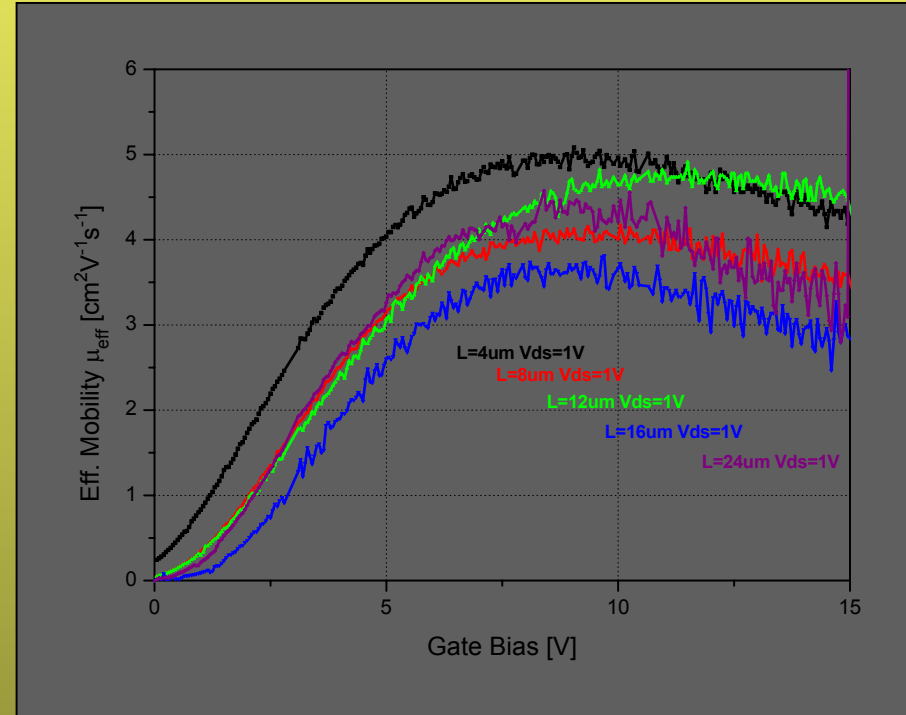
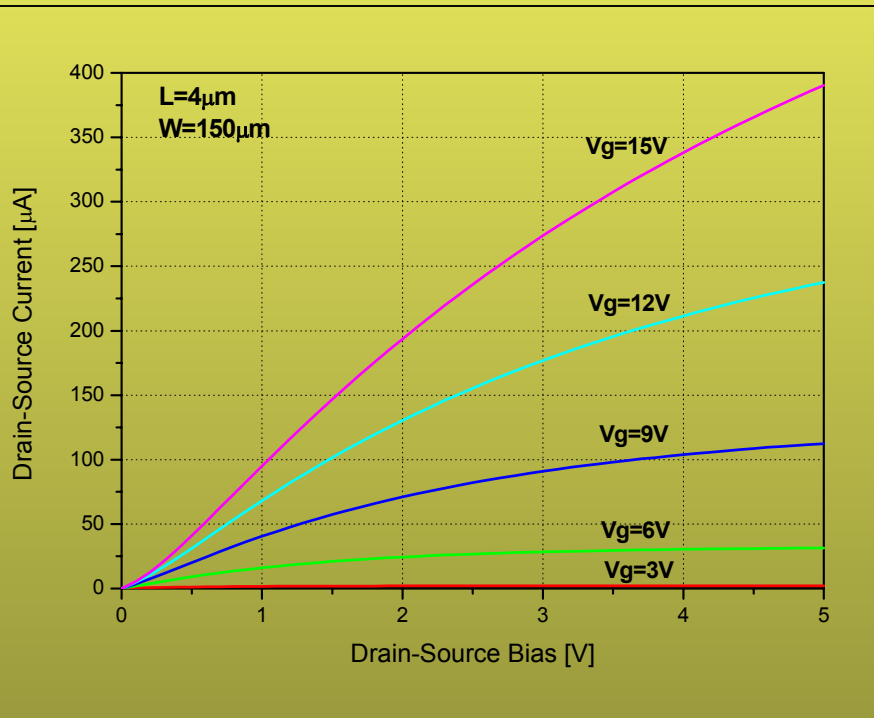
Oxide growth rate slower on trench bottom

Maximum Oxide field 2MV/cm limits field in SiC to 0.8MV/cm ie 0.2 of critical value

Can implant P+ layer at bottom of trench to reduce field

MOSFET test structure

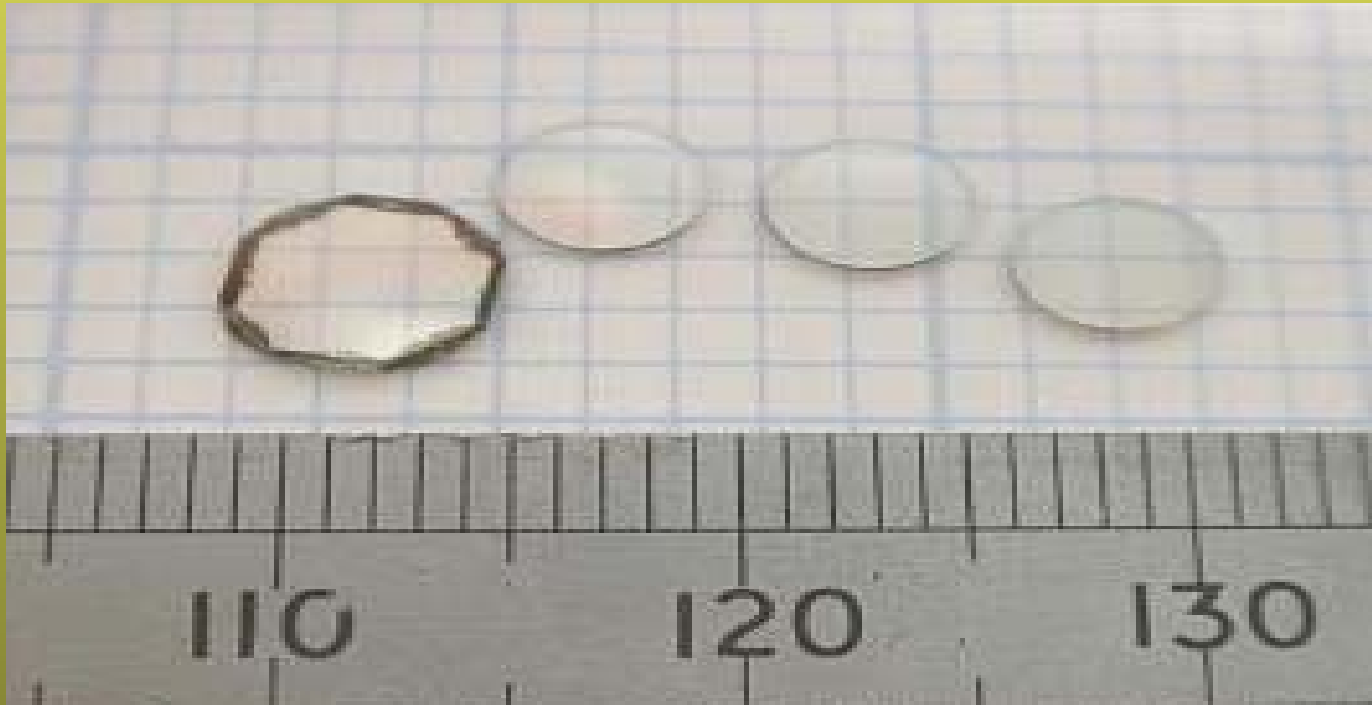
N-MOSFET on 4H-SiC



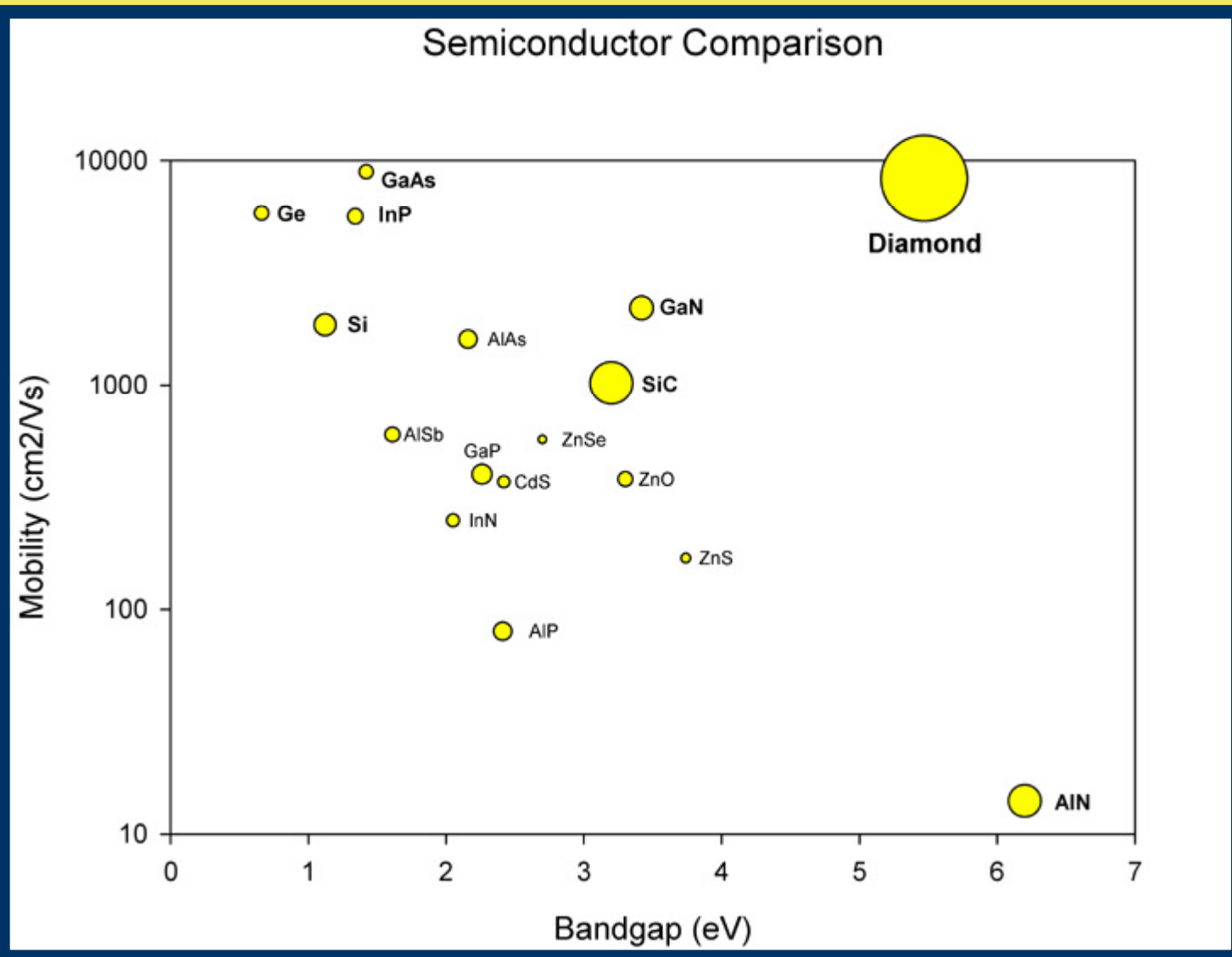
Gate oxide thickness: 38 nm
Effective channel mobility 2 cm^2/Vs
Not rectifying contact
Reference device.

Science 297 (6 Sept. 2002) p1670

Not only polycrystalline diamond was possible but E6 had developed technology for producing free-standing single crystal CVD diamond with material properties which far exceeded even the most optimistic expectations.



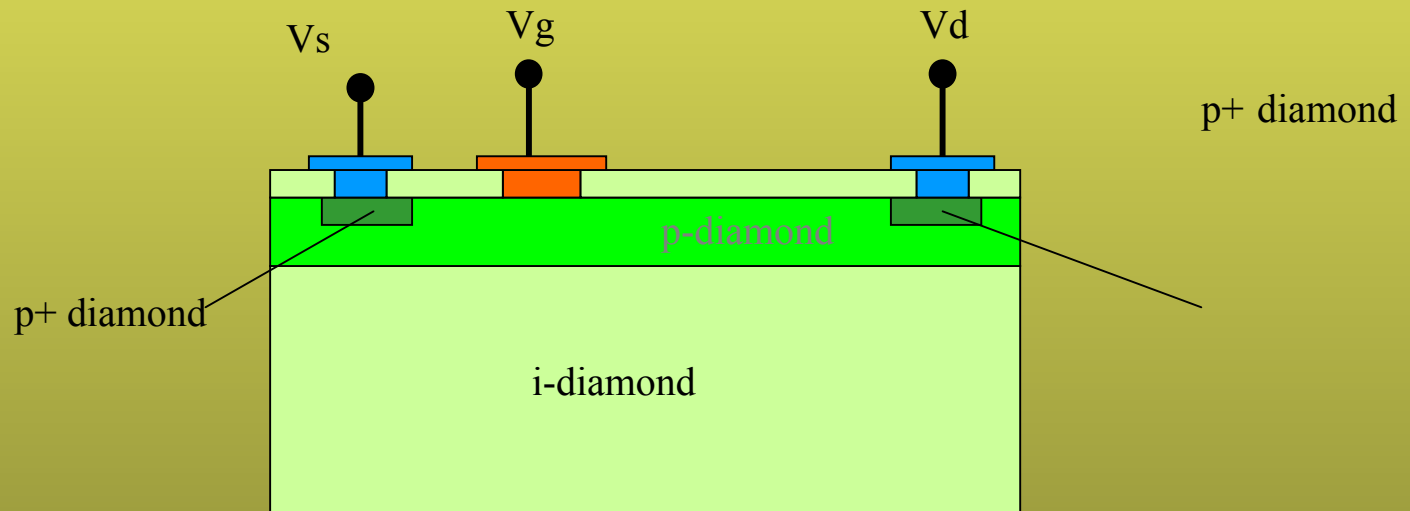
Diamond - the only wide bandgap high mobility material



Diamond Properties

	Si	SiC-4H	GaN	Diamond
Band gap (eV)	1.1	3.2	3.44	5.5
Breakdown field (MV/cm)	0.3	3	5	10
Electron mobility (cm ² /Vs)	1450	900	440	4500
Hole mobility (cm ² /Vs)	480	120	200	3800
Thermal conductivity (W/cmK)	1.5	5	1.3	24
Johnson's Figure of Merit	1	410	280	8200
Keyes' Figure of Merit	1	5.1	1.8	32
Baligas Figure of Merit	1	290	910	17200

CVD Diamond MESFETs for Power applications



Conclusions

- Power Device Performance is doubling every 18 months
- Power Electronics is Critical for Efficient energy usage
- New Devices and Materials are needed to maintain this rapid change

Many Thanks to

- Dr Petar Igic, Dr Owen Guy, Dr Li Chen, Dr. Zhonfu Zhou, Dr. Salah Khanniche plus all other members of the Power Electronics Research Centre